



COLUMBIA UNIVERSITY
IN THE CITY OF NEW YORK

Department of Electrical Engineering

0.5V Analog integrated circuits for nanoscale CMOS technologies

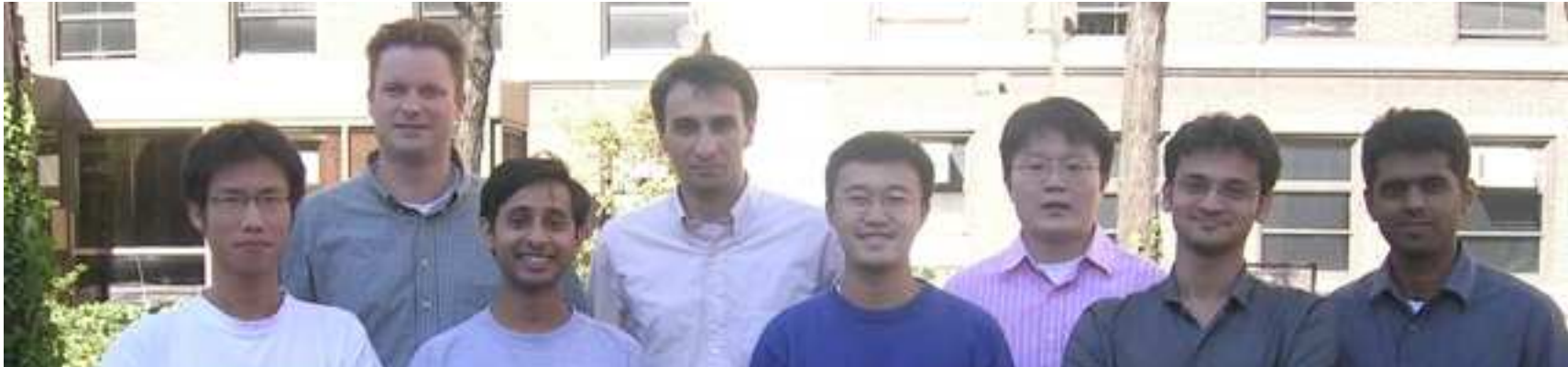
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Collaborators: Shouri Chatterjee, Yannis Tsividis, K.P. Pun^{*}

^{*}Chinese University of Hong Kong

Analog & RF Design Research



Ultra-low voltage
circuits: 0.5V

RF integrated
oscillators

Ultra-wideband
RF circuits

RF Passives

Injection locked
circuits

Device mismatch &
its influence on
Analog & RF ICs

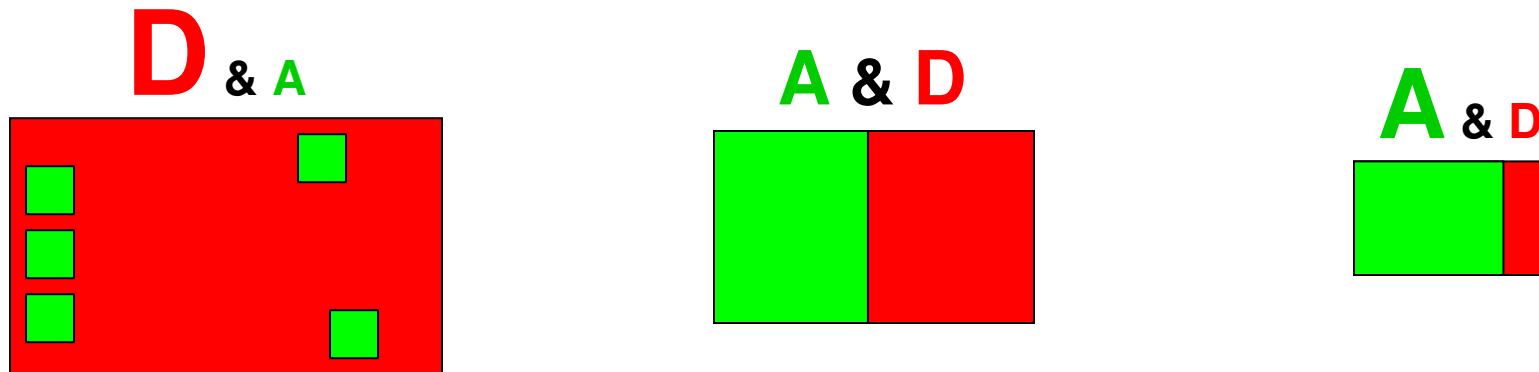
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Outline

- Do we need Analog Integrated Circuits in nanometer CMOS?
- Design Challenges & Opportunities.
- 0.5 V Operational Transconductance Amplifiers & Biasing Circuits.
- 0.5 V Fully Integrated Active RC Filter with on-chip Automatic Tuning.
- A 0.5V 74dB SNDR 25kHz CT $\Sigma\Delta$ Modulator with Return-to-open DAC
- Conclusions.

Analog in a *Mixed Signal World*

- Sounds, images, EM waves, are **ANALOG**.
- Information processing & storage are **DIGITAL**.
- System-on-chip is powerful economic paradigm.

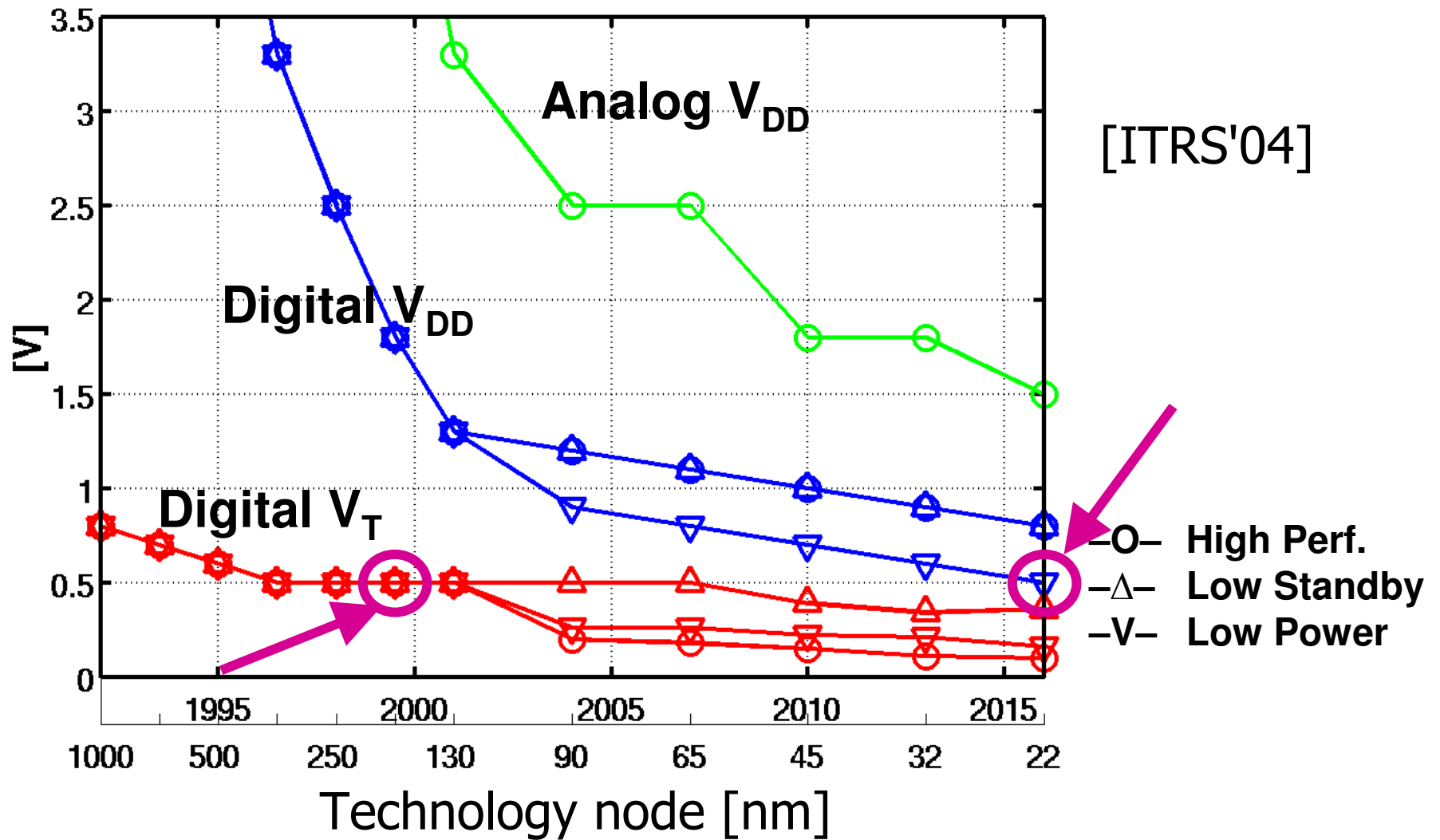


- Digital drives technology development & choice.

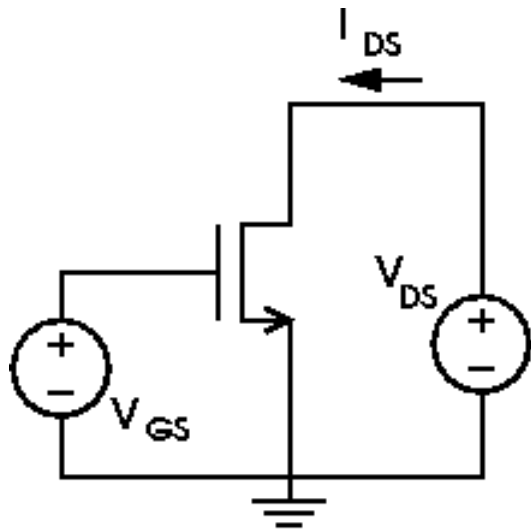
Most Digital ICs need some Analog!

**If Analog can be done in a digital technology,
it will be done.**

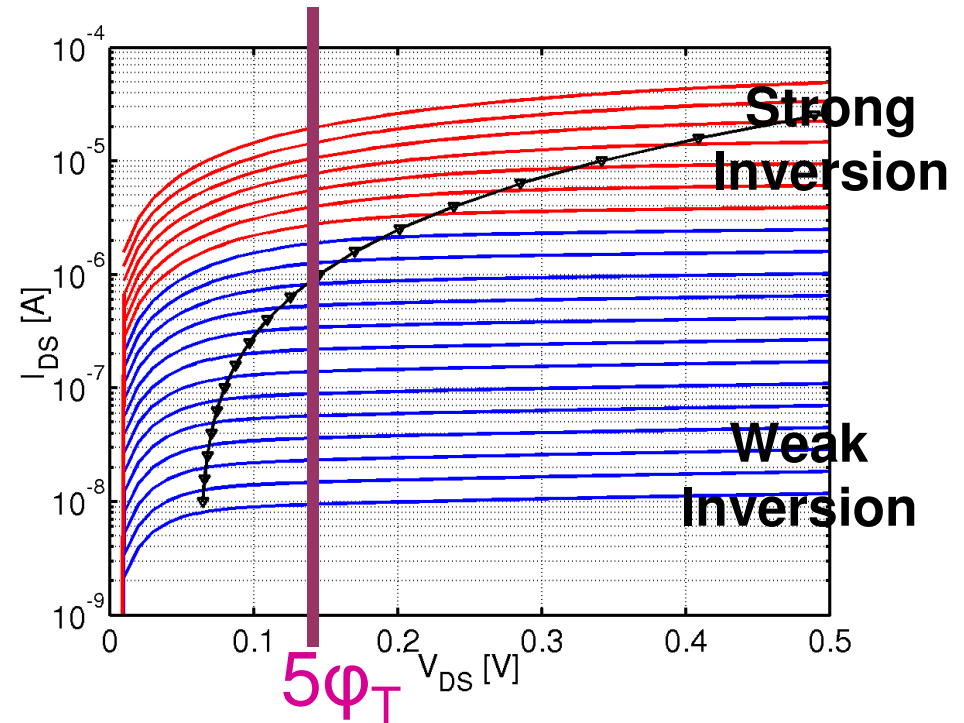
CMOS trends: Supply voltage



MOST biasing: CS or VCCS



0.24 μ m/0.36 μ m nMOS
in 0.18 μ m CMOS

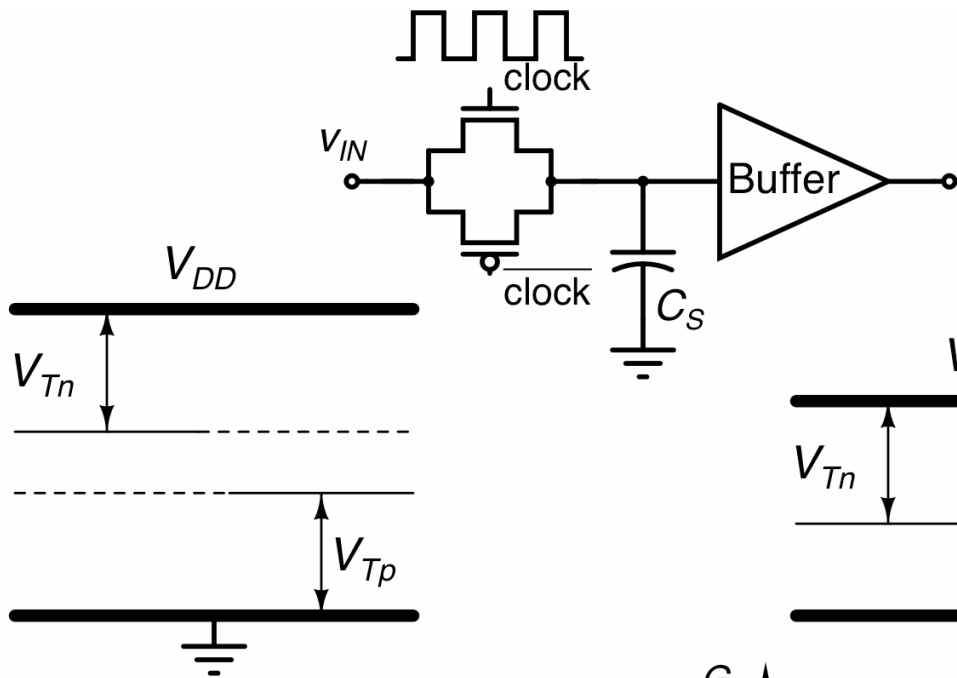


- Transconductor or Current Source
 $V_{DS} > 0.15V$ (for $V_{GS} - V_T \leq 0.2$)

Switches at 0.5 V

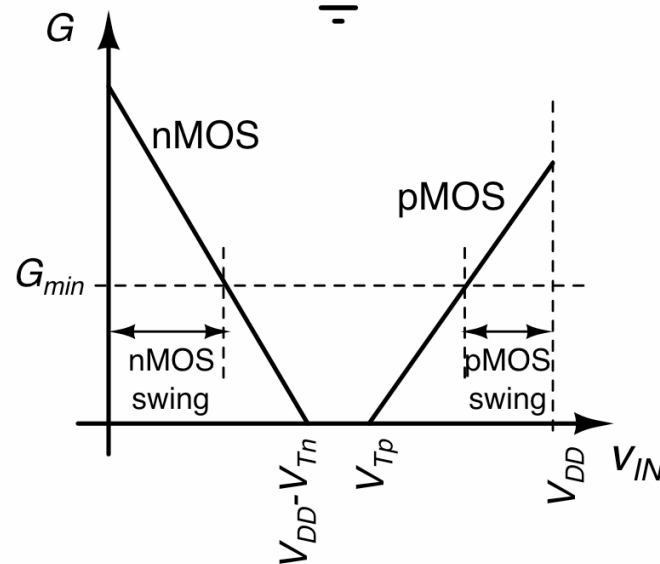
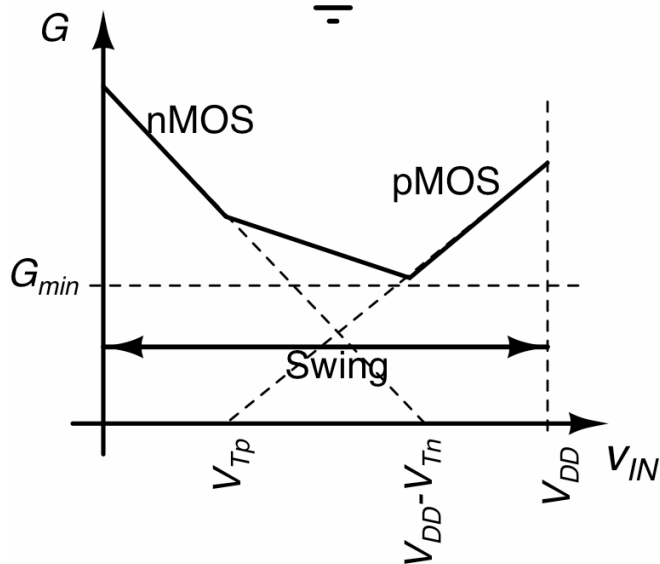
Large V_{DD}

Enough headroom

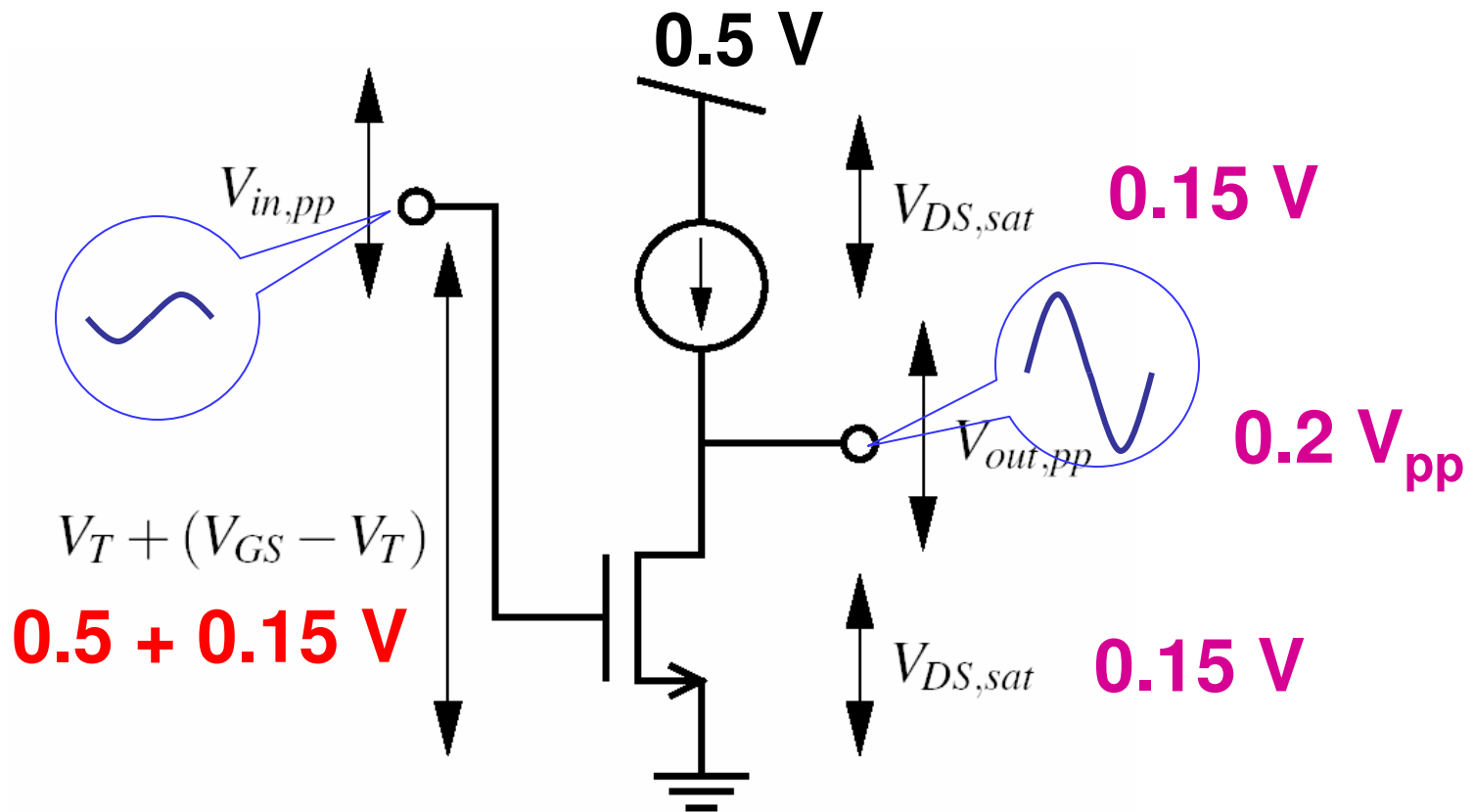


Small V_{DD}

No headroom



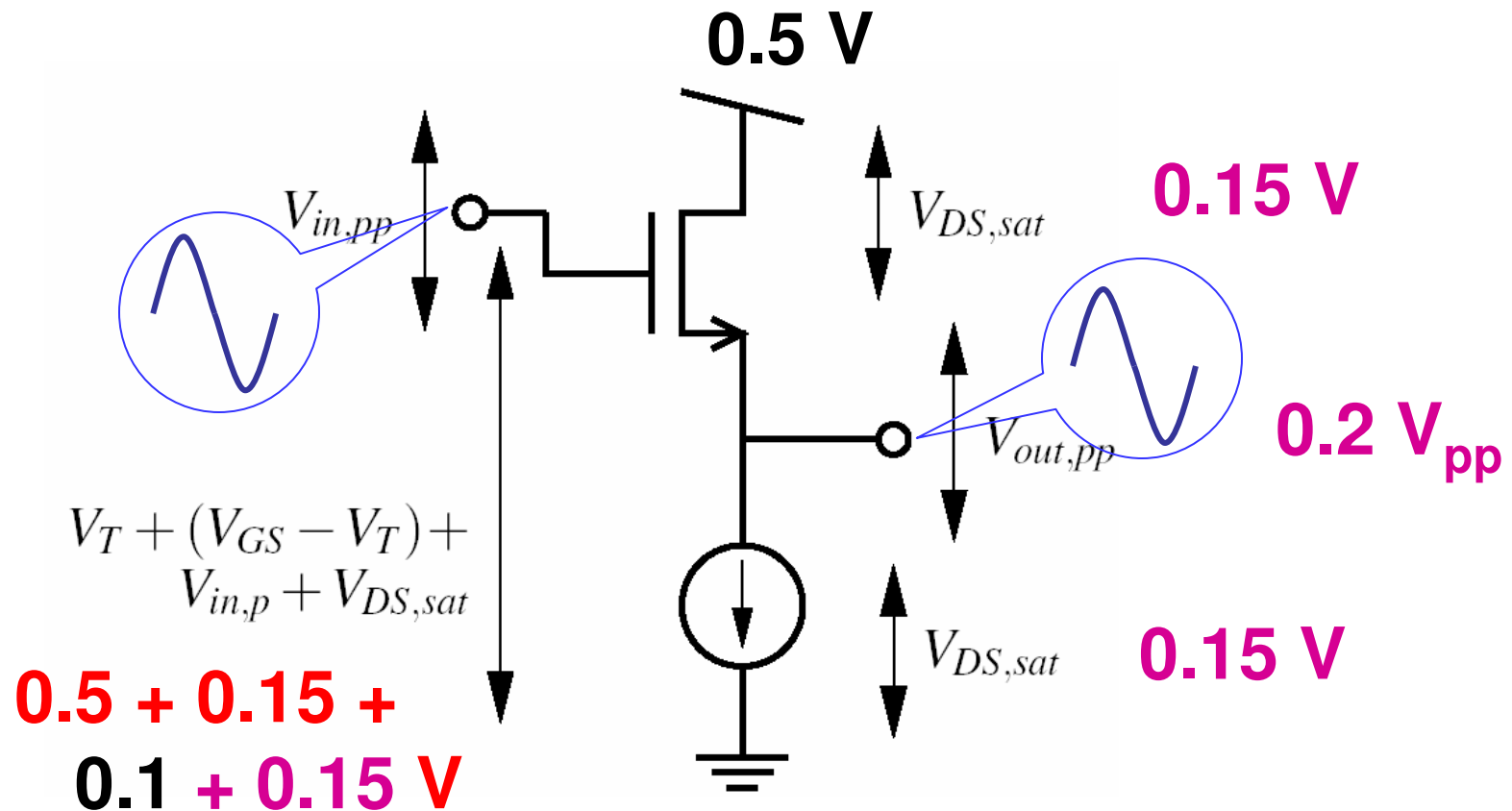
Common source amplifier



$$V_T = 0.5 \text{ V}$$

$$V_{DS,sat} = 0.15 \text{ V}$$

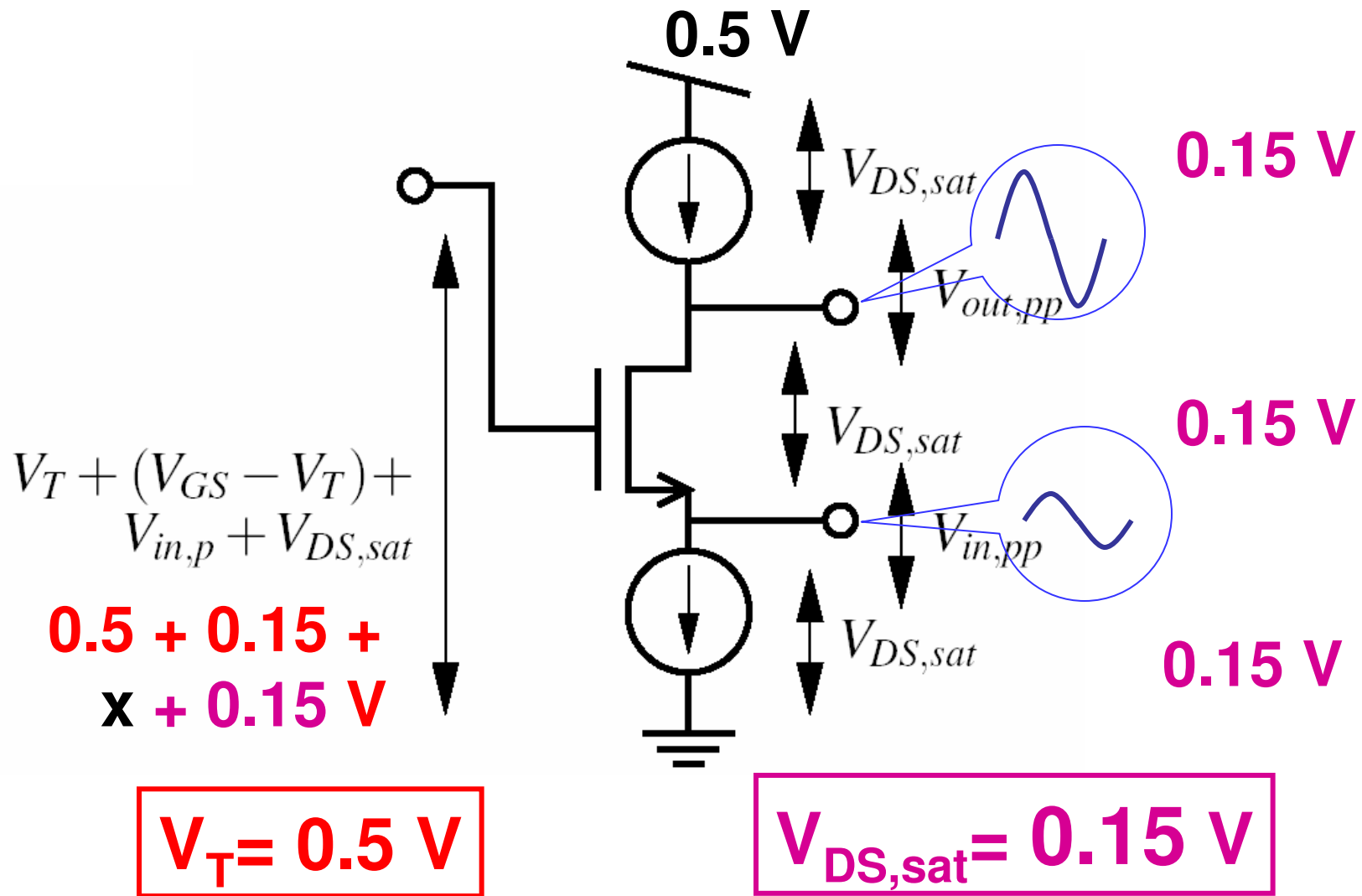
Common drain buffer



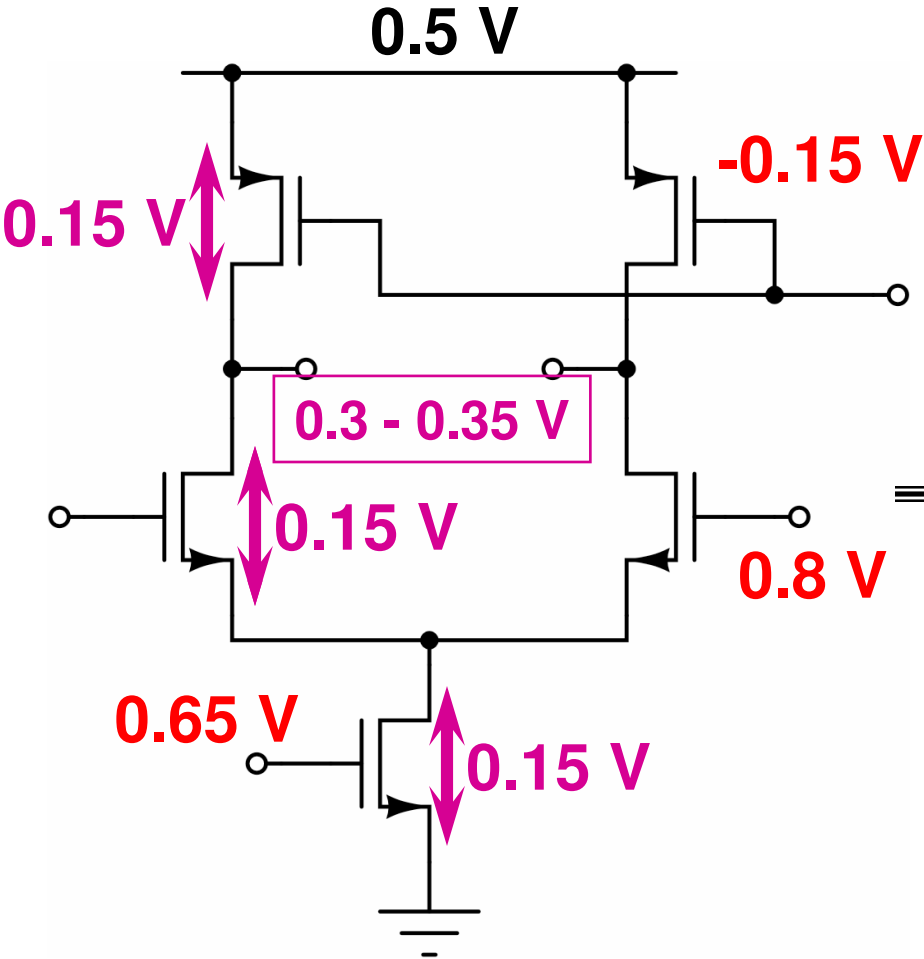
$$V_T = 0.5 \text{ V}$$

$$V_{DS,sat} = 0.15 \text{ V}$$

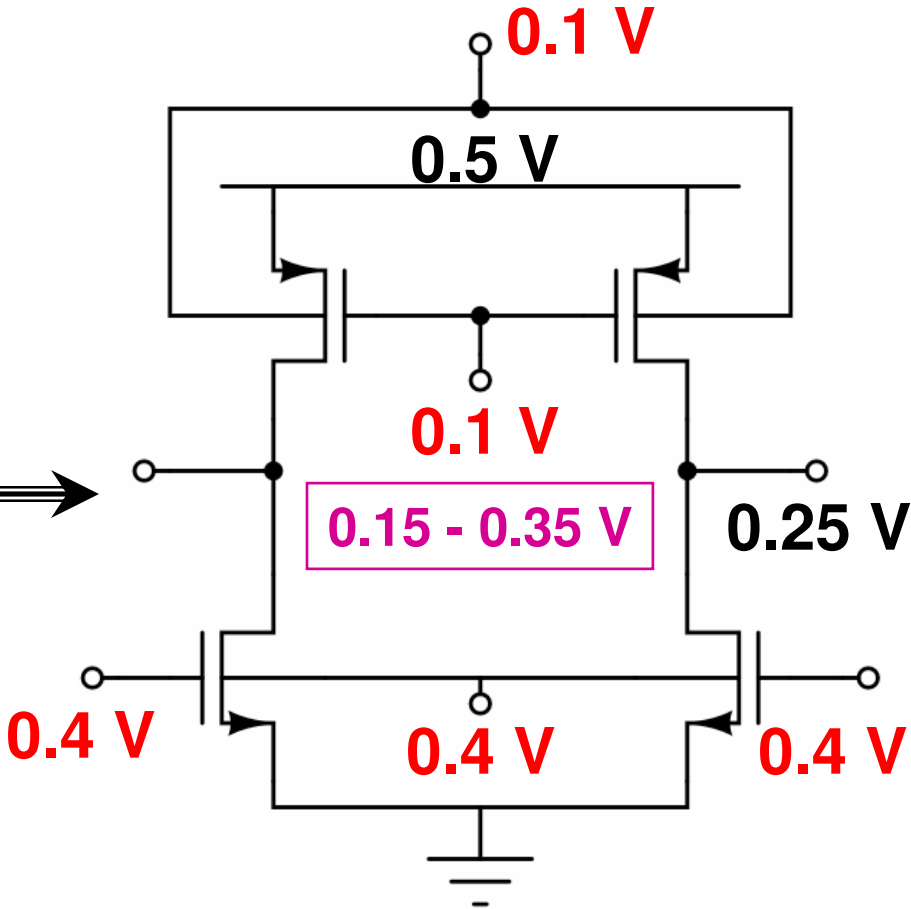
Common gate amplifier / Cascode



Differential OTA design challenges

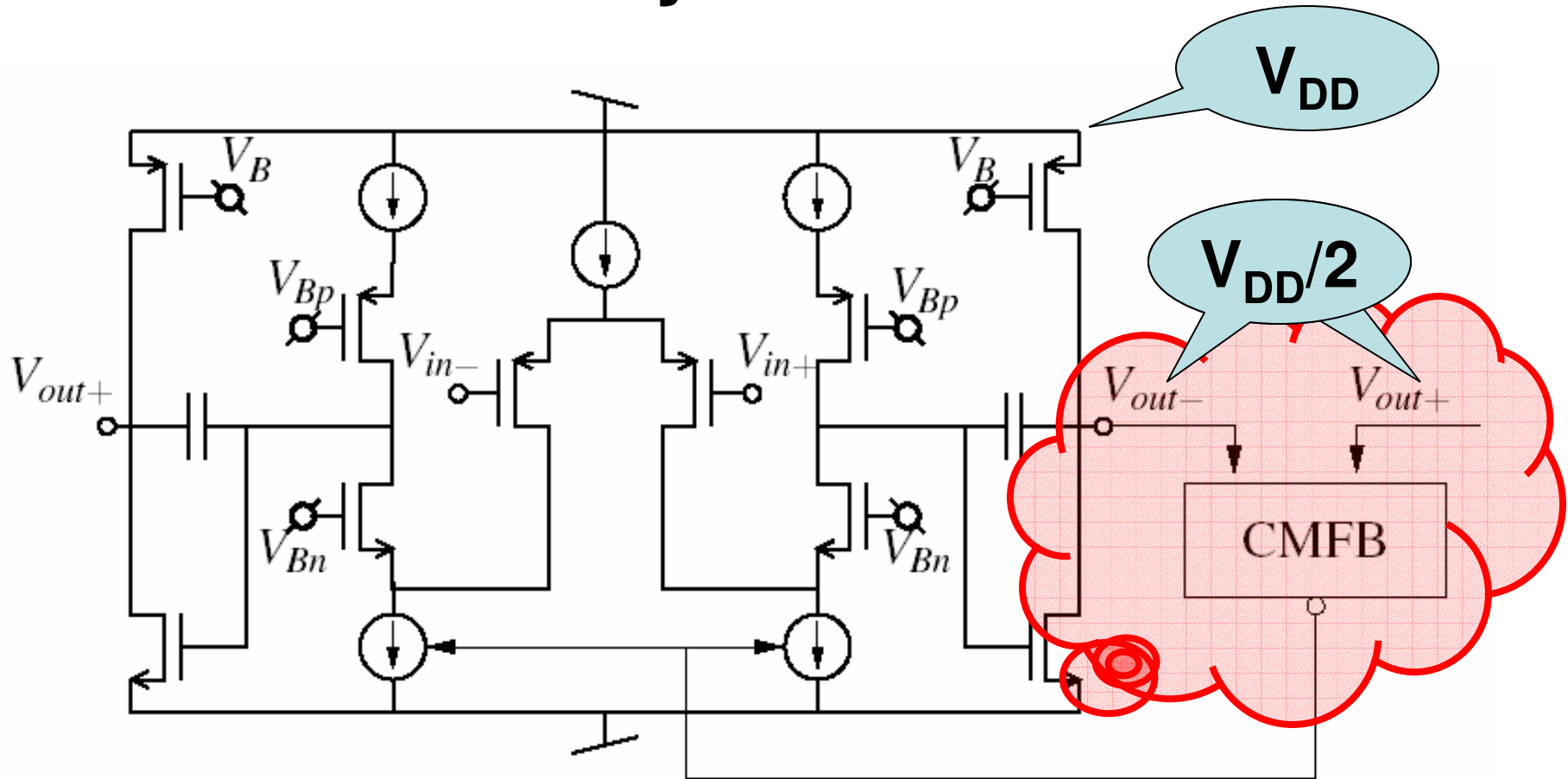


$$V_T = 0.5\text{ V}$$



$$V_{DS,sat} = 0.15\text{ V}$$

CMFB for fully differential OTAs



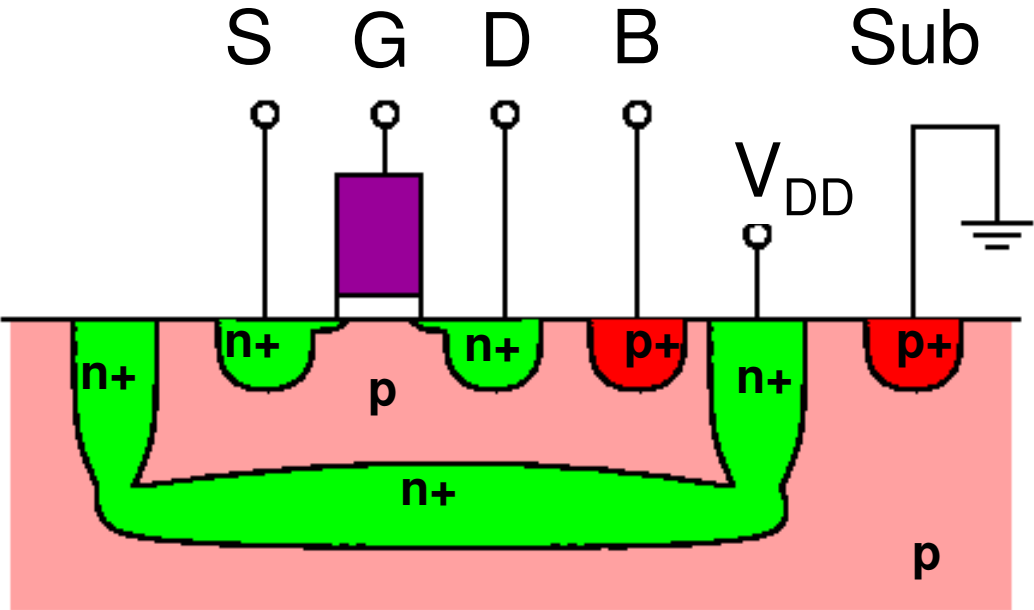
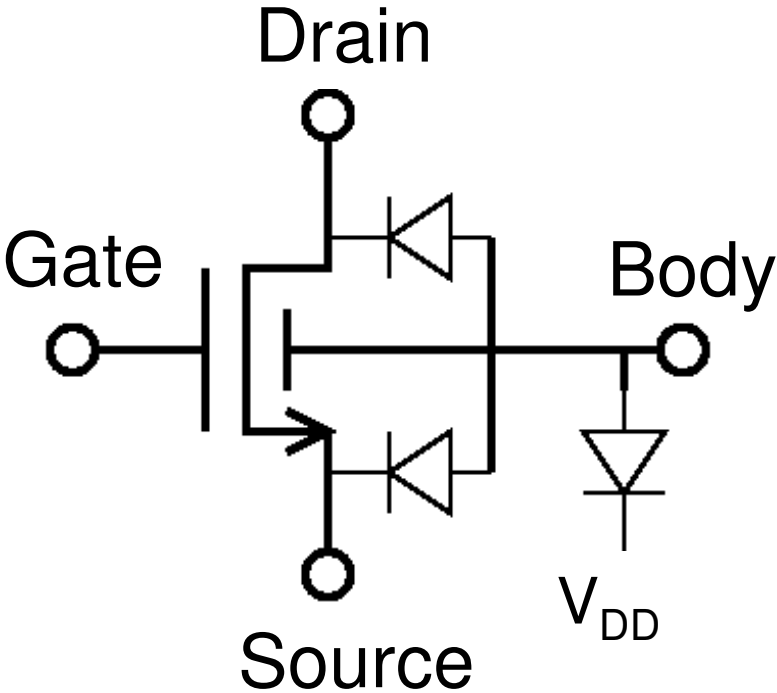
Common Mode Feedback requires 'fast' amplifier operating from $V_{out,CM} = V_{DD}/2$!?

Challenges at 0.5 V

- $V_{DS,sat}$ related challenges:
 - Independent of region of operation!
 - Independent of V_T !
 - Signal swings are limited:
 - Use differential circuits.
 - Avoid transistor stacks:
 - No tail current source: How to achieve CM rejection?
 - No cascodes: How to increase DC gain?
- V_{GS} related challenges:
 - Depend on region of operation & $(V_{GS}-V_T)$.
 - Depend on V_T !
 - Avoid signal swing on gate:
 - How to do overall CMFB?
 - How to achieve strong inversion operation?

Opportunities at 0.5 V: MOST has 4-terminals

nMOS circuit equivalent
(deep n-well process)

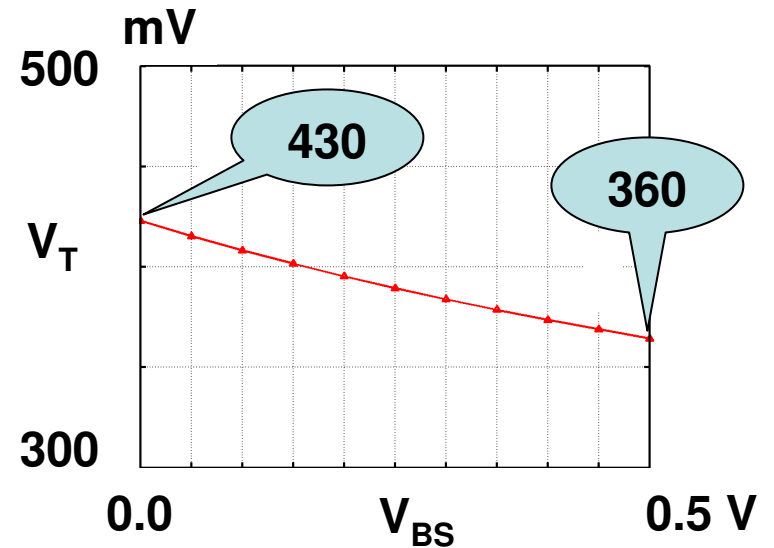
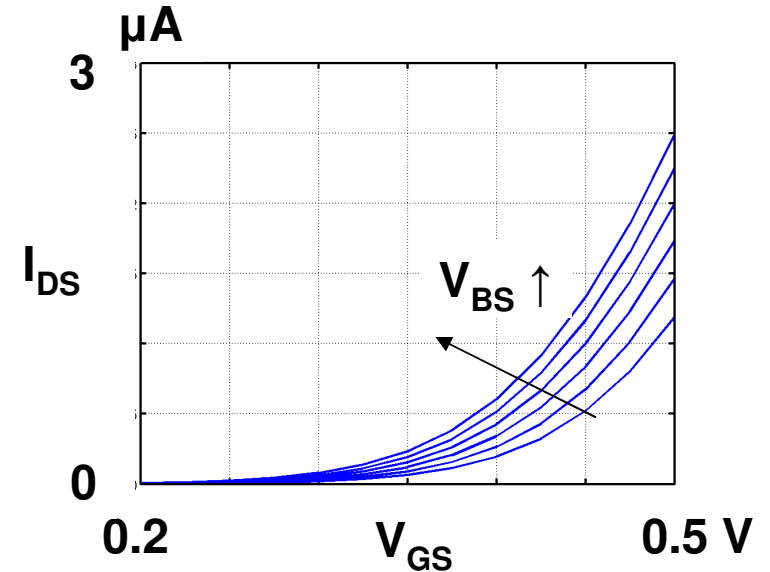


nMOS cross section
(deep n-well process)

Opportunities at 0.5 V

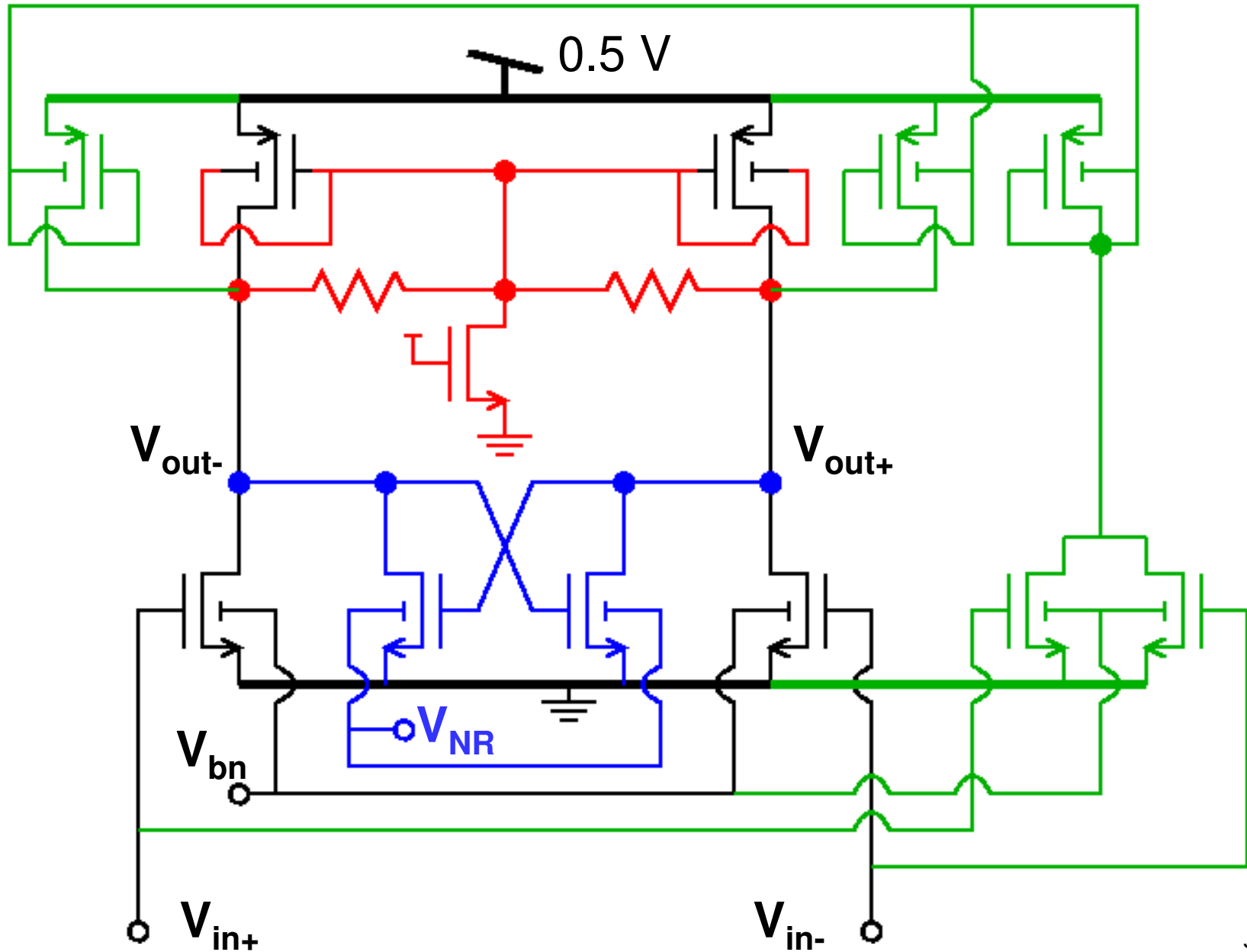
- Body terminal
 - Signal input: [Guz87]
 - V_T reduction & control [Kob94], [Von94]
 - Bias control
- Latch-up not an issue
 - Assuming V_{DD} and GND are ‘well behaved’.
- Techniques can be ported to ‘double gate’ devices

0.24 μ m/0.36 μ m nMOS
in 0.18 μ m CMOS

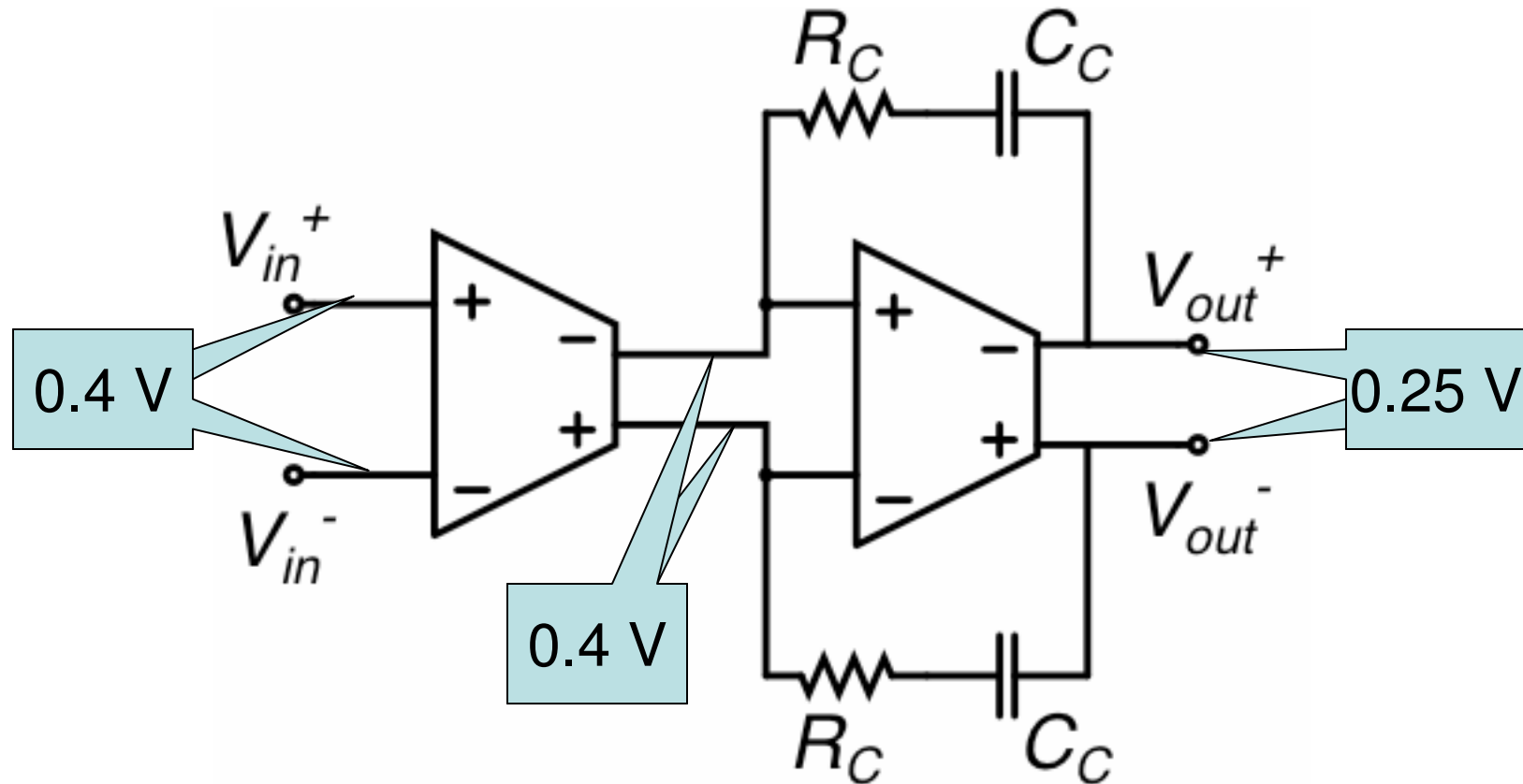


0.5 V Gate-input OTA

0.5 V Gate-input OTA stage

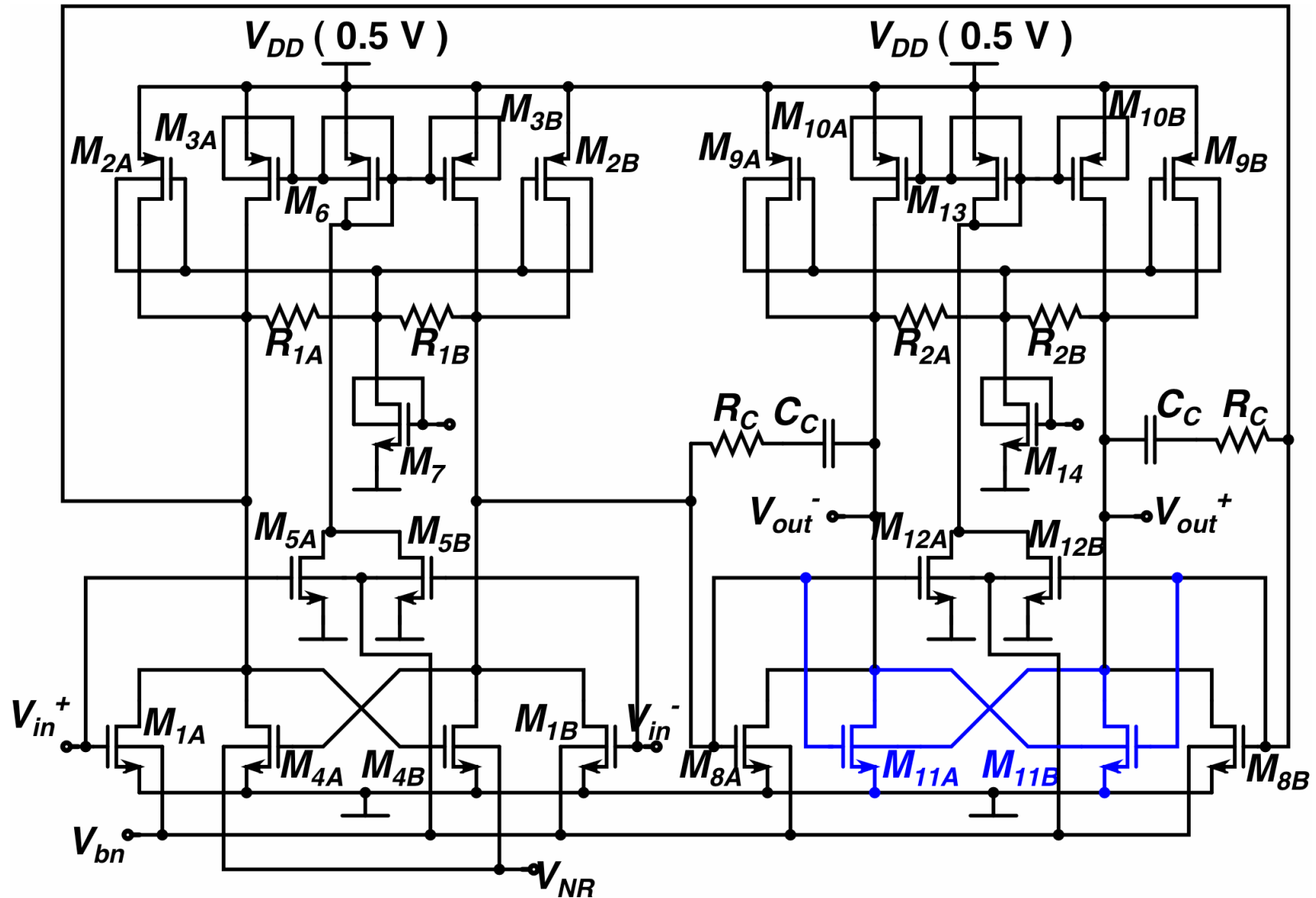


Two stage OTA

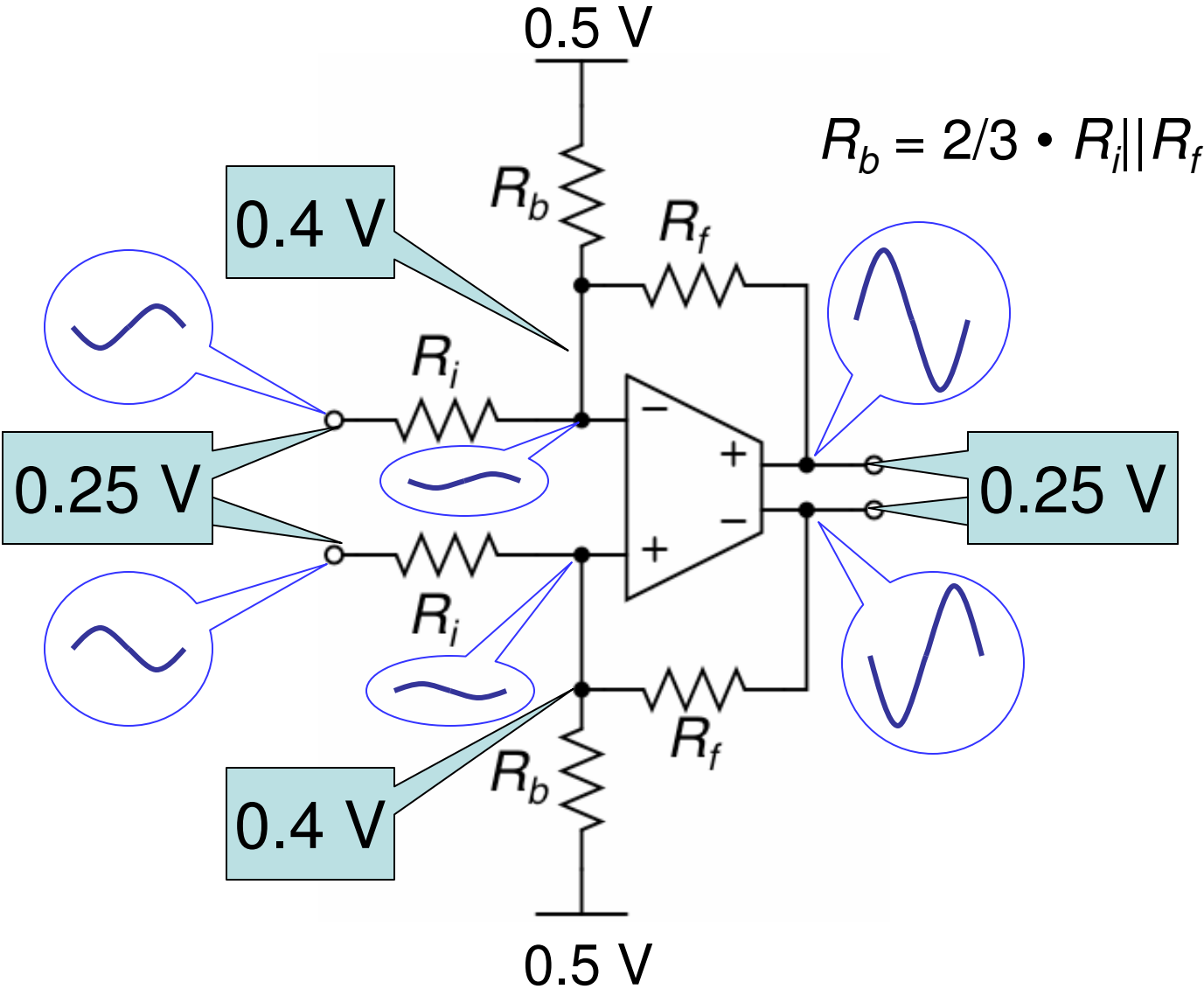


- Common-mode output of first stage is 0.4 V

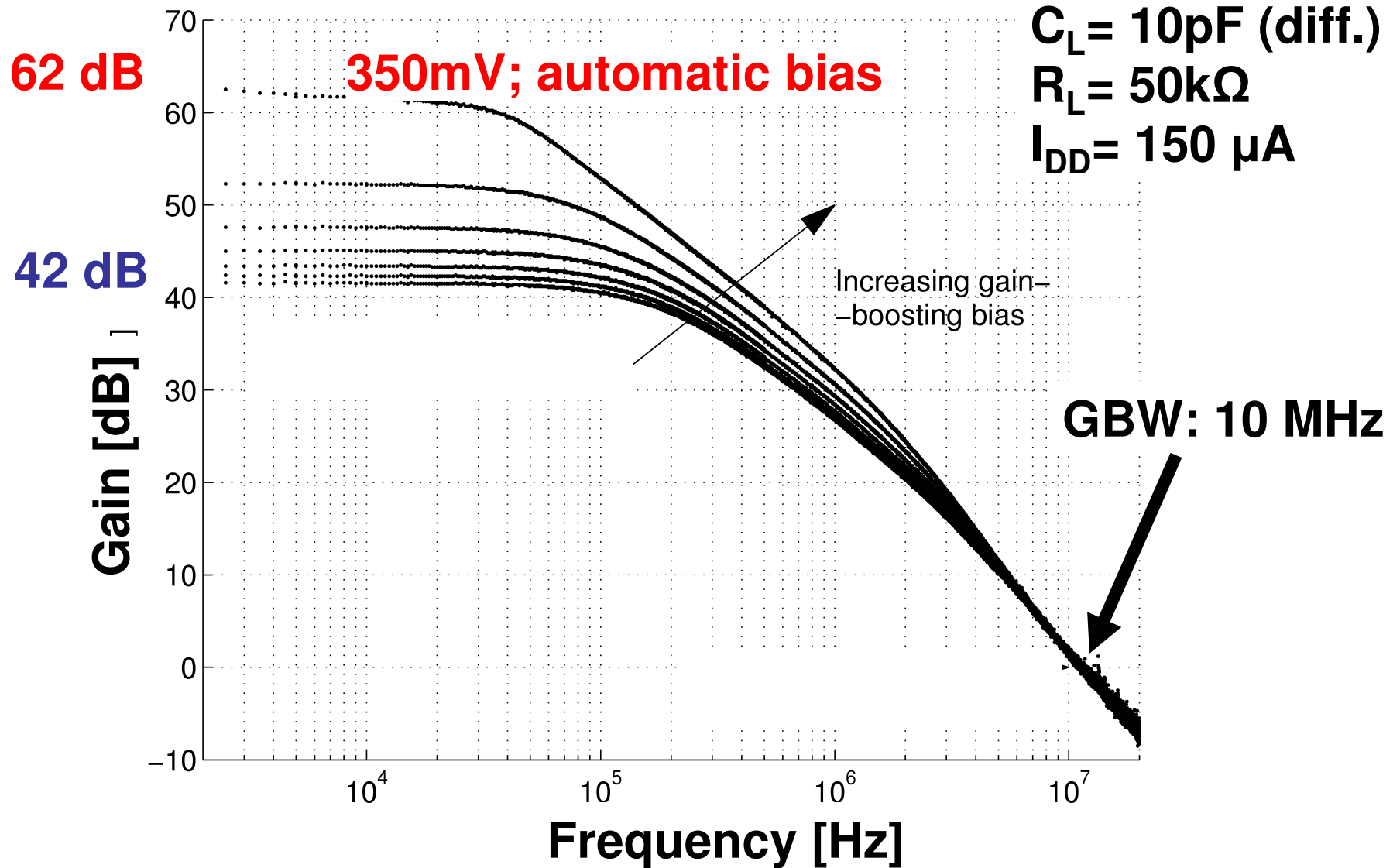
Two-stage fully differential 0.5 V OTA with Miller compensation



Setting common-mode voltages

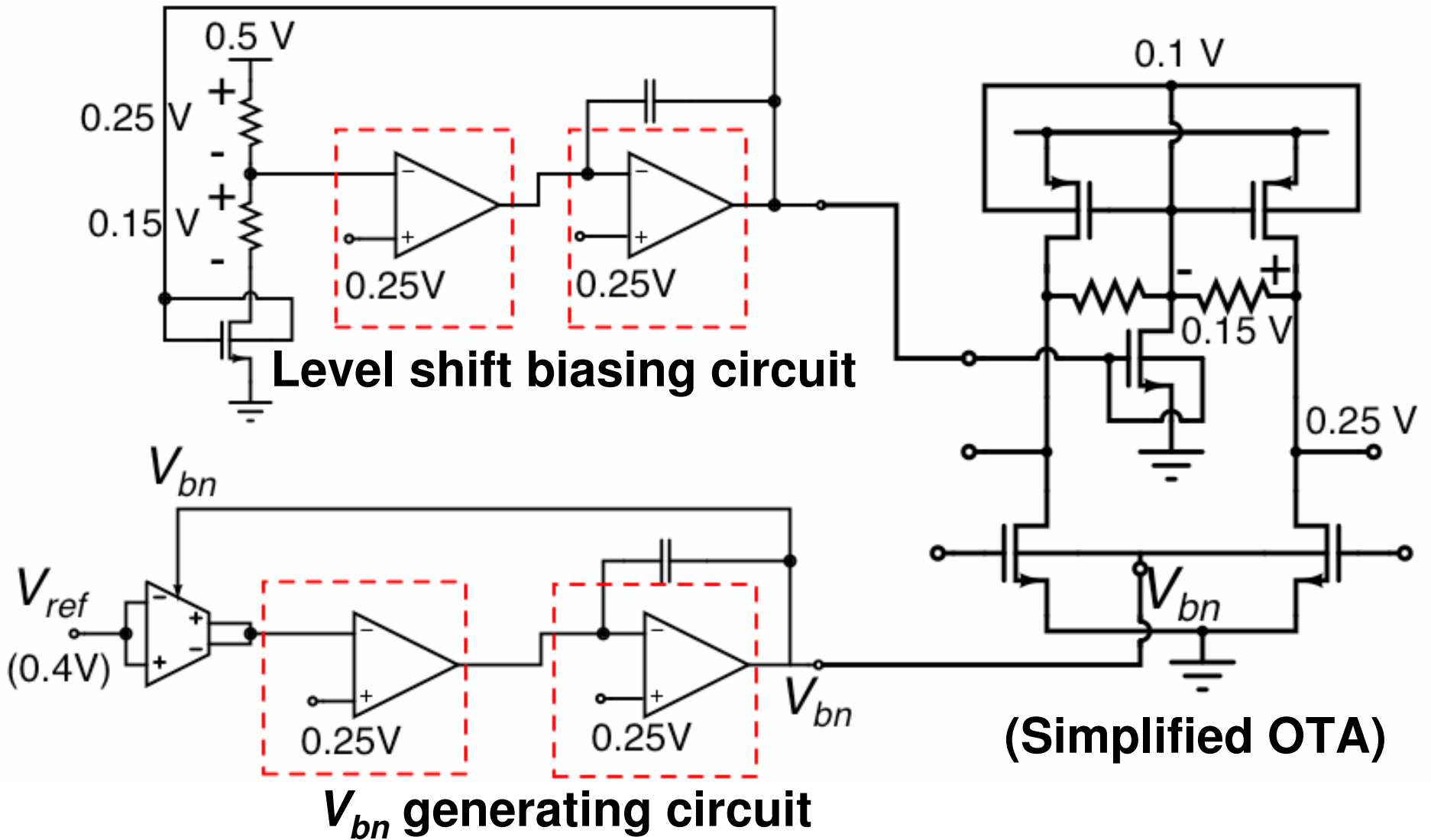


Open loop performance (meas.)

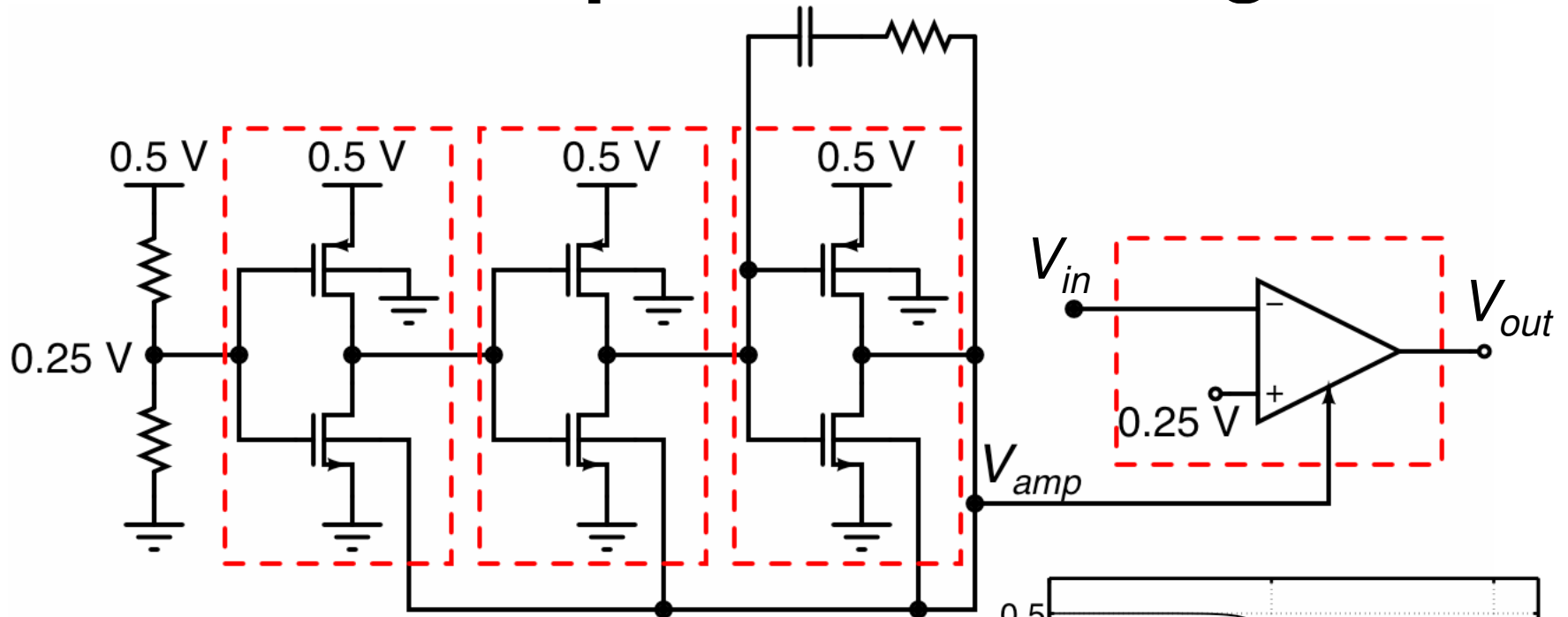


On-chip automatic biasing circuits

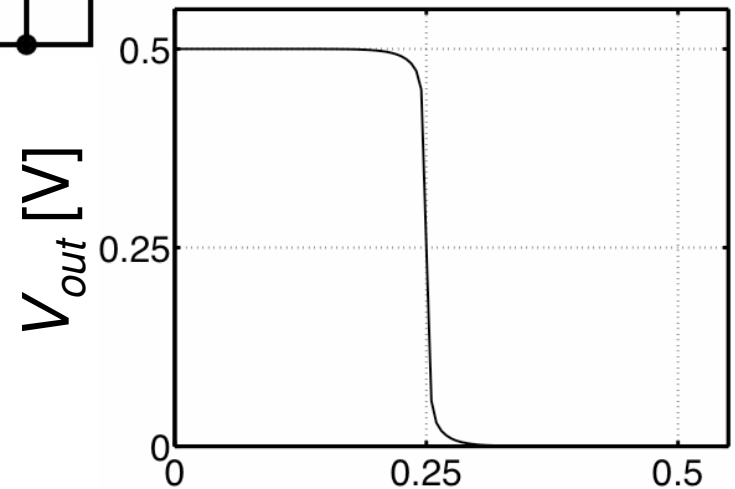
On-chip biasing circuits



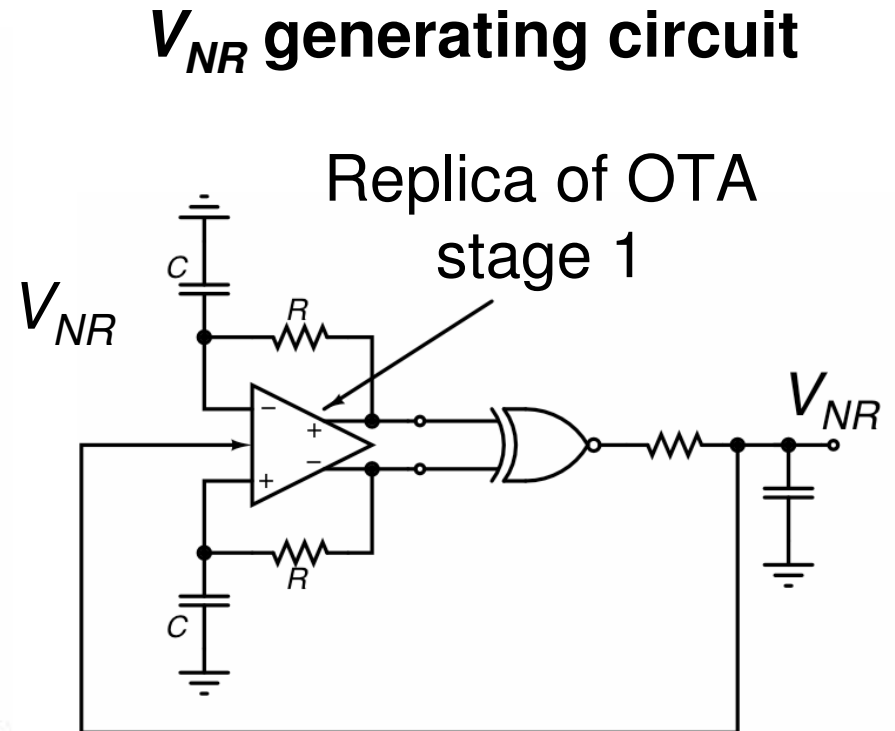
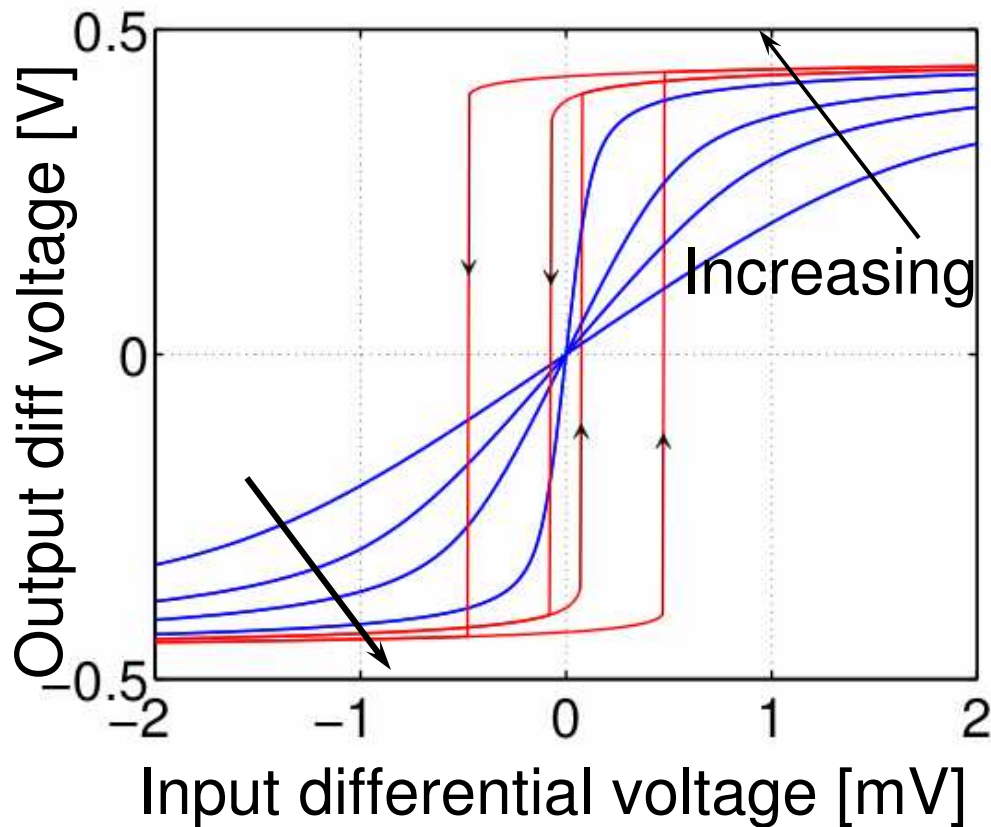
Error amplifier for biasing



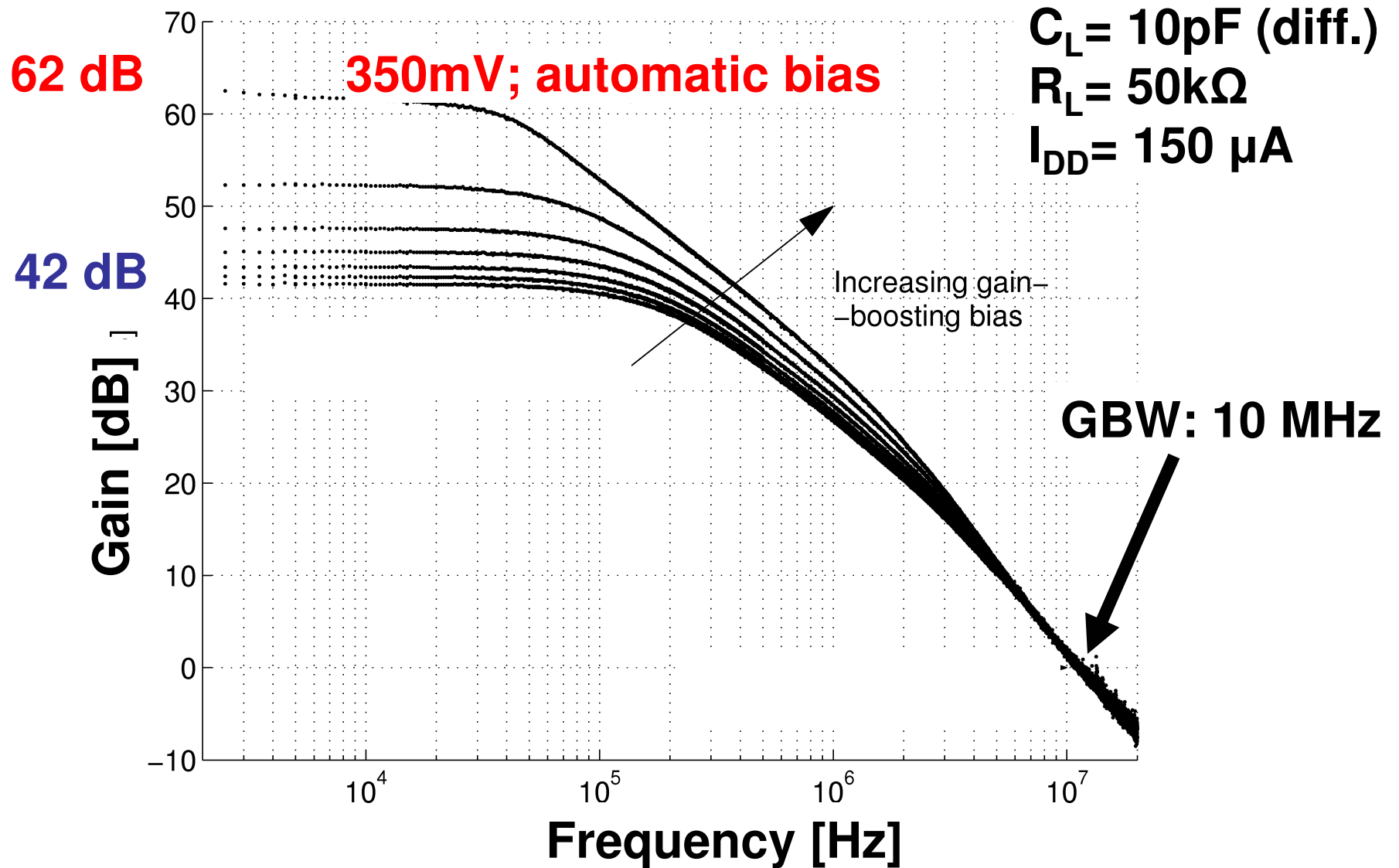
- 20 kHz GBW for 1 pF load
- 2 μ A current
- Controlled body voltage sets the amplifier threshold



OTA DC transfer characteristics and V_{NR} generation

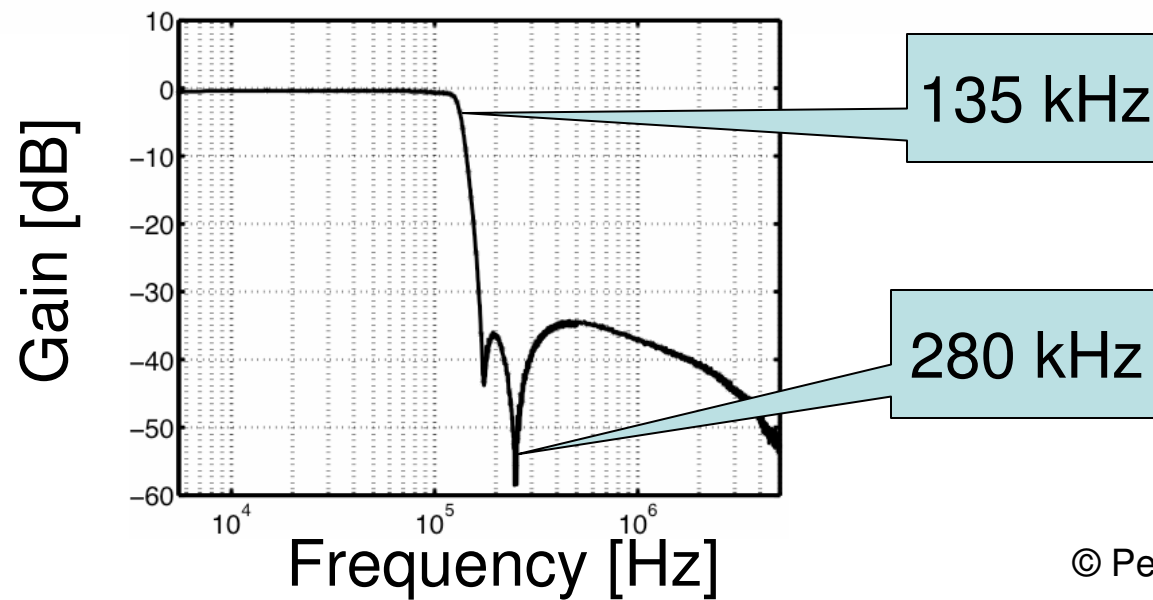
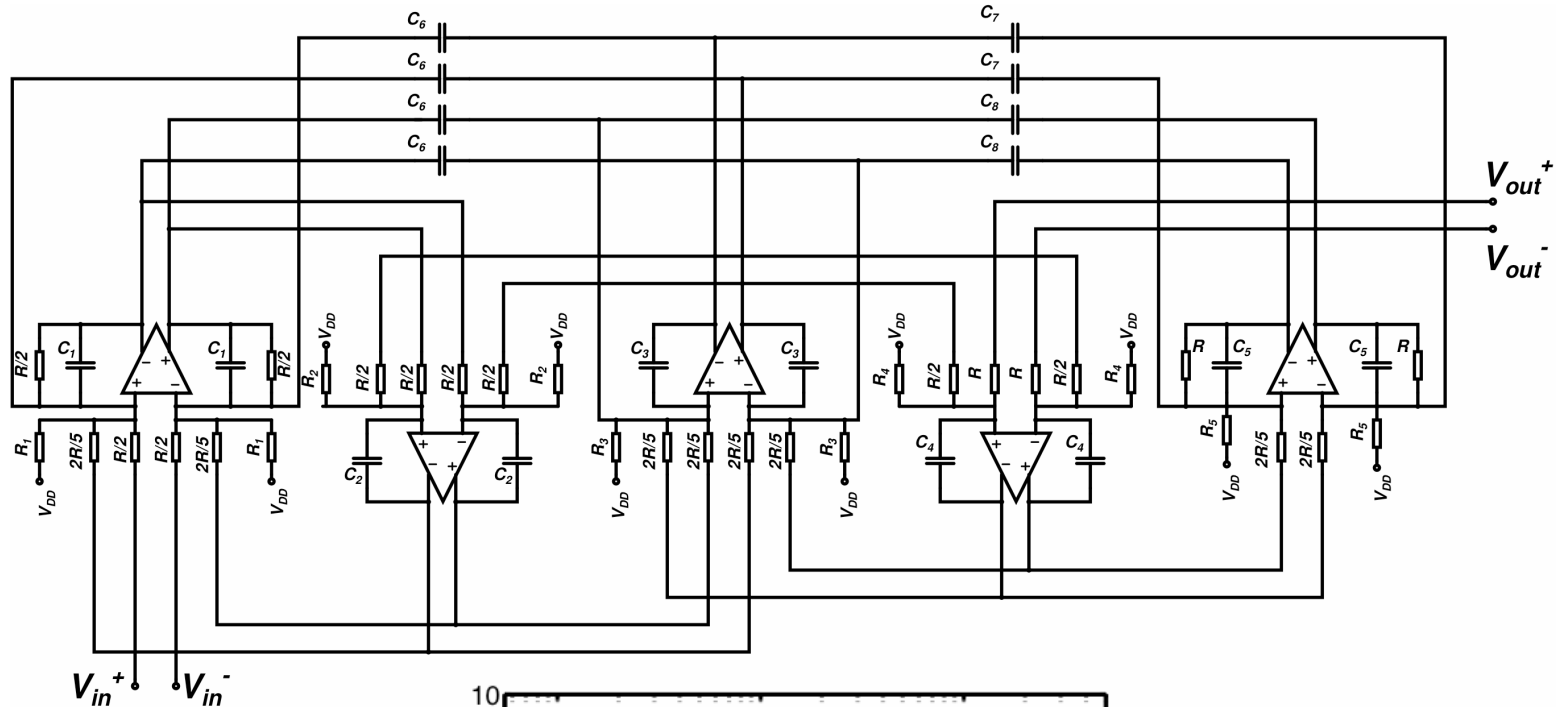


Open loop performance (meas.)



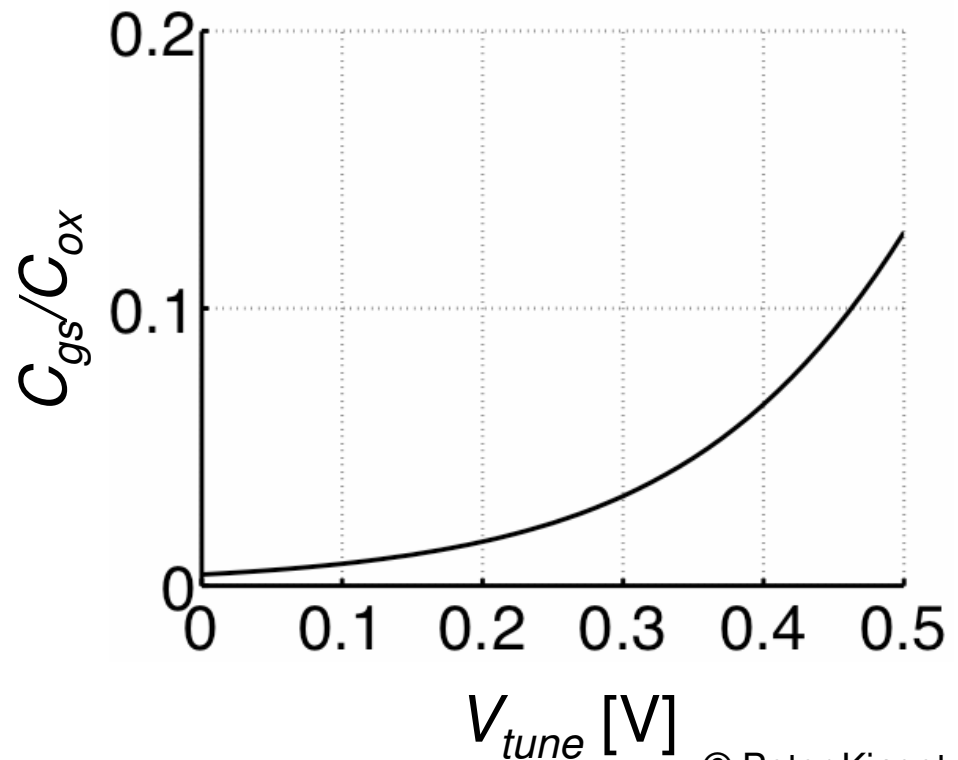
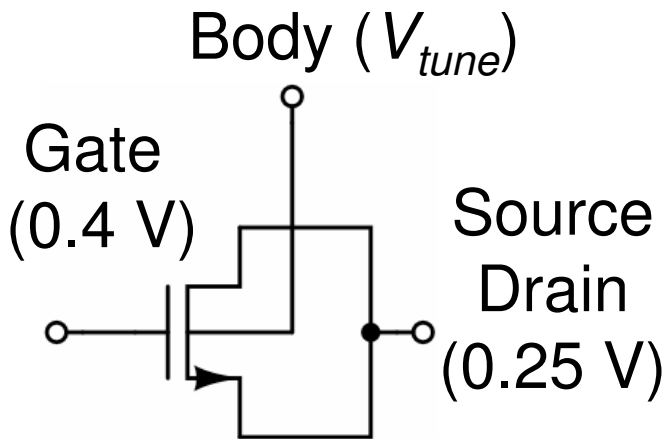
0.5 V Continuous time tunable active RC Filter

0.5 V 5th order elliptic LPF

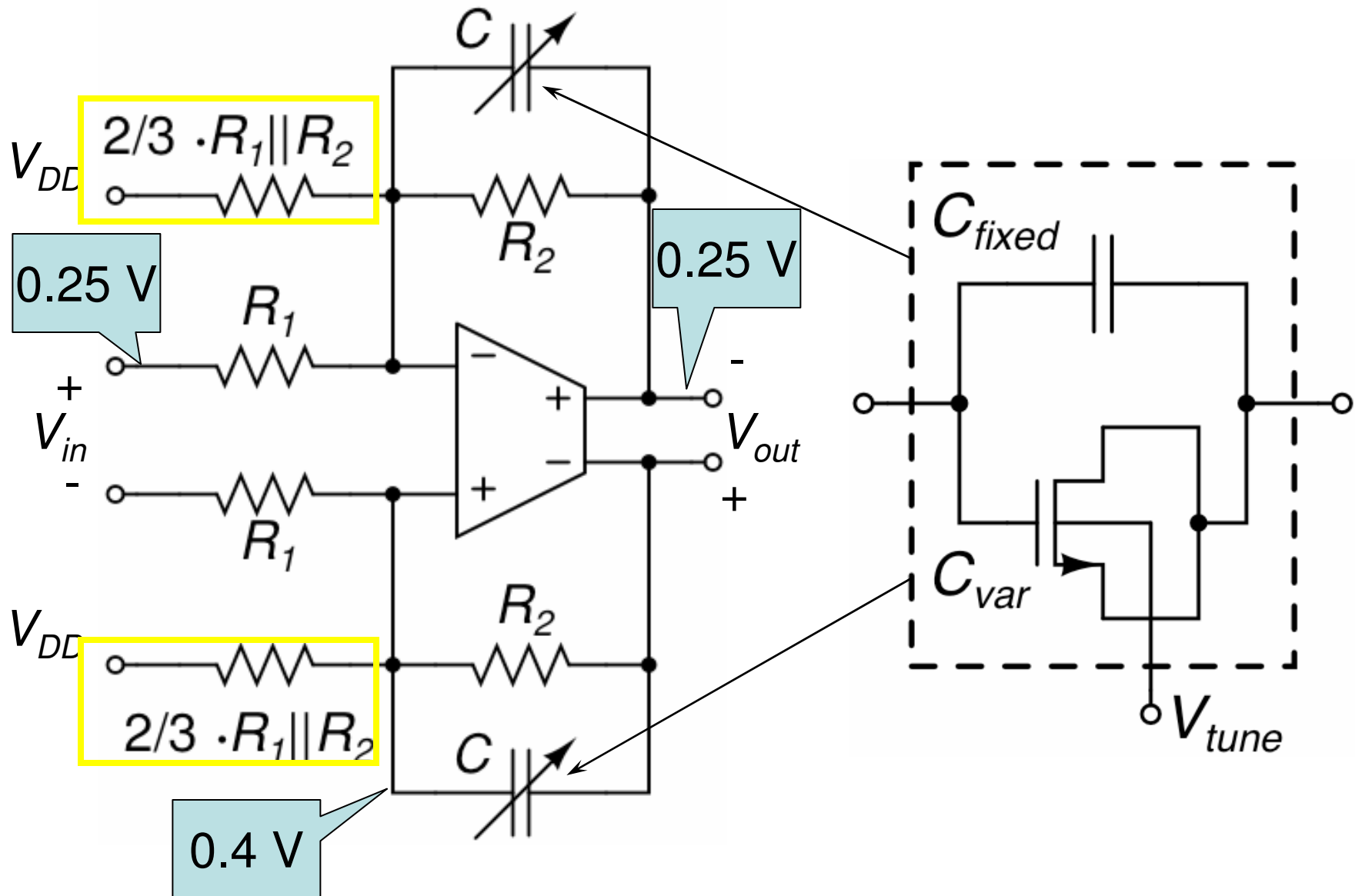


Filter tuning challenges at 0.5 V

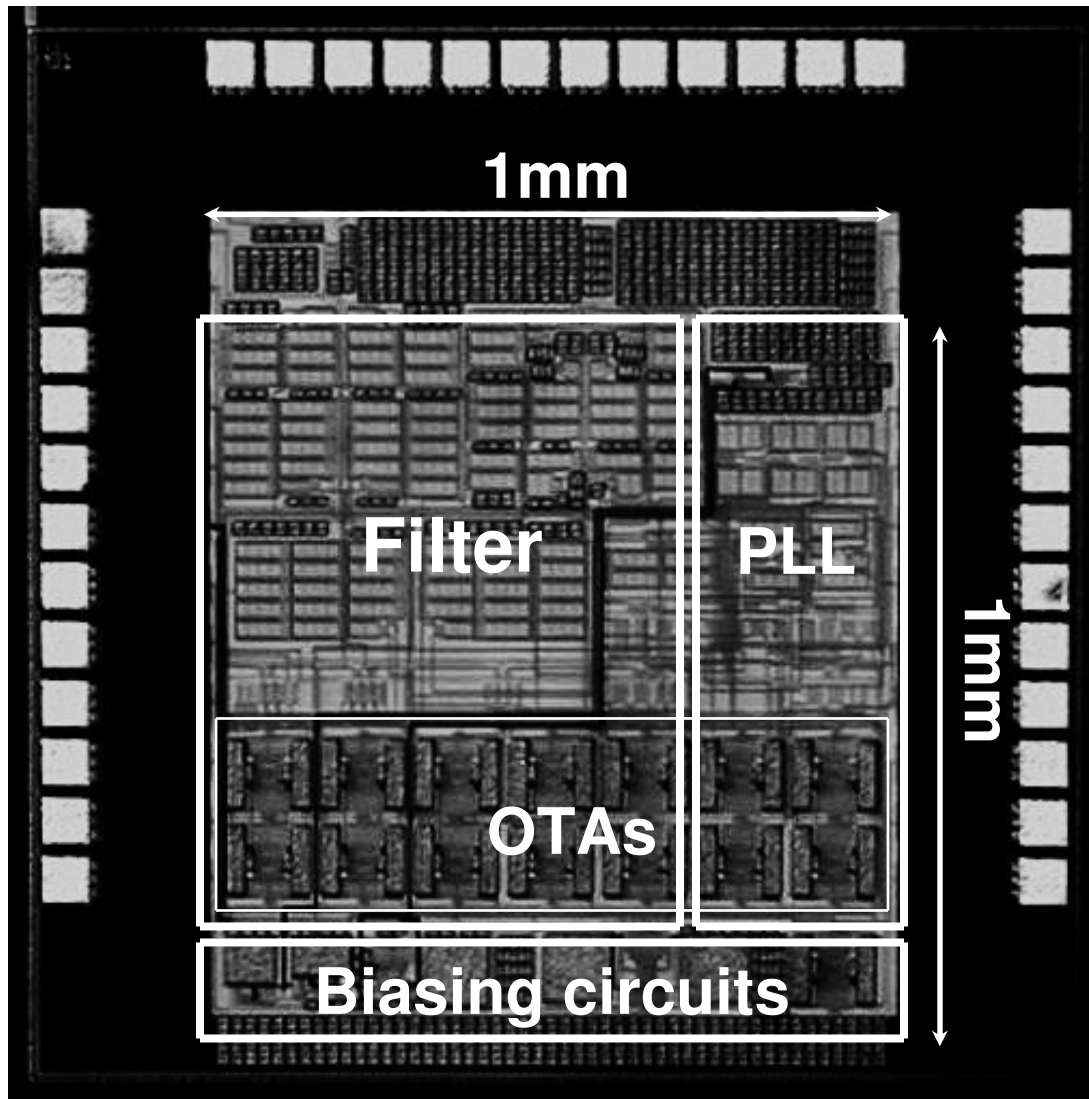
- Gm-C
- MOSFET-C
- Switching banks of R's and C's
- **Varactor-R techniques**



Low-voltage tunable integrator



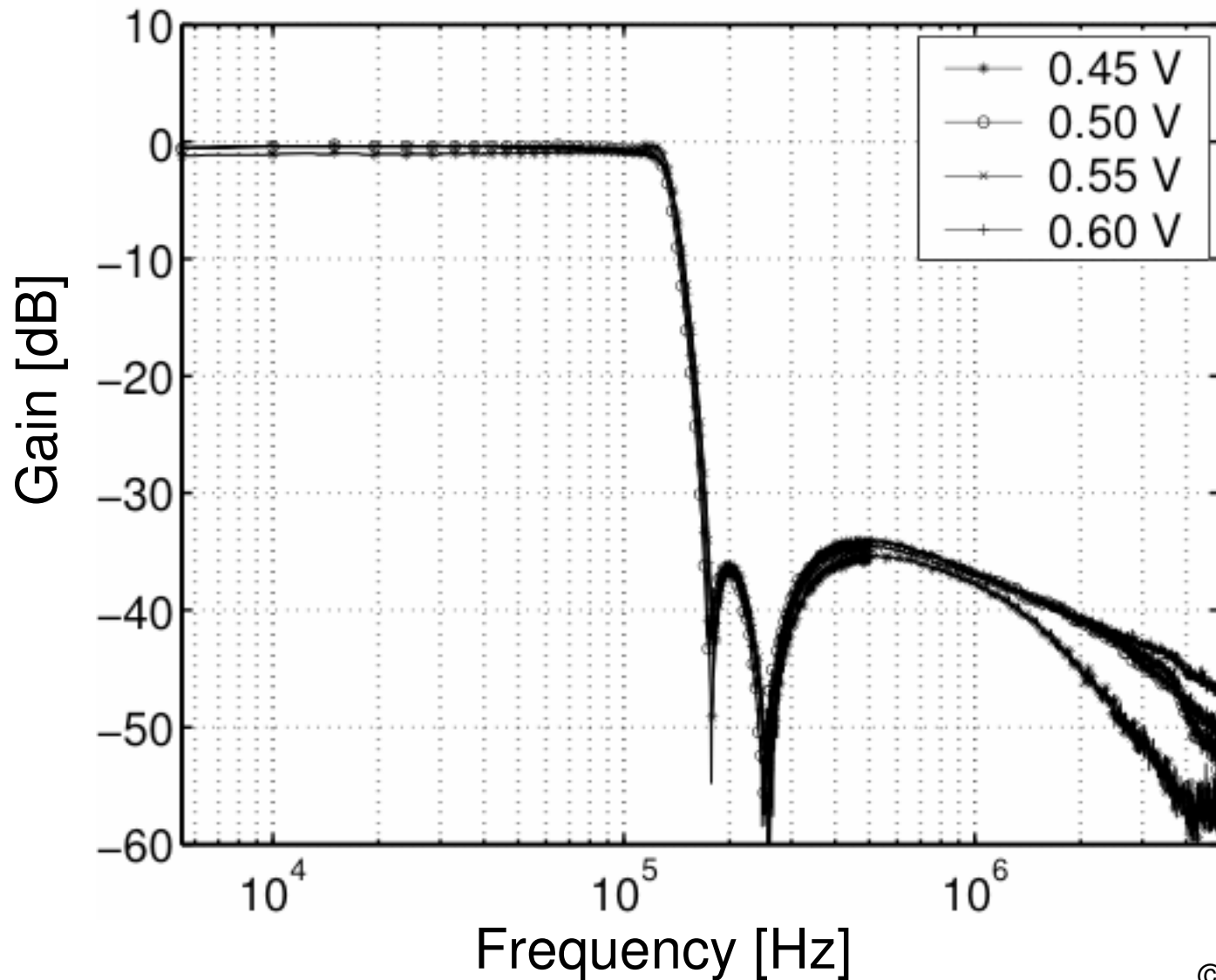
Die photograph



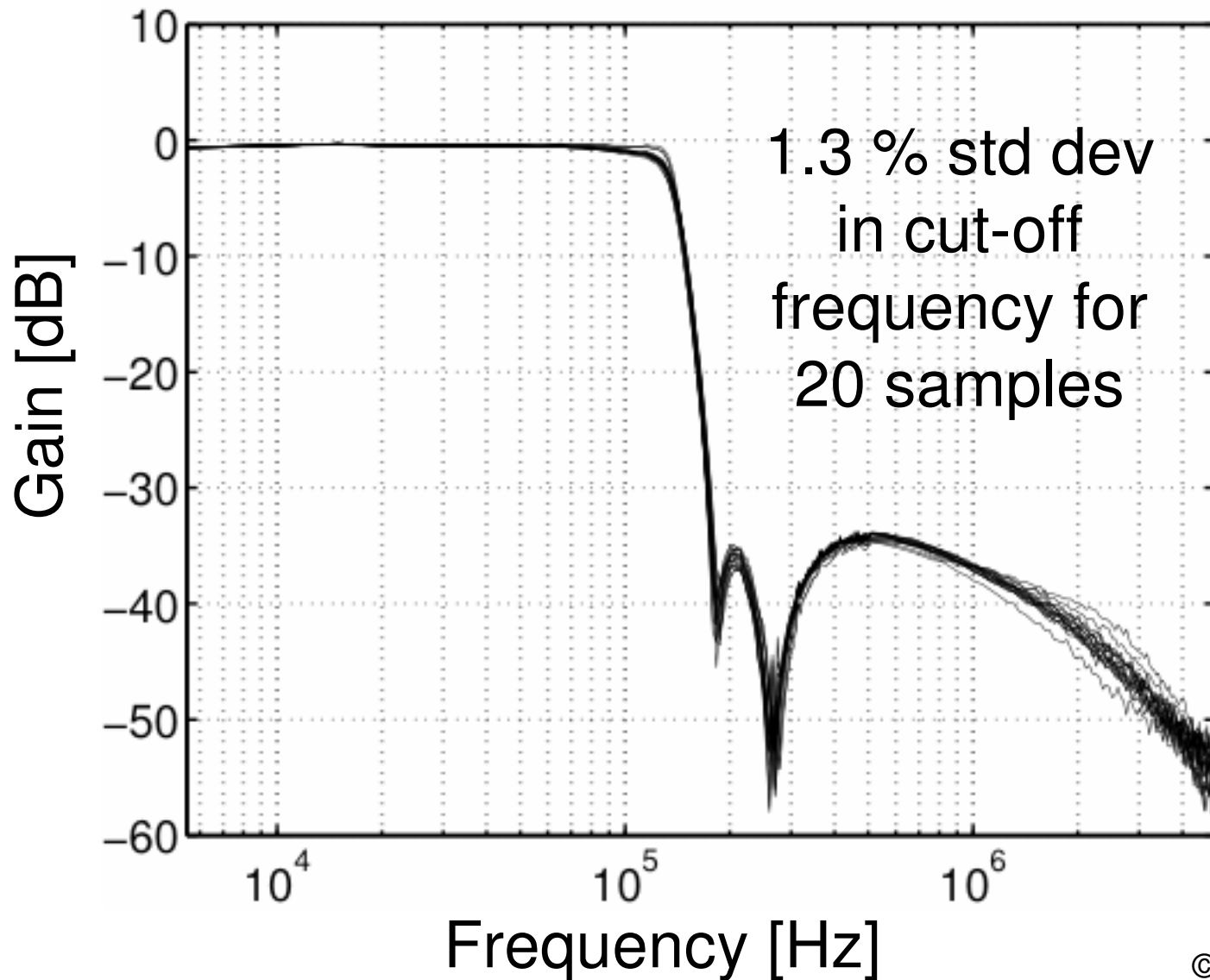
- 0.18 μm CMOS
- MIM capacitors
- High-res resistors
- Standard V_T
- Triple well devices

S. Chatterjee, Y. Tsvividis, and P. Kinget, "A 0.5 V filter with PLL-based tuning in 0.18 μm CMOS technology," in IEEE International Solid-State Circuits Conference (ISSCC), pp. 506-507, February 2005.

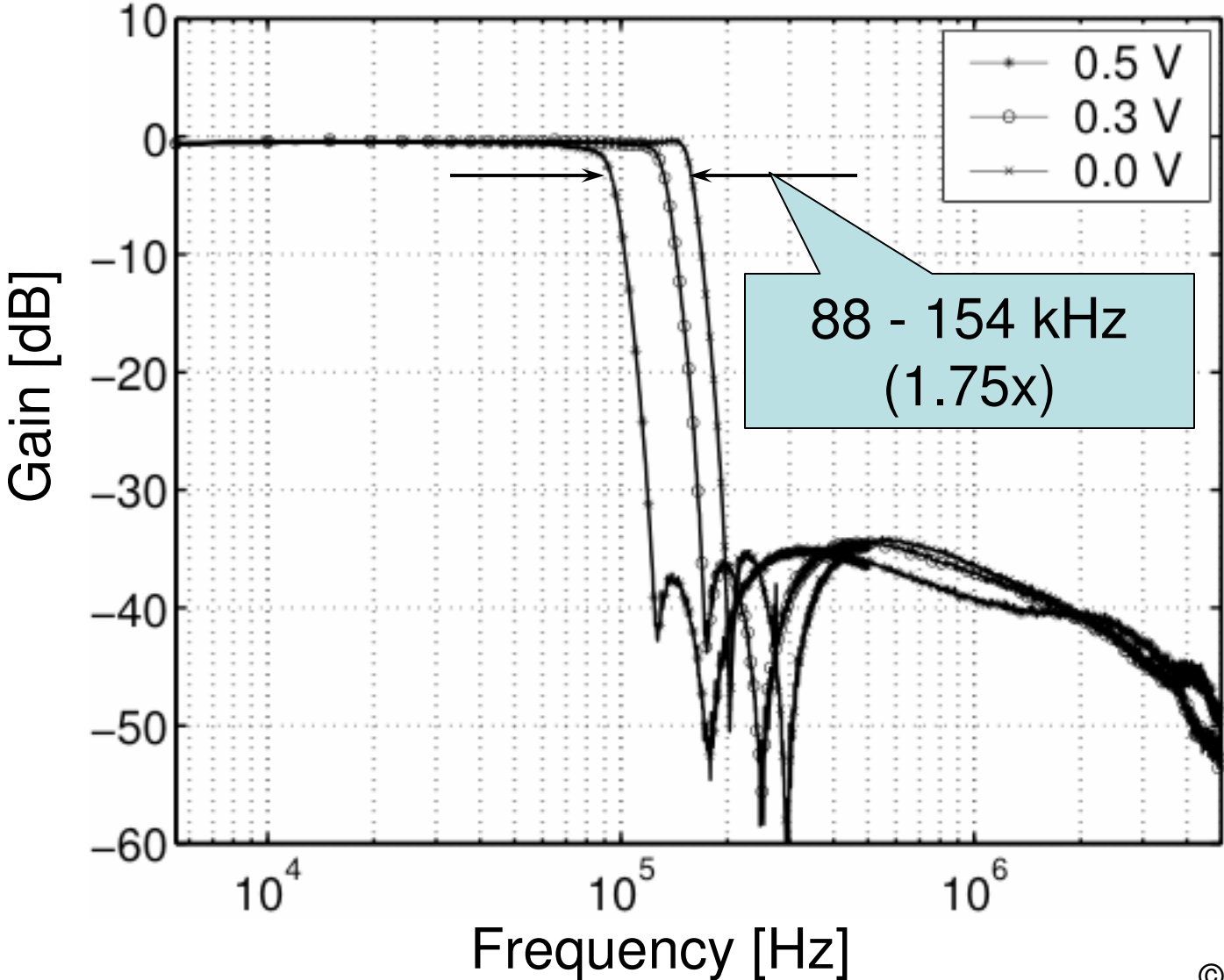
Measured filter response for different supply voltages



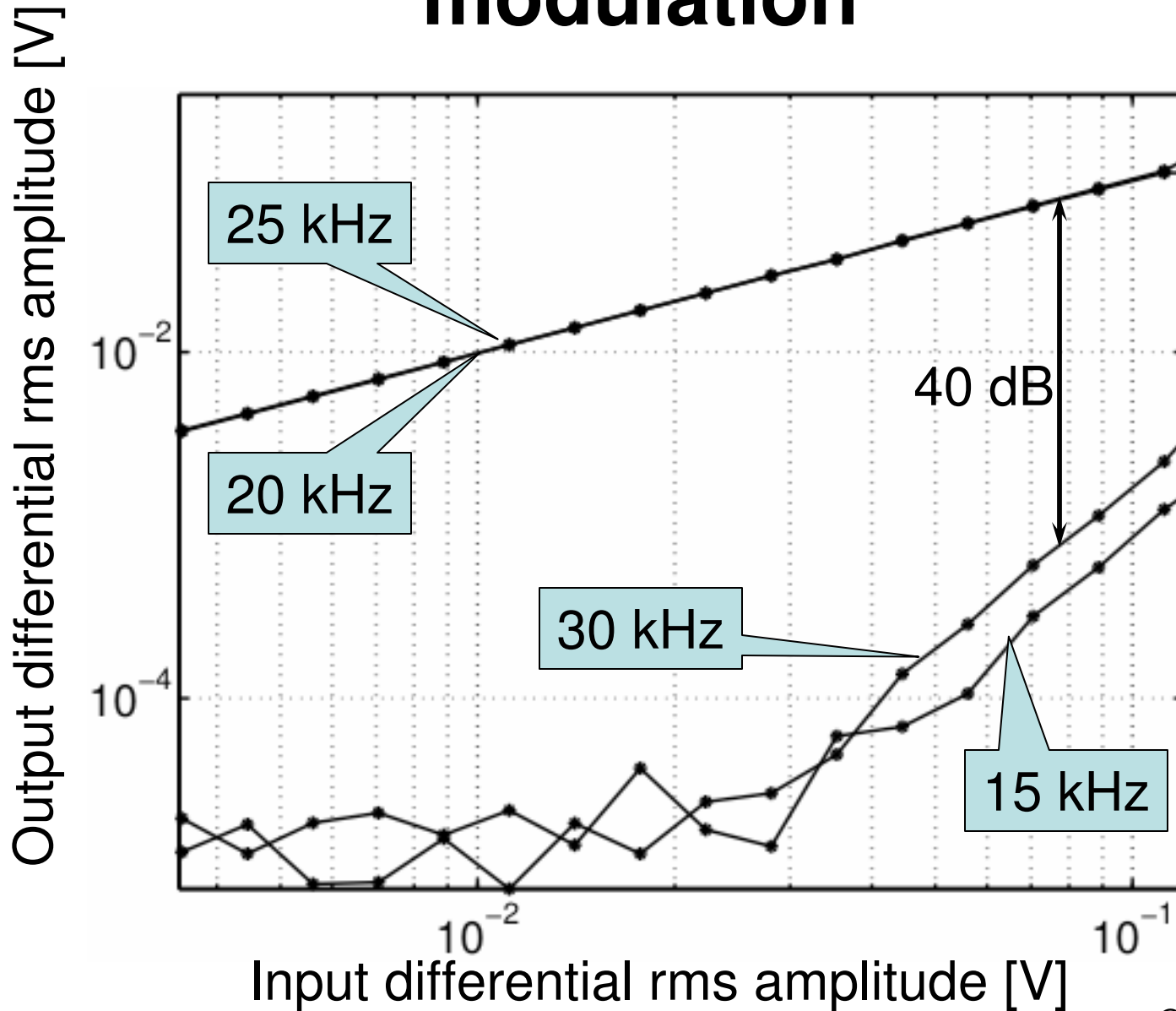
Measured filter response for different chips



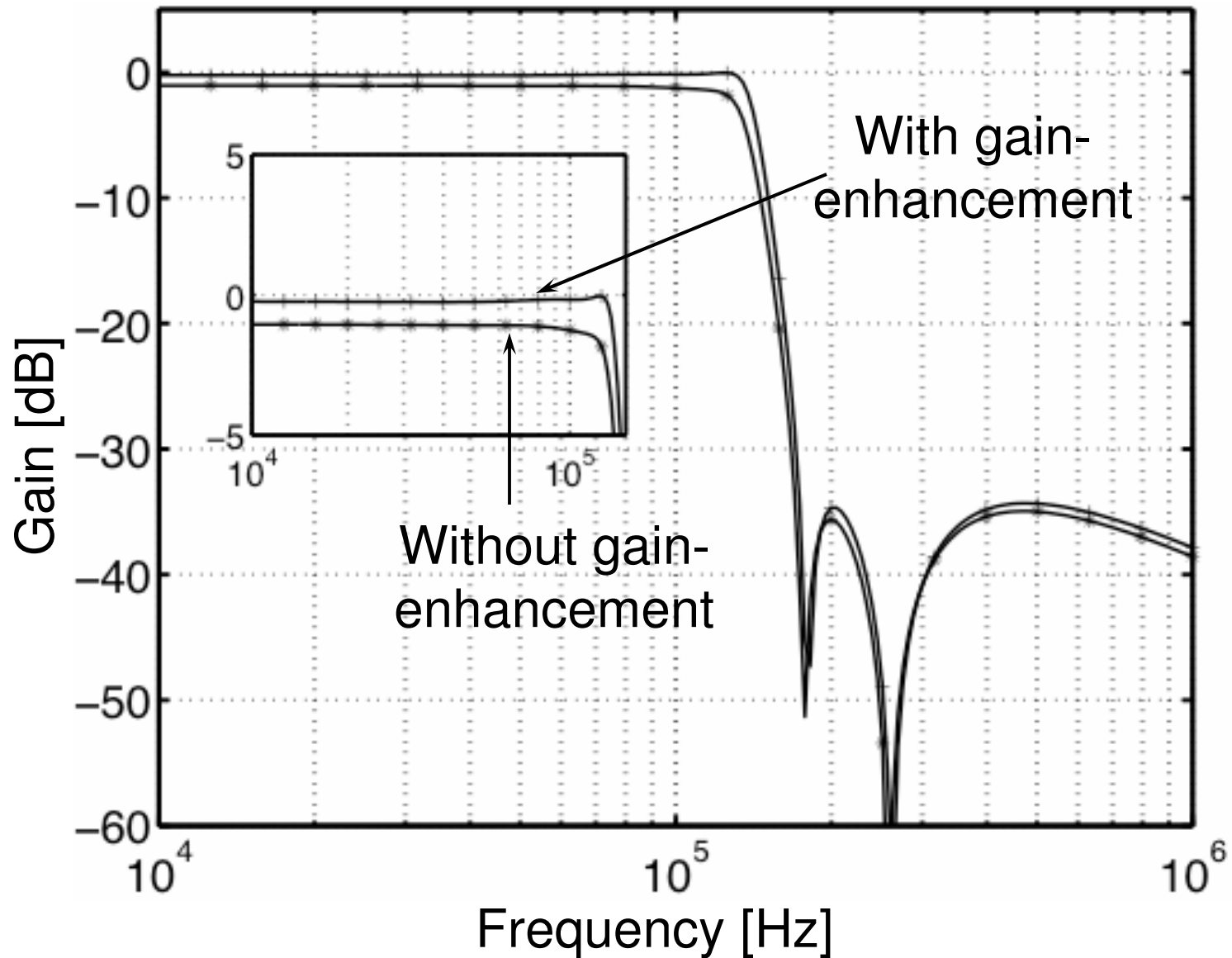
Measured filter response for different tuning voltages



Measured 3rd order inter-modulation



Effect of gain enhancement



Performance summary at 27C

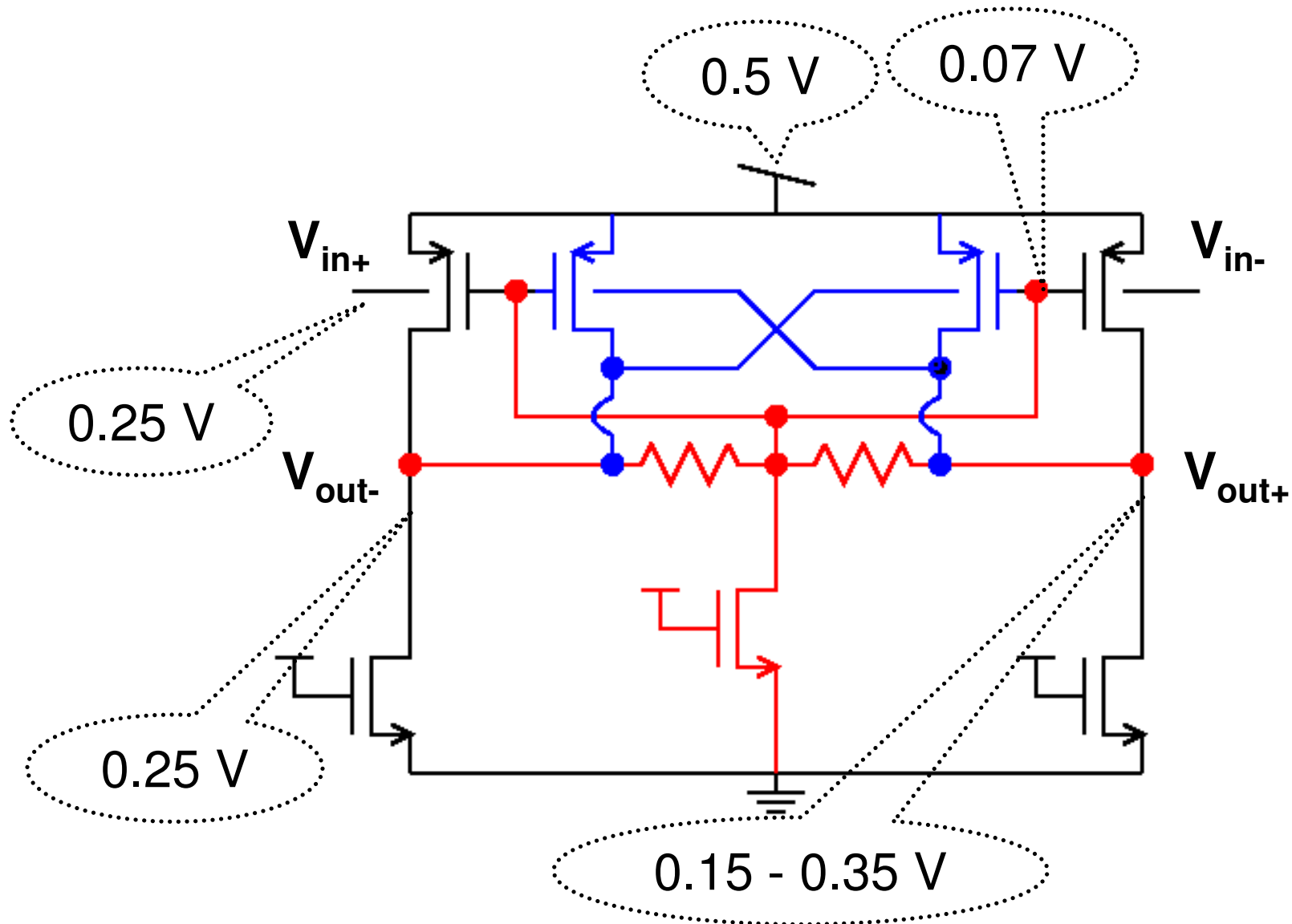
V_{DD} [V]	0.45	0.50	0.55	0.60	
-3 dB cut-off frequency [kHz]	135.0	135.0	135.0	135.0	
Total current [mA]	1.5	2.2	3.3	4.3	
Noise [μ V rms]	87	74	68	65	
Input [mV rms] (100kHz / 1% THD)	50	50	50	50	
In-band IIP ₃ [dBV]	-5	-3	-3	-3	
Out-of-band IIP ₃ [dBV]	3	5	3	5	
Dynamic range [dB]	55	57	57	58	
Tuning range [kHz]	$V_{tune} = V_{DD}$	96.5	88.0	84.5	69.0
	$V_{tune} = 0.0$ V	153.0	154.5	148.0	150.5
VCO feed-thru @280kHz [μ V rms]	104	85	72	72	

- Measured CMRR (10 kHz common mode tone): 65 dB
- Measured PSRR (10 kHz tone on power supply): 43 dB

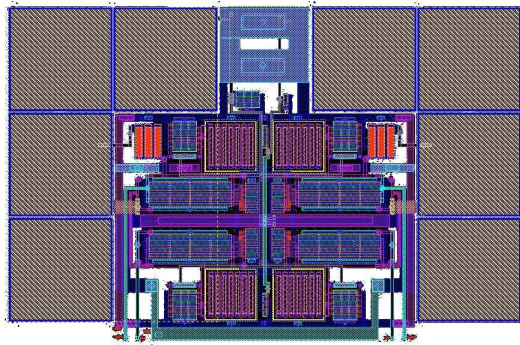
Functionality tested from 5C to 85C at 0.5 V

0.5 V Body-input OTA

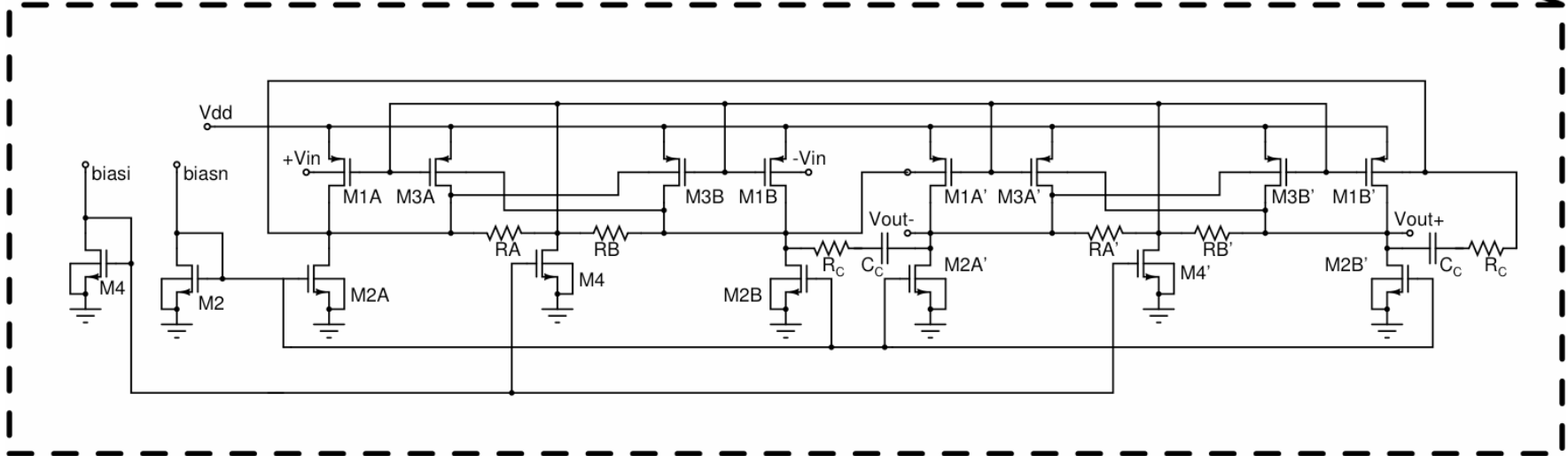
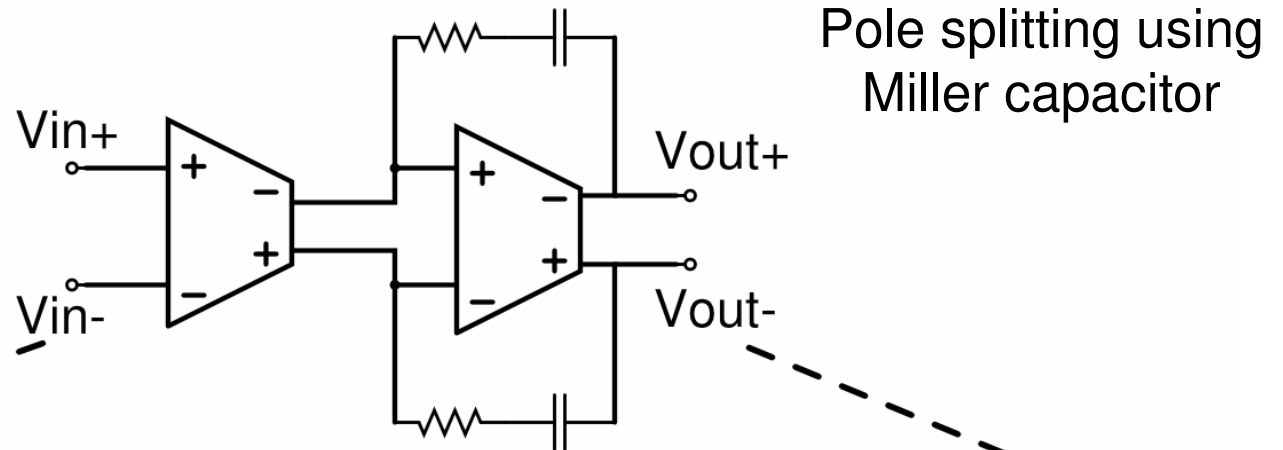
0.5 V Body-input OTA stage



Two-stage fully-differential OTA

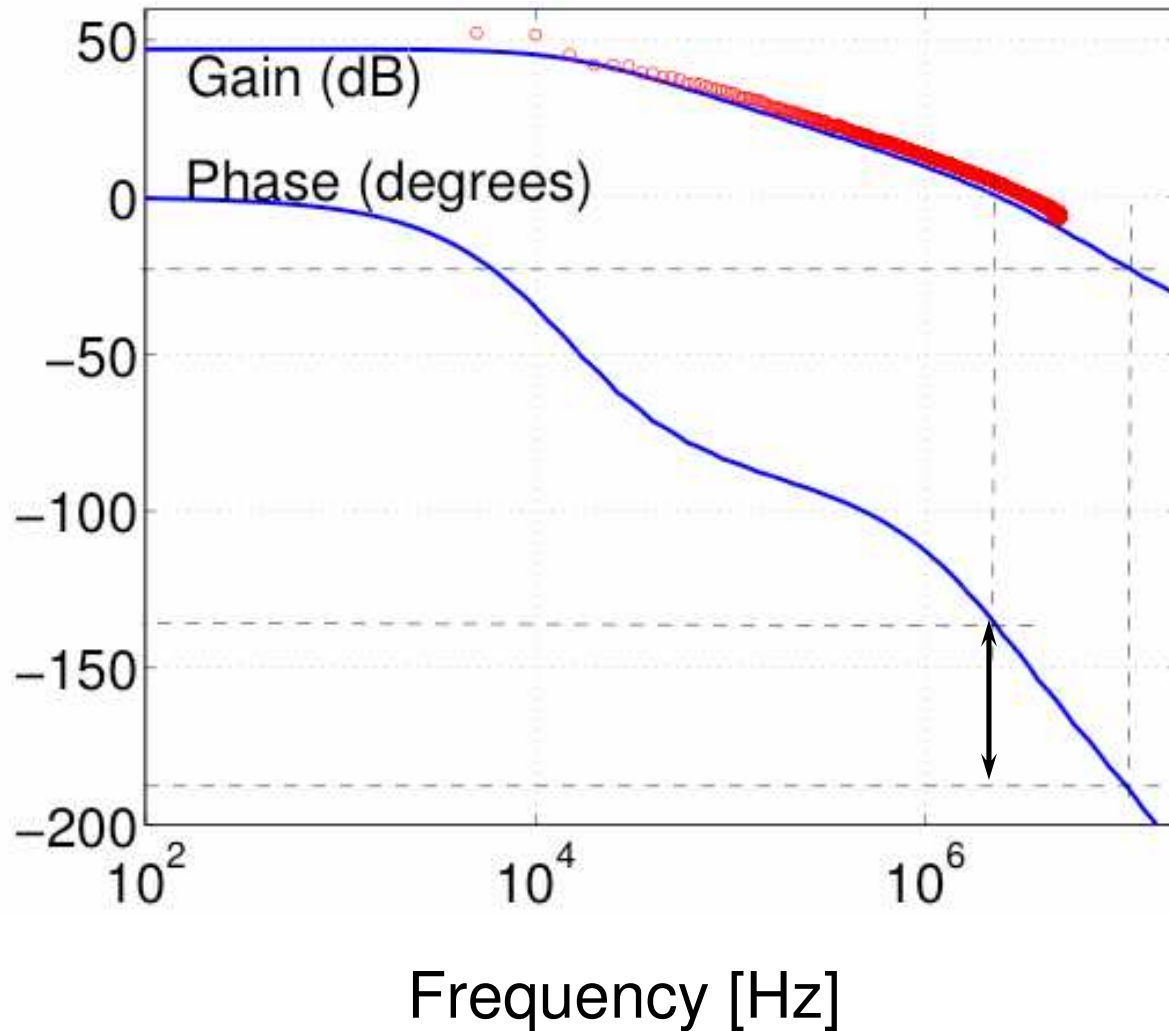


0.18 μm CMOS



S. Chatterjee, Y. Tsvetkov, and P. Kinget, "A 0.5 V bulk input fully differential operational transconductance amplifier," in European Solid-State Circuits Conference (ESSCIRC), pp.147-150, September 2004.

Open loop frequency response



DC gain: 52 dB

GBW: 2.5 MHz

.....
Measurement

—————
Simulation

Phase Margin: 45°

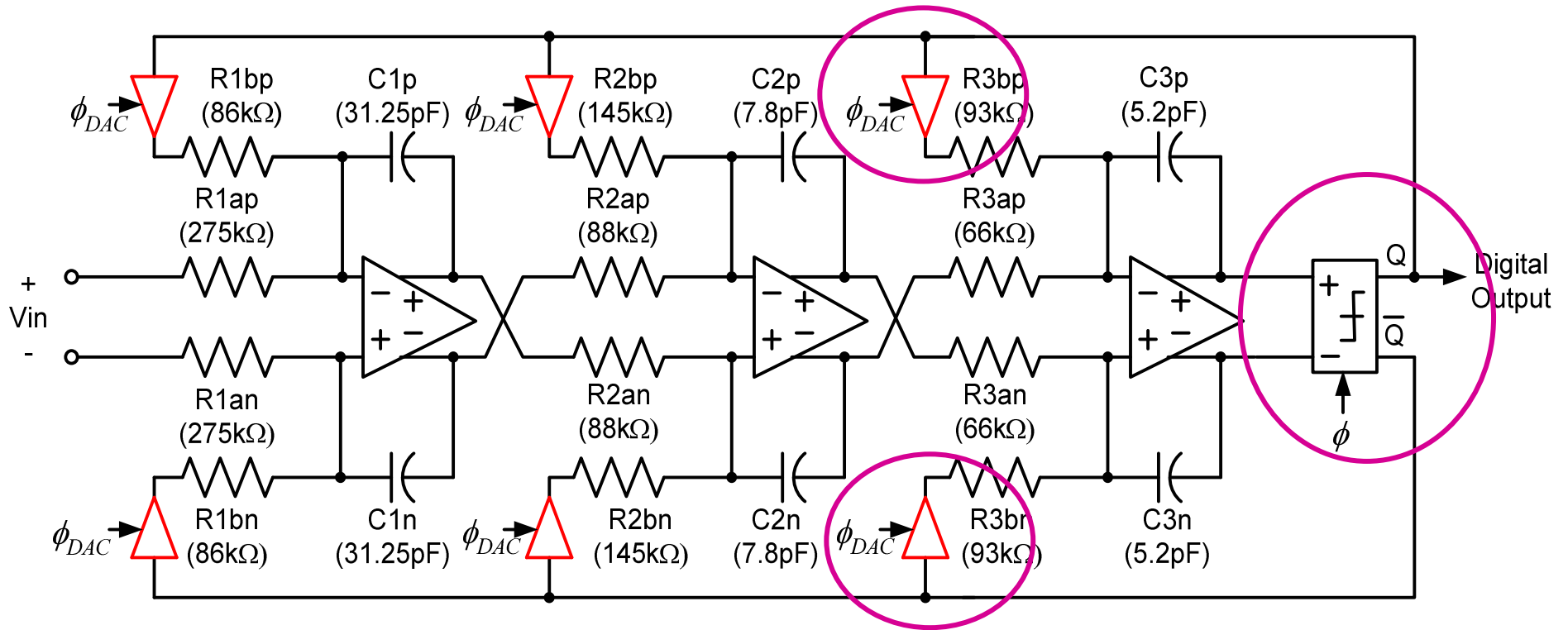
	[Bla 98]	[Las 00]	[Leh 01]	[Sto 02]	[Fer 96]	[Pel 98]	B-I	G-I
V_{DD} [V]	1	1	0.8	0.9	1.3	0.9	0.5	0.5
A_{DC} [dB]	49	70	53	70	84	59	52	50/62
GBW [MHz]	1.3	0.2	1.3	6e-3	1.3	4	2.5	10
Power [μ W]	300	5	-	0.5	460	-	110	75
C_L [pF]	22	7	20	12	-	14	10	10
SE/Diff.	S	S	S	S	S	D	D	D
Techn. [μ m]	2	0.35	0.5	2.5	0.7	0.5	0.18	0.18
Special Devices	Lat. BJT	-	Lat. BJT	Depl. MOS	-	-	-	-
100 η [1/V]	9.5	28		13			11.4	66.7

S. Chatterjee, Y. Tsvividis and P. Kinget, "0.5 V Analog Circuit Techniques and Their Application in OTA and Filter Design," IEEE Journal of Solid-State Circuits (JSSC), vol. 40, no 12, pp. 2373 - 2387, December 2005.

$$\eta = \frac{GBW \cdot C_L}{I_{supply}}$$

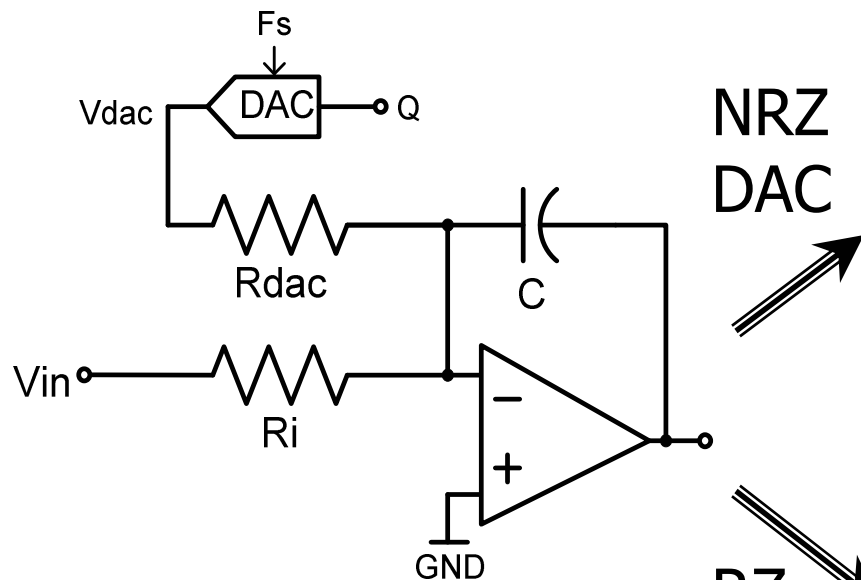
**A 0.5V 74dB SNDR 25kHz
CT $\Sigma\Delta$ Modulator
with Return-to-open DAC**

3rd order CT $\Sigma\Delta$ Modulator



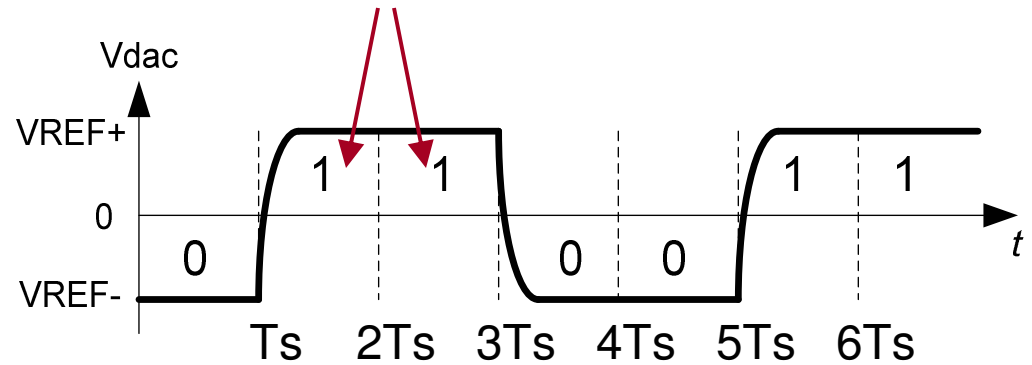
Using Active RC integrators

Continuous-time $\Sigma\Delta$ Modulator: Need of Return-to-zero DAC



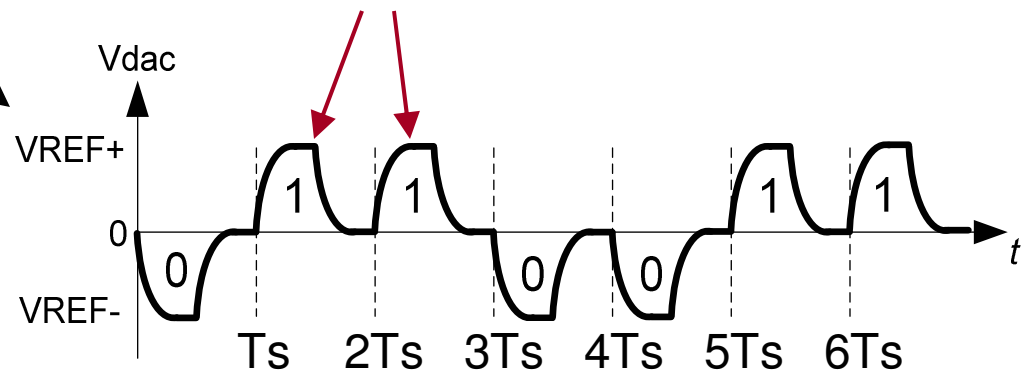
NRZ
DAC

ISI exists: area for each “1” depends on its previous symbol.

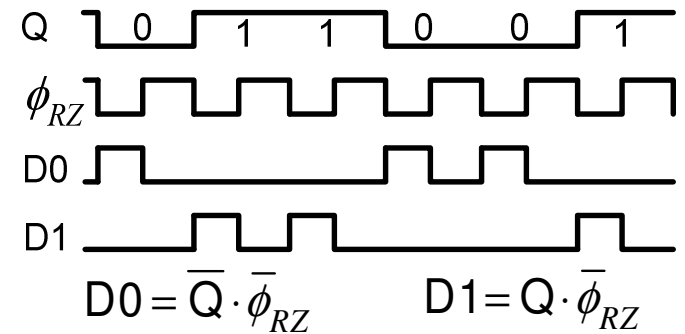
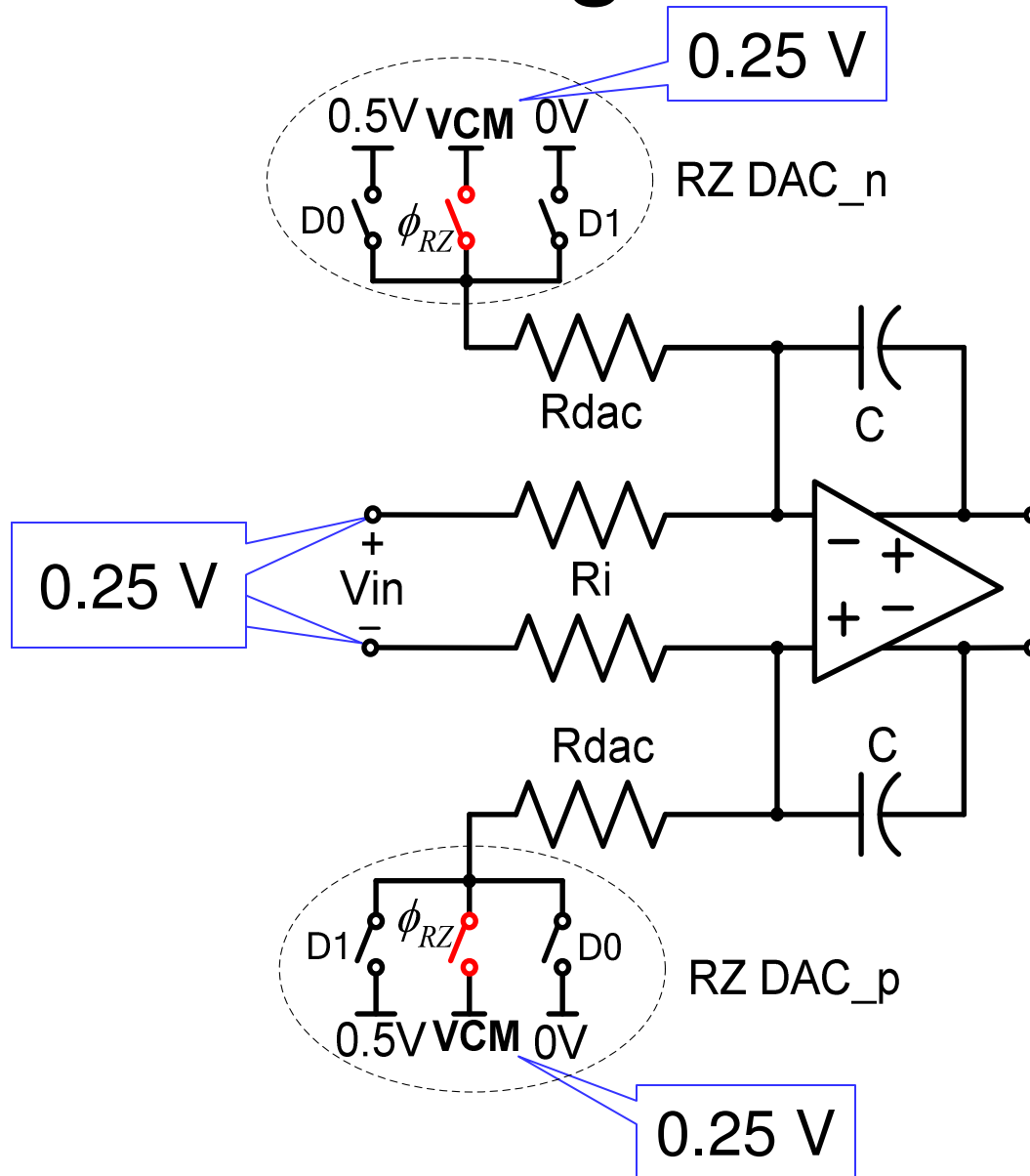


RZ
DAC

No ISI: same area for all “1”s.

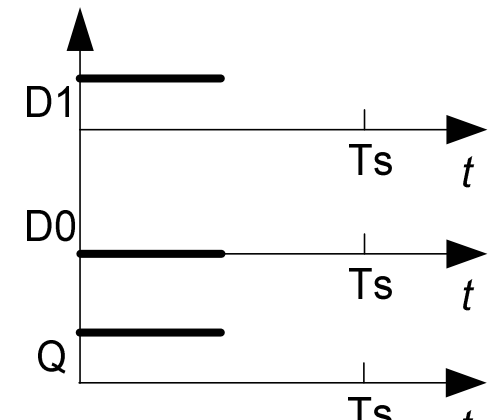
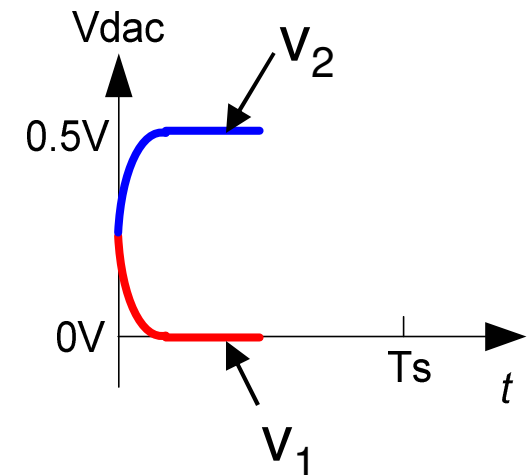
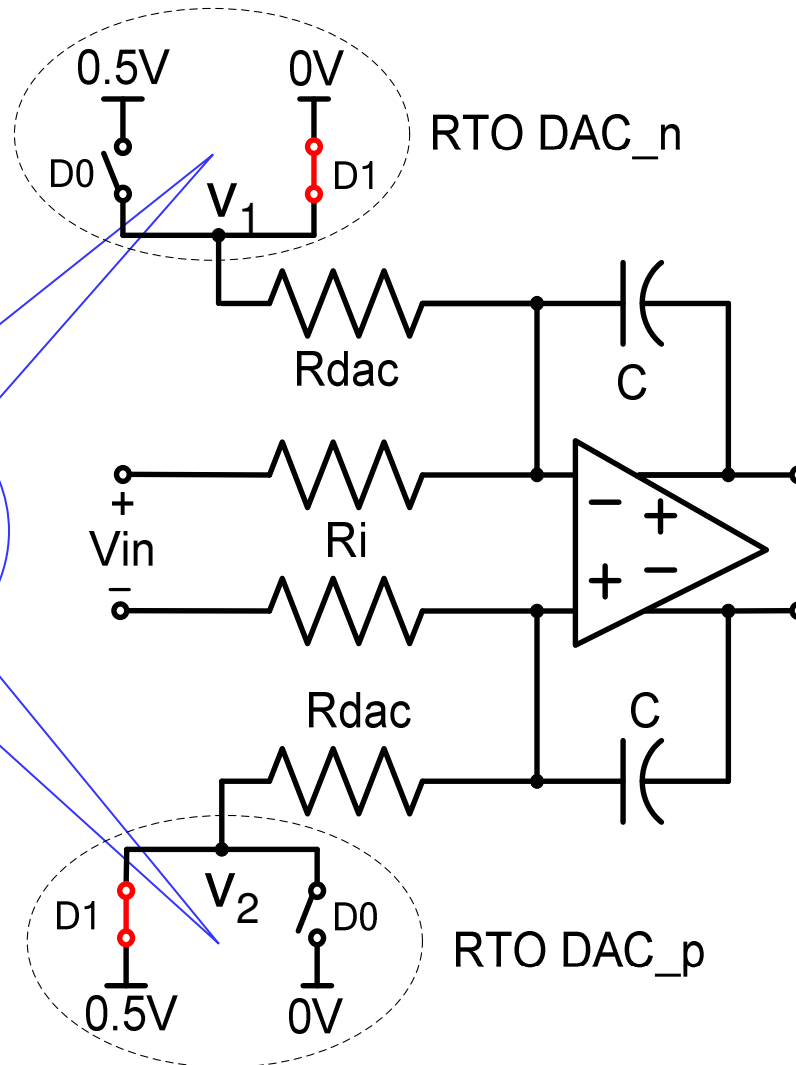


RZ Challenge: Switches at $V_{DD}/2$



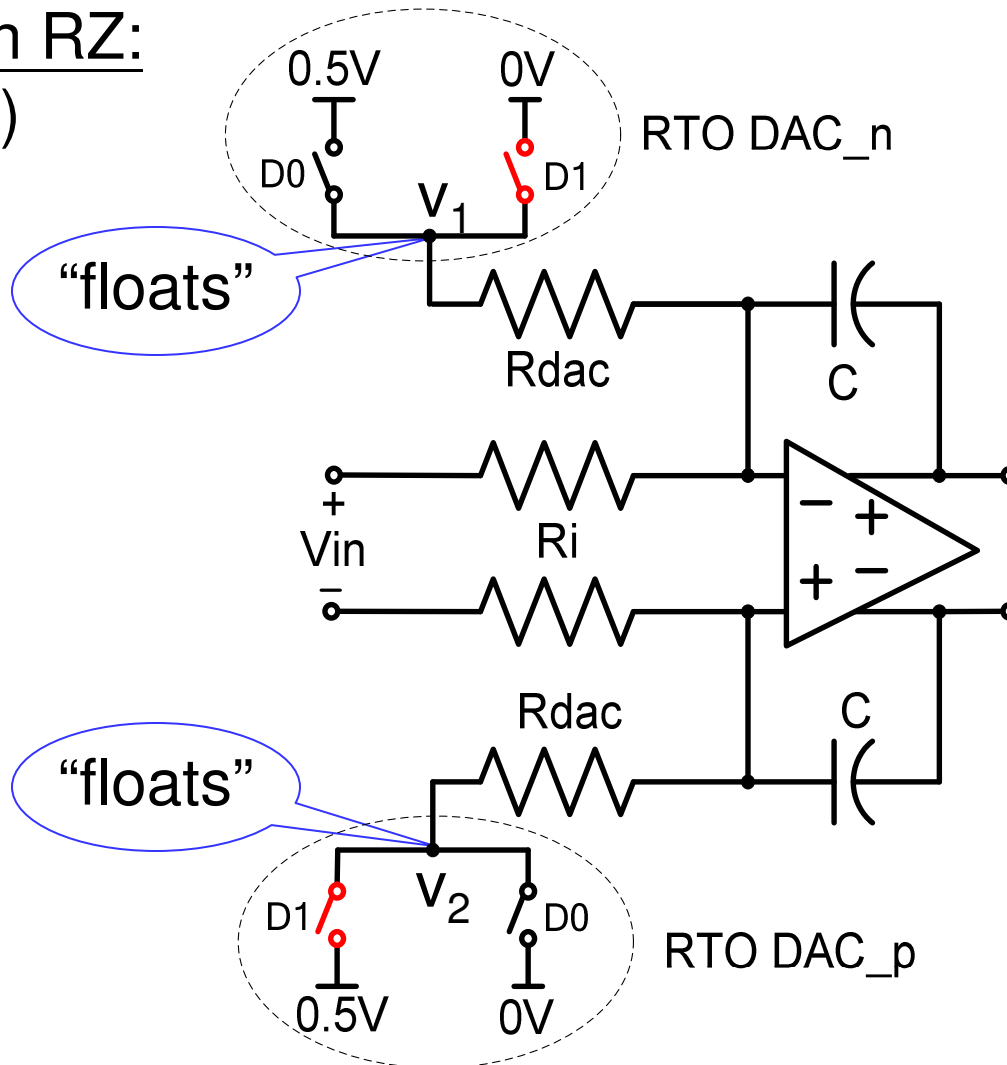
Solution: Return-to-open

Before RZ:
(Q=1)



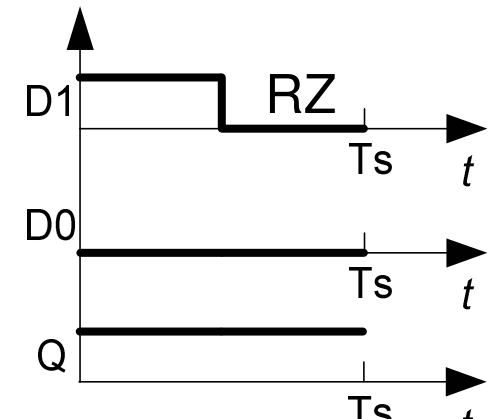
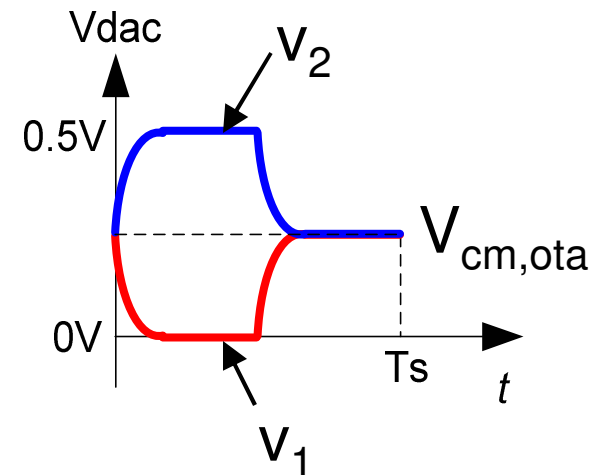
Solution: Return-to-open

When RZ:
(Q=1)



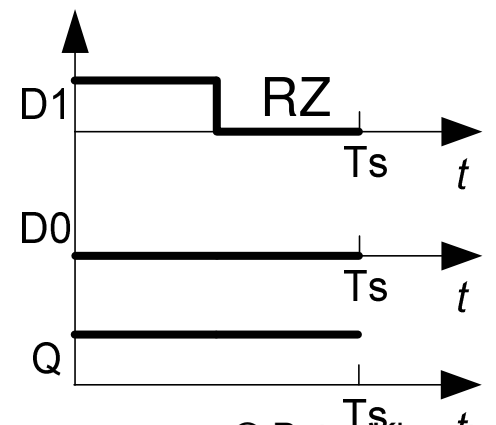
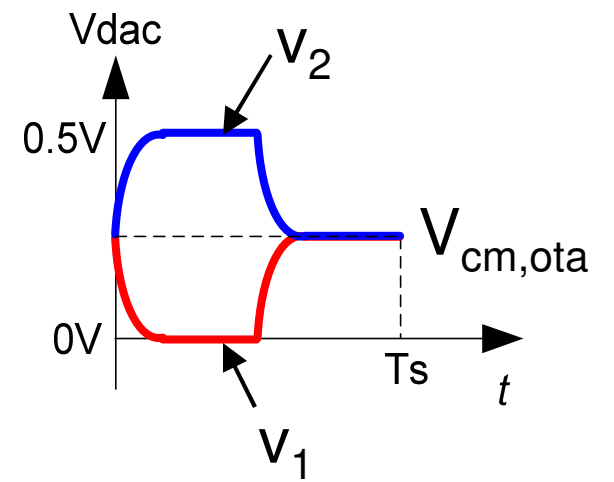
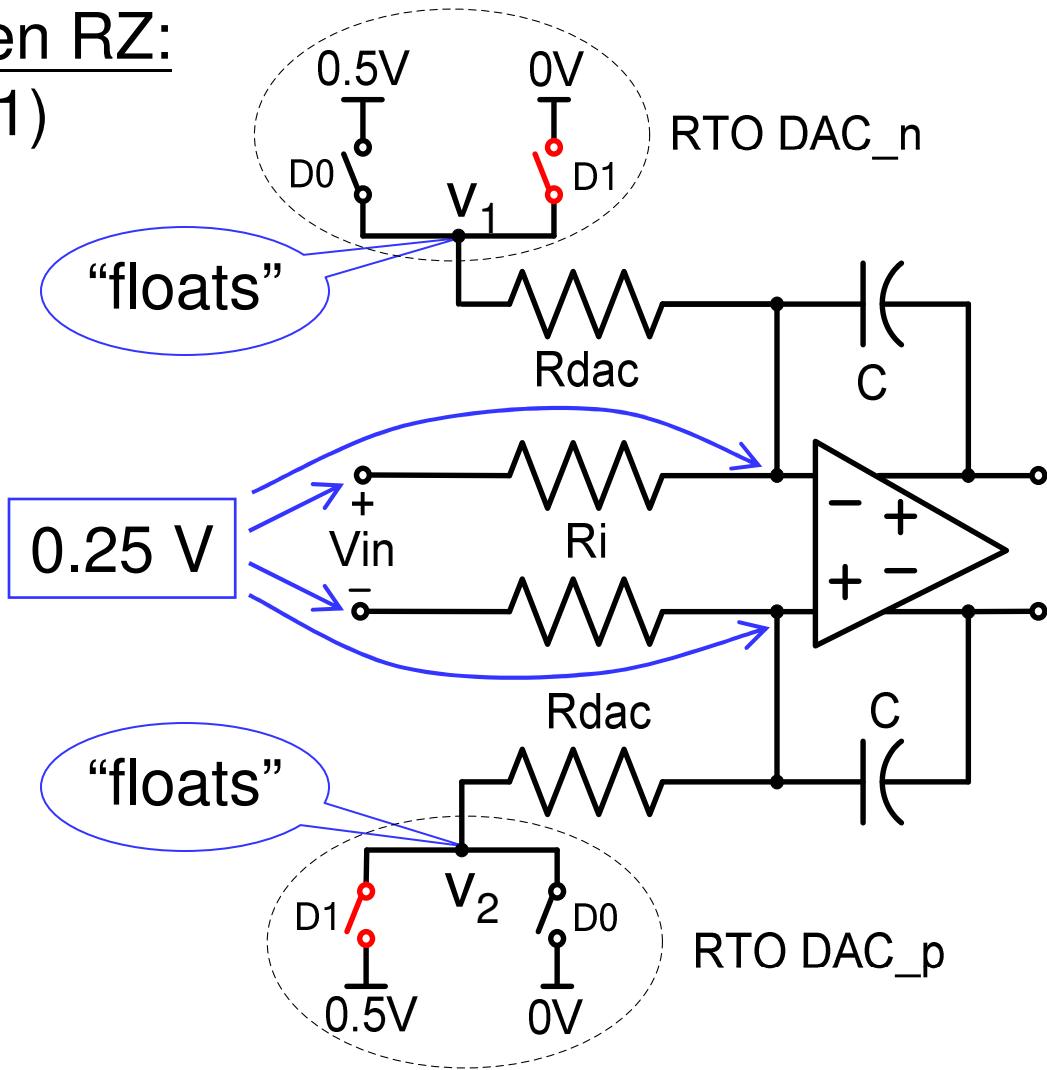
“floats”

“floats”

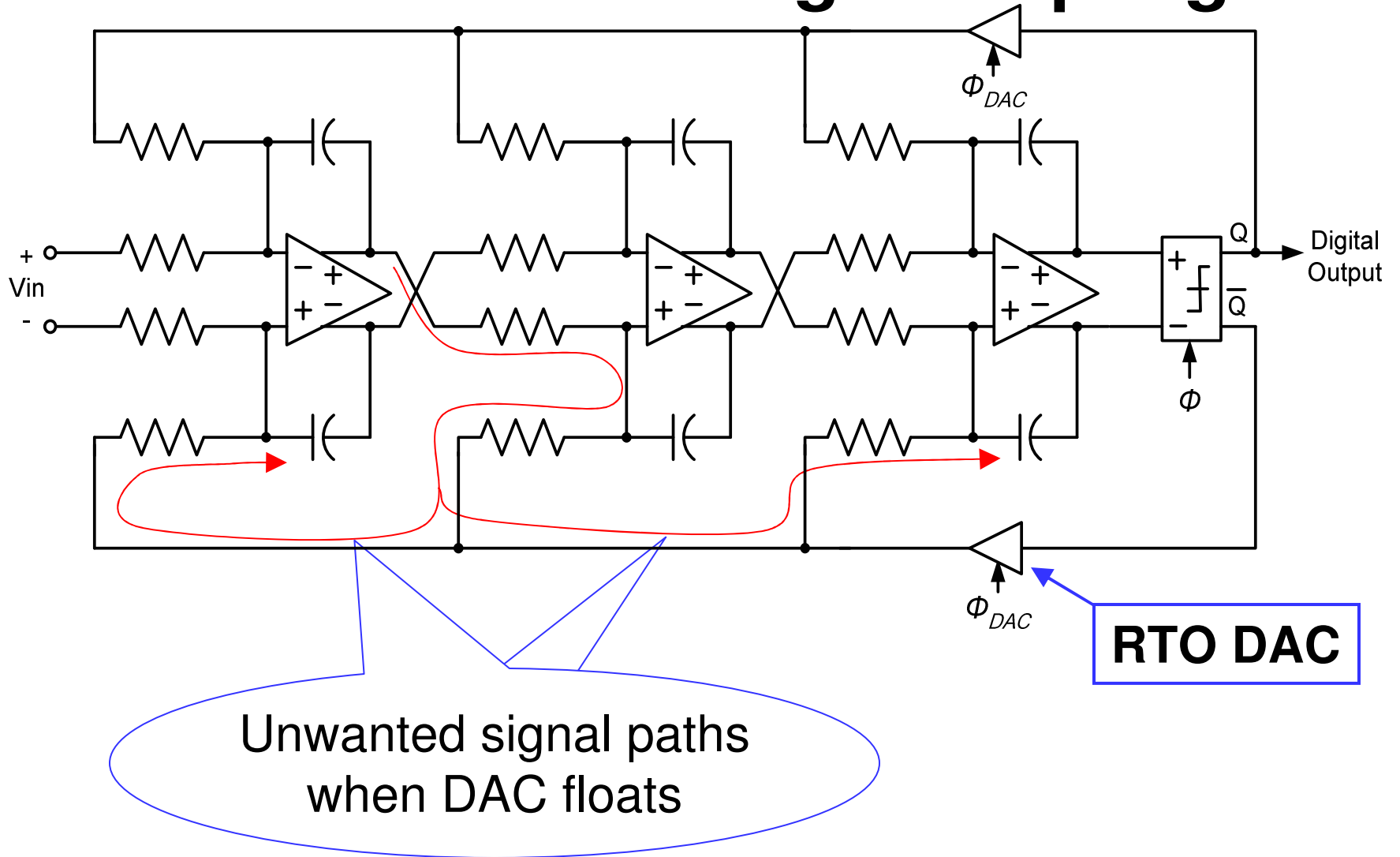


Solution: Return-to-open

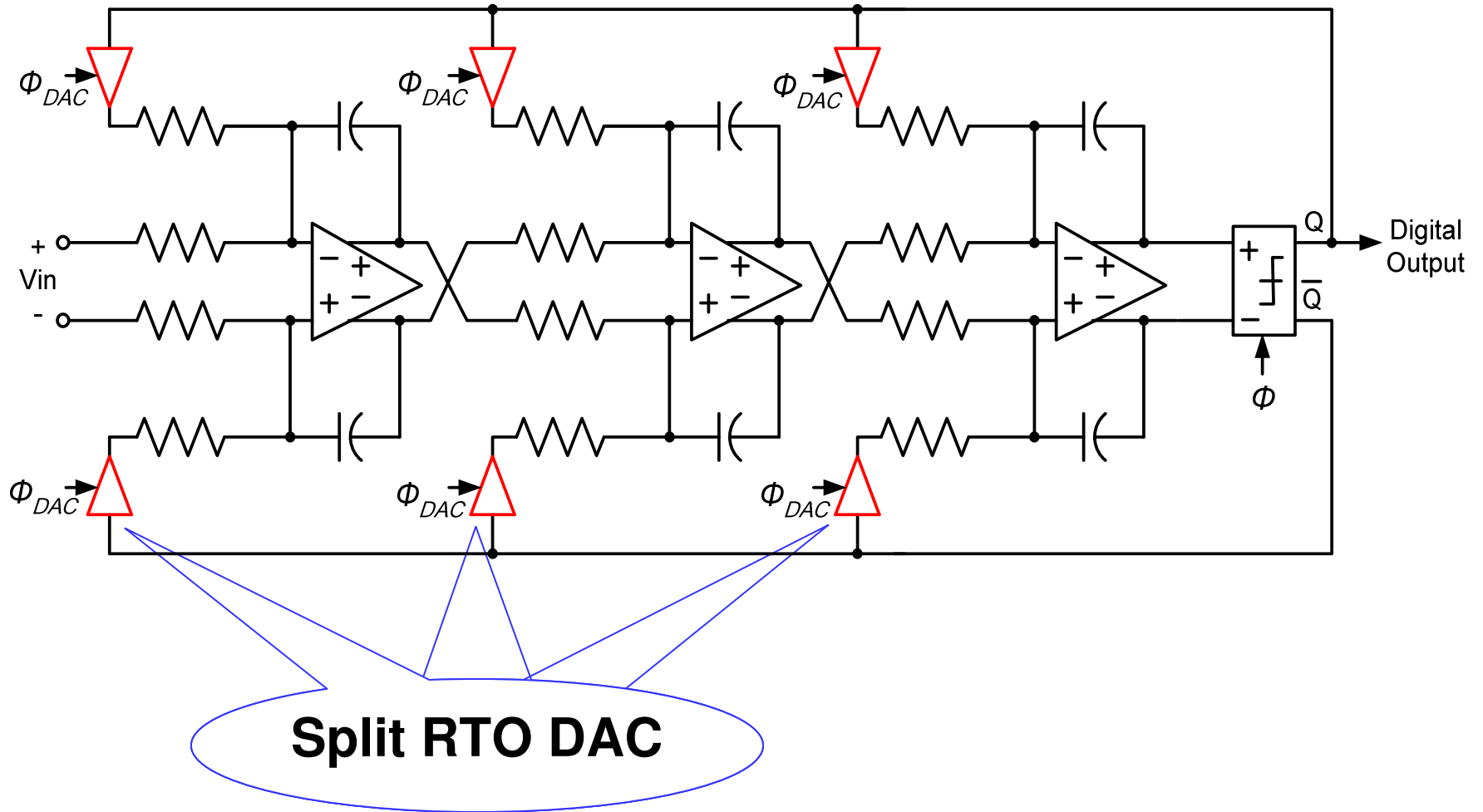
When RZ:
(Q=1)



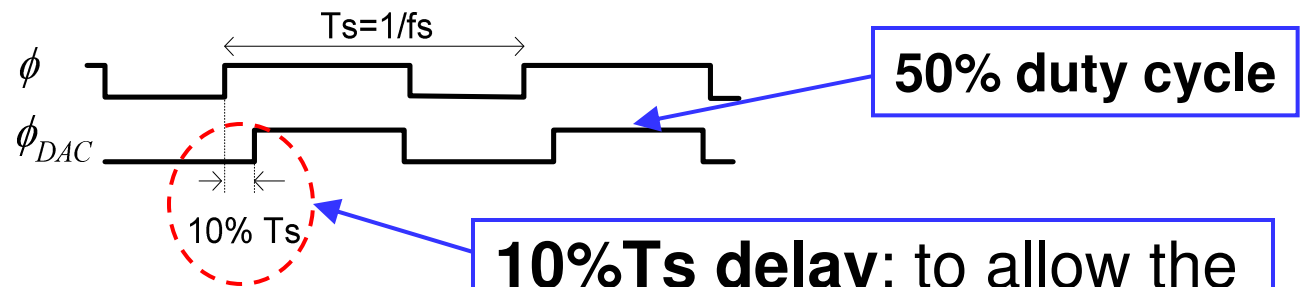
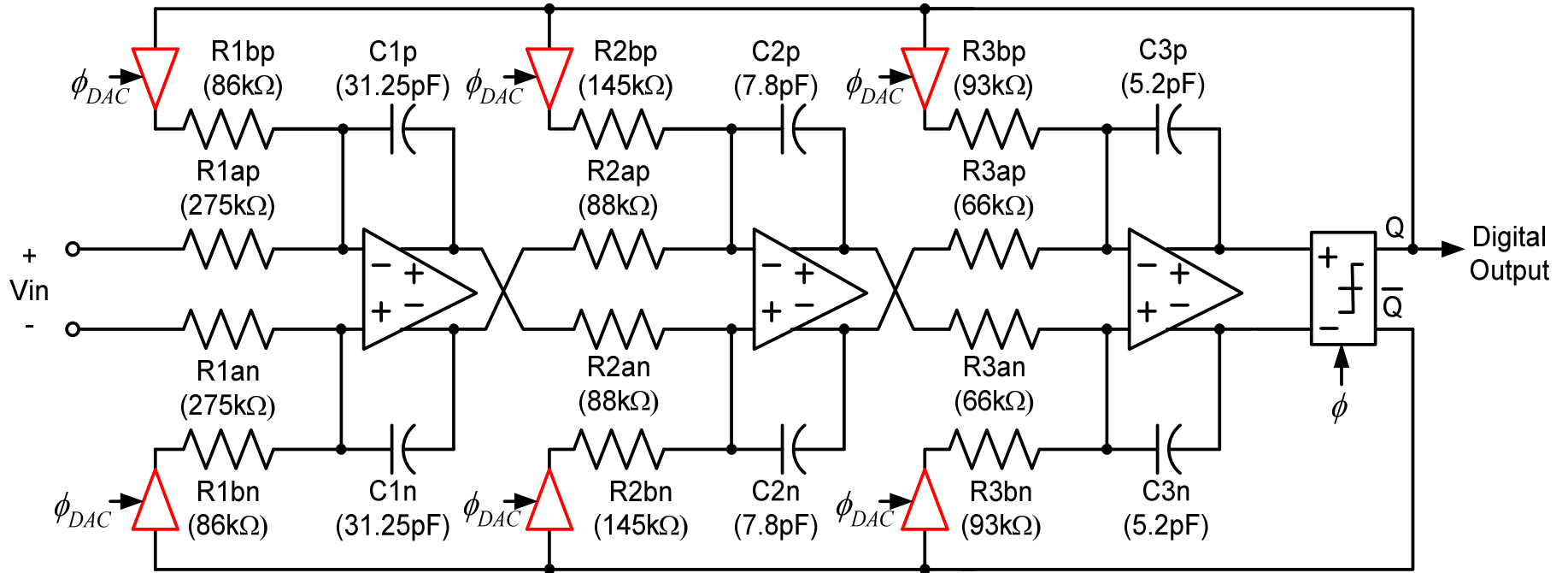
RTO SDM: Inter-stage Coupling



Split RTO SDM Architecture



Modulator Details

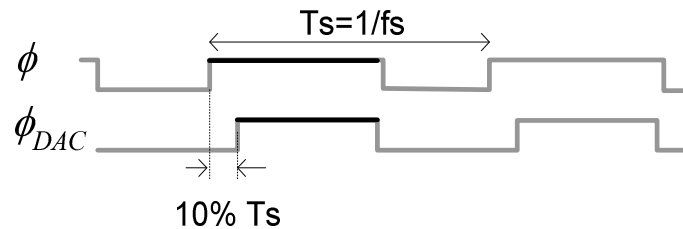
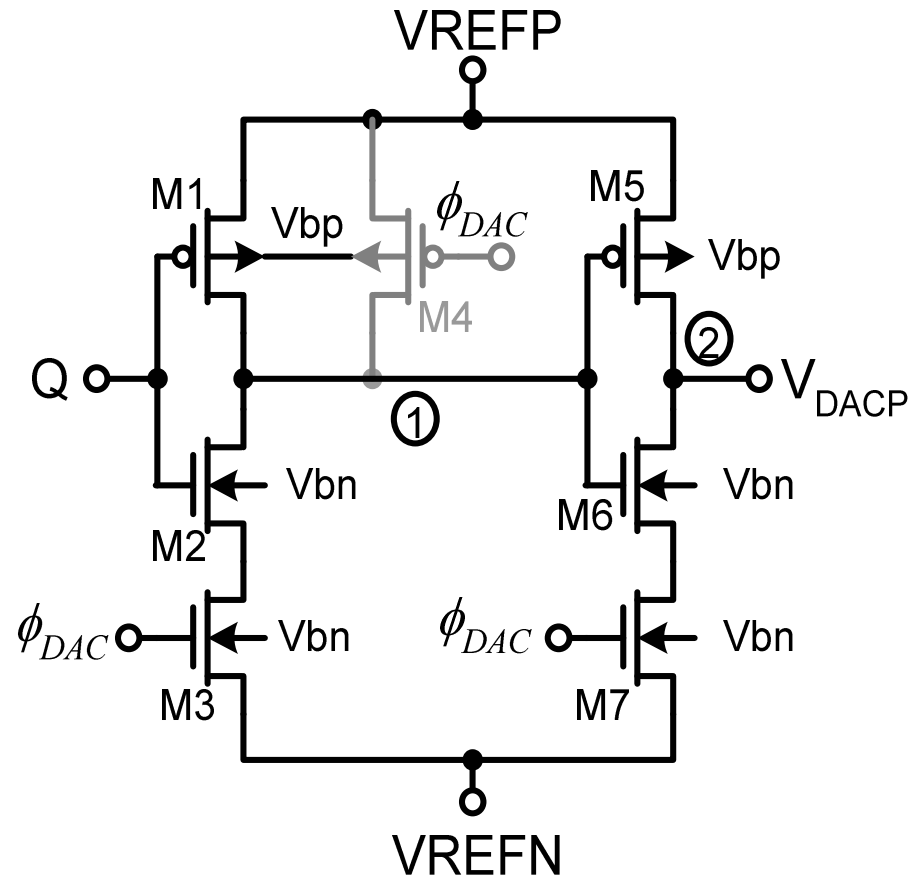


BW = 25kHz, $f_s = 3.2\text{MHz}$,
 $V_{in,max} = 1\text{Vppdiff}$.

10% T_s delay: to allow the comparator outputs to fully settle before the DACs become active.

RTO DAC Circuit

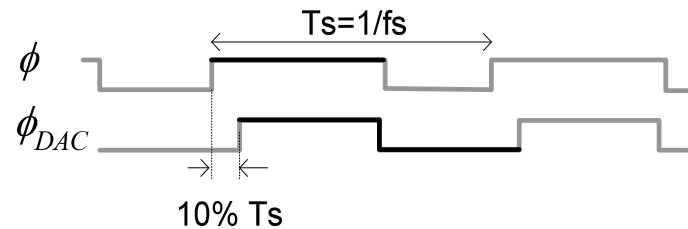
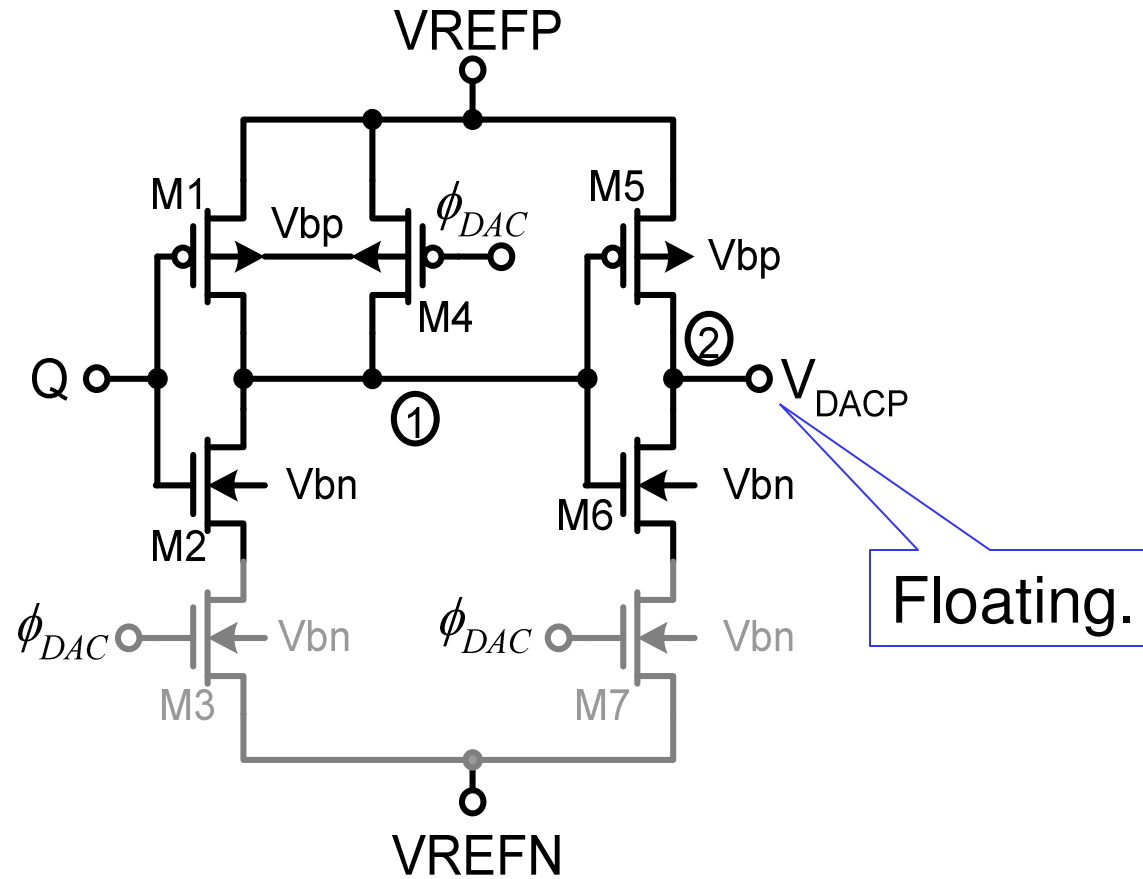
ϕ_{DAC} High:



All the bodies tied to $V_{DD}/2$.

RTO DAC Circuit

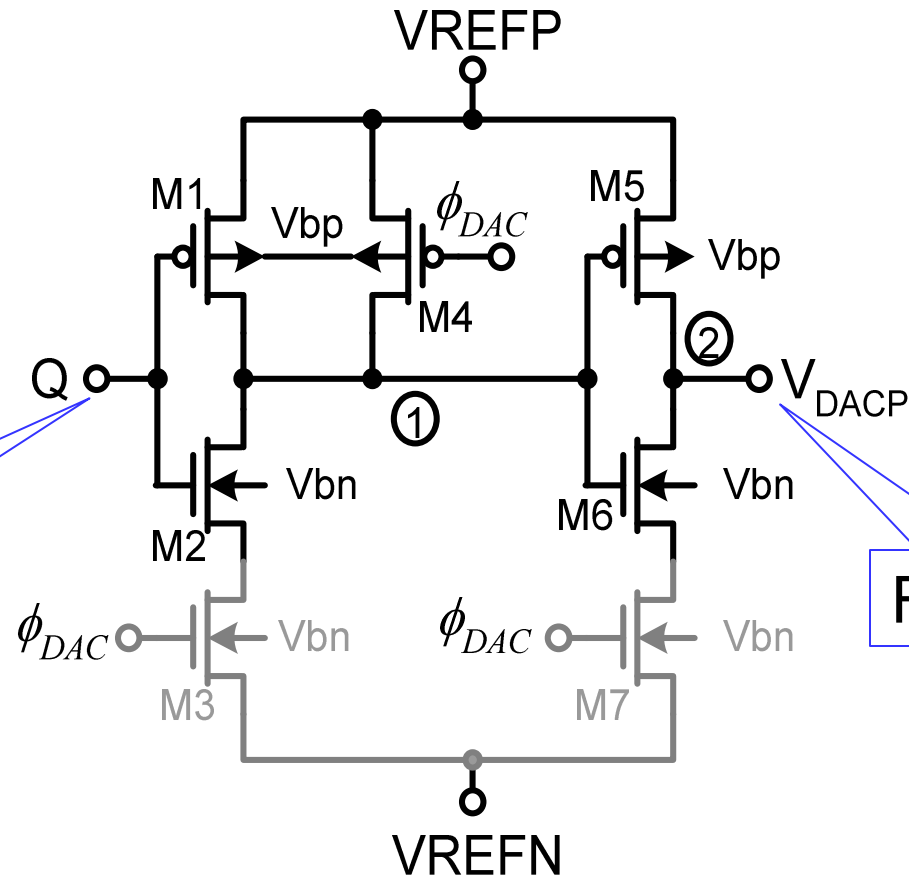
ϕ_{DAC} Low:



(All the bodies tied to $V_{DD}/2$.)

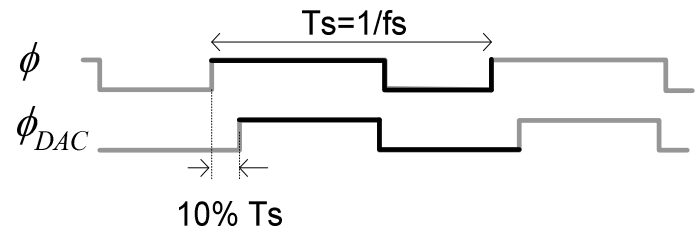
RTO DAC Circuit

ϕ_{DAC} Low:



Q invalid for ϕ low.

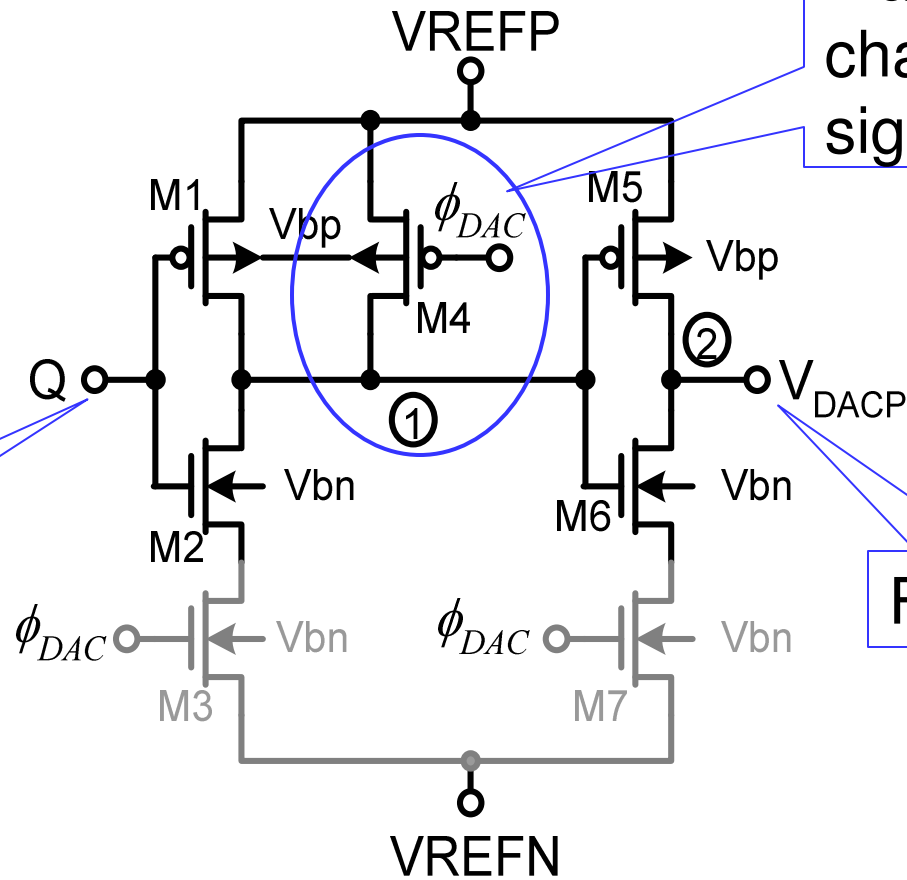
Floating.



All the bodies tied to $V_{DD}/2$.

RTO DAC Circuit

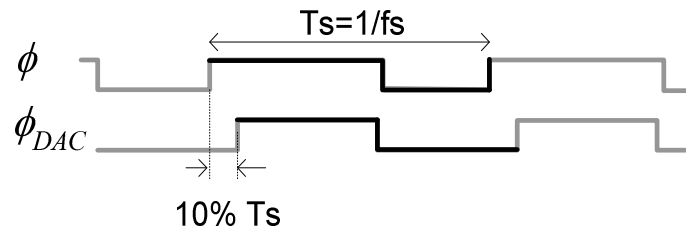
ϕ_{DAC} Low:



Make charge-injection signal-independent.

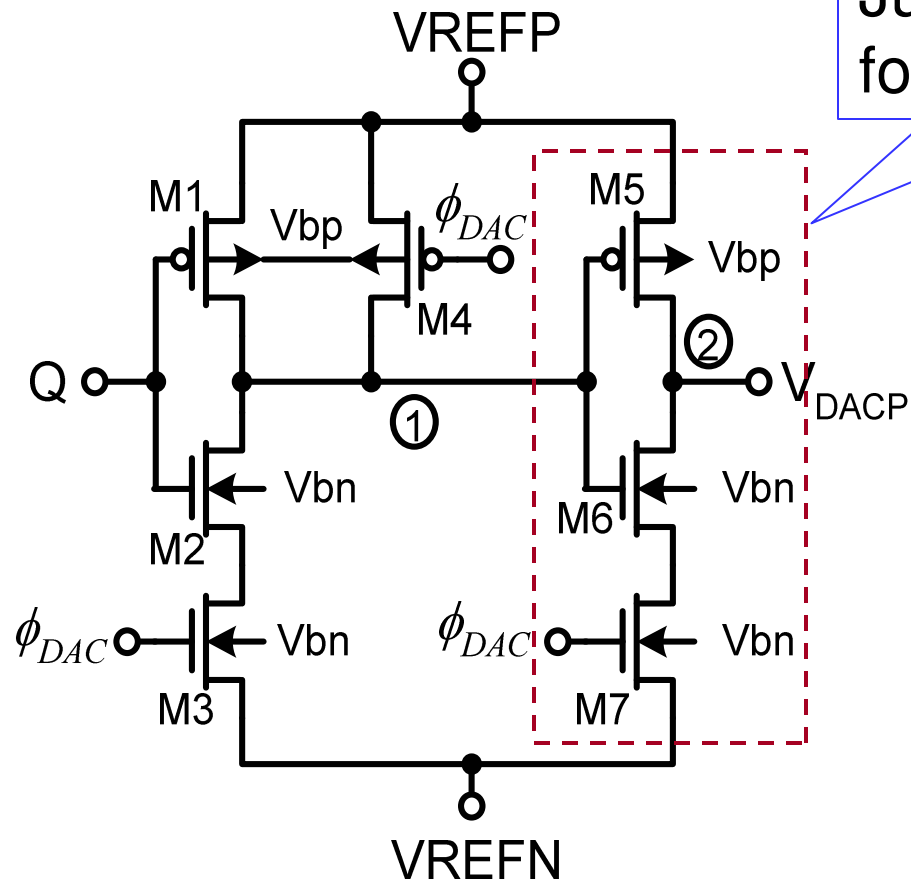
Q invalid for ϕ low.

Floating.

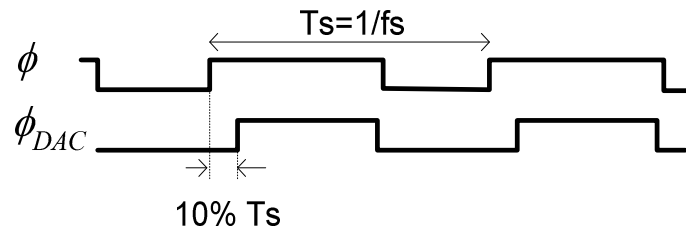


All the bodies tied to $V_{DD}/2$.

RTO DAC Circuit



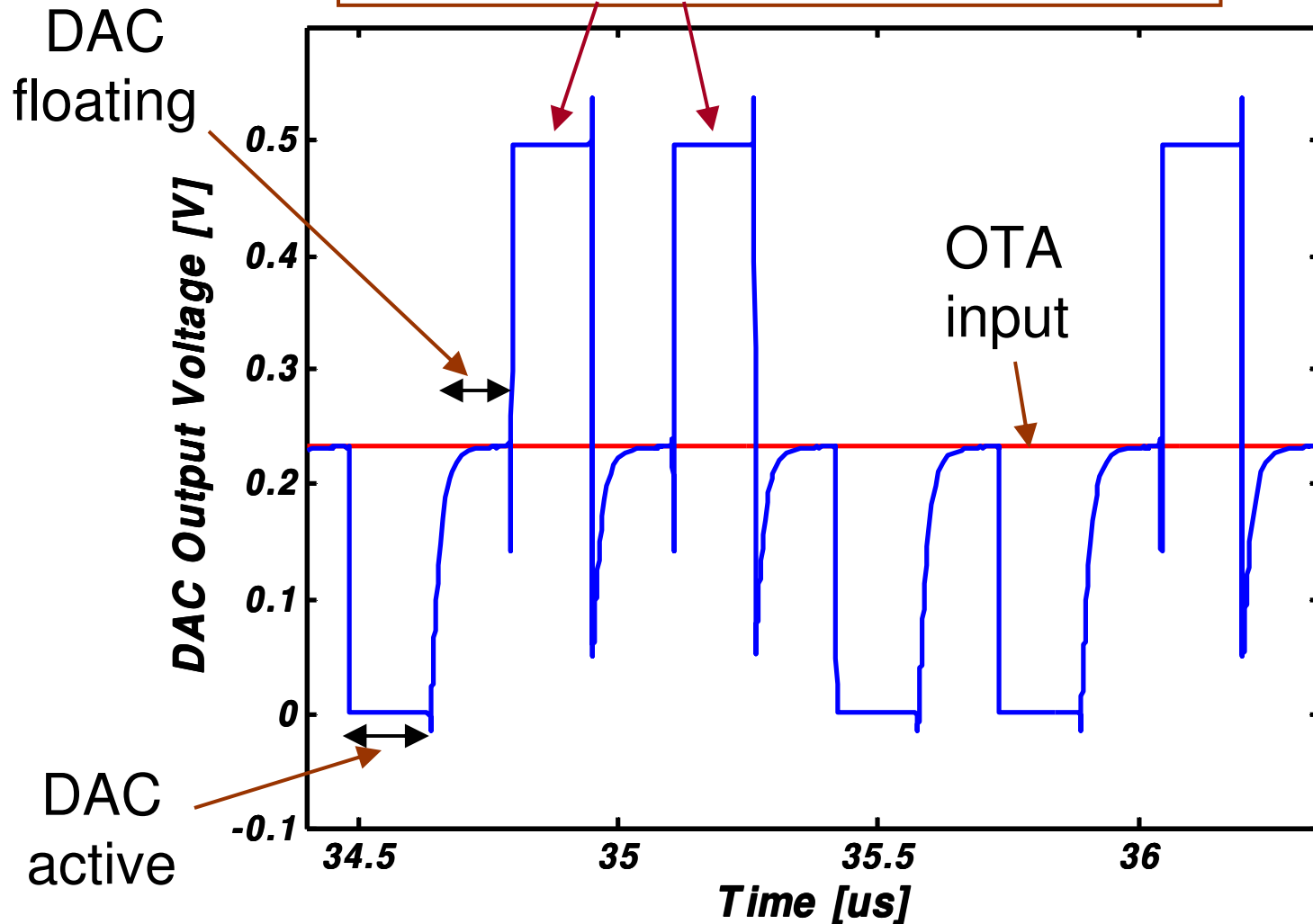
Just split M5-M7 for each FB path.



All the bodies tied to $V_{DD}/2$.

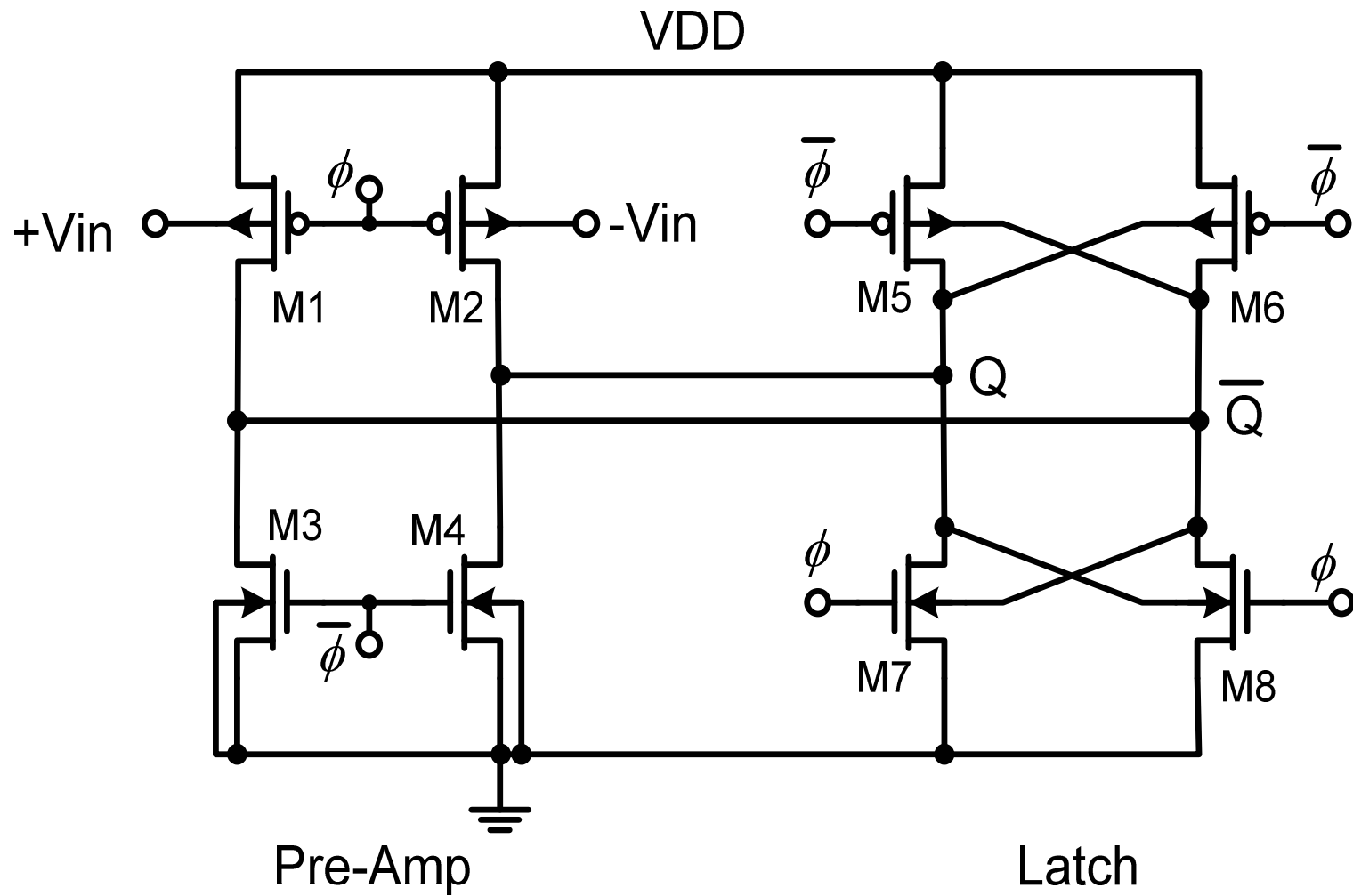
Waveform of RTO DAC

Same shape for all "1"s No ISI

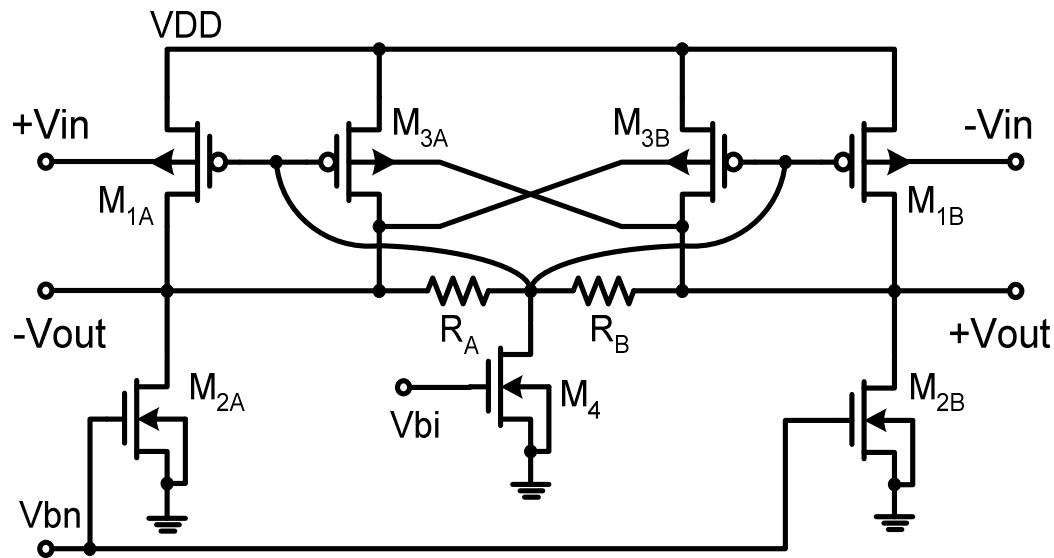


Simulated output waveform of 1st DAC

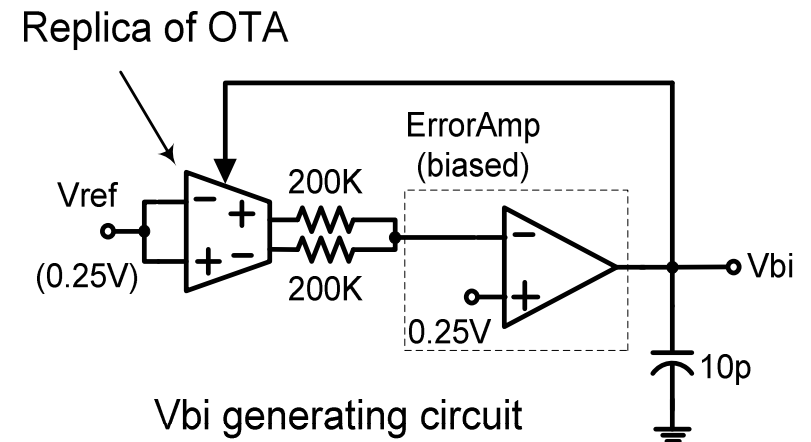
0.5V Body-input Gate-clocked Comparator



0.5V Fully Differential OTA



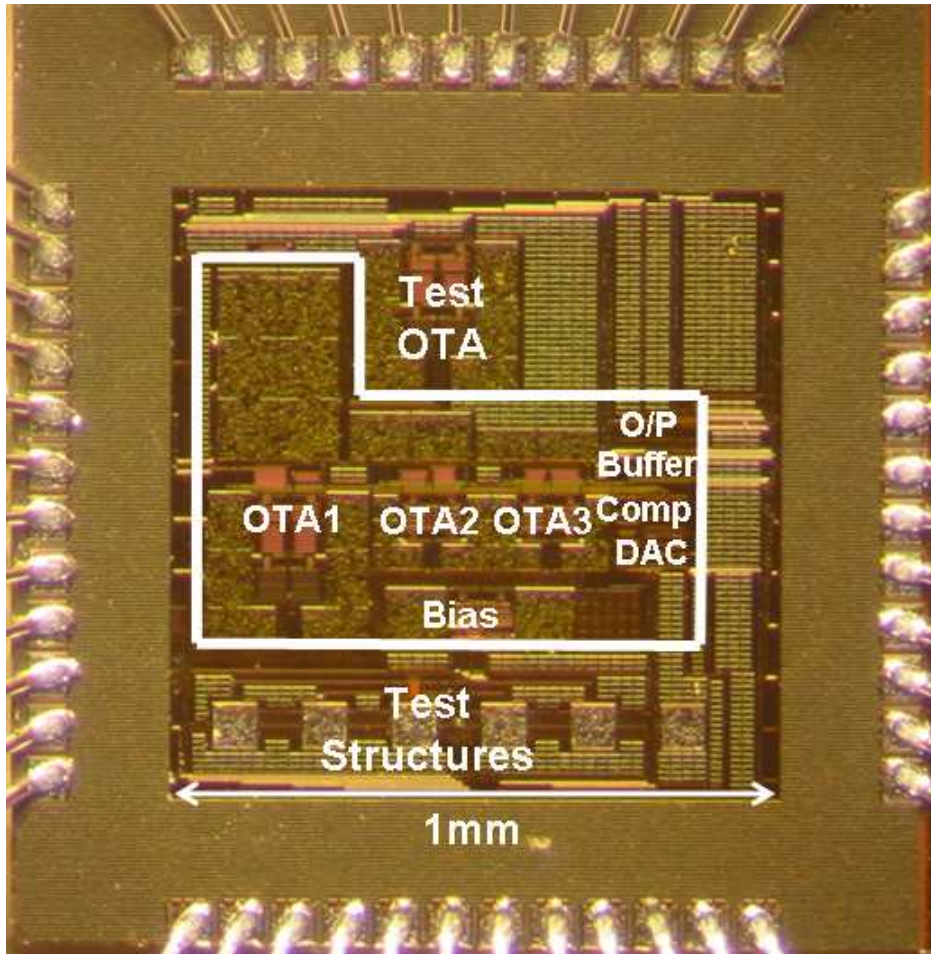
[Chatterjee ESSCIRC'05]



[Chatterjee ISSCC'05]

- Measurements on a replica of the 1st OTA:
 - $A_{DC} = 46\text{dB}$, $U_{GB} = 4\text{MHz}$;
 - Input referred noise:
 $33\text{nV}_{\text{rms}} @ 10\text{kHz}$ and $12\text{nV}_{\text{rms}} @ 1\text{MHz}$.

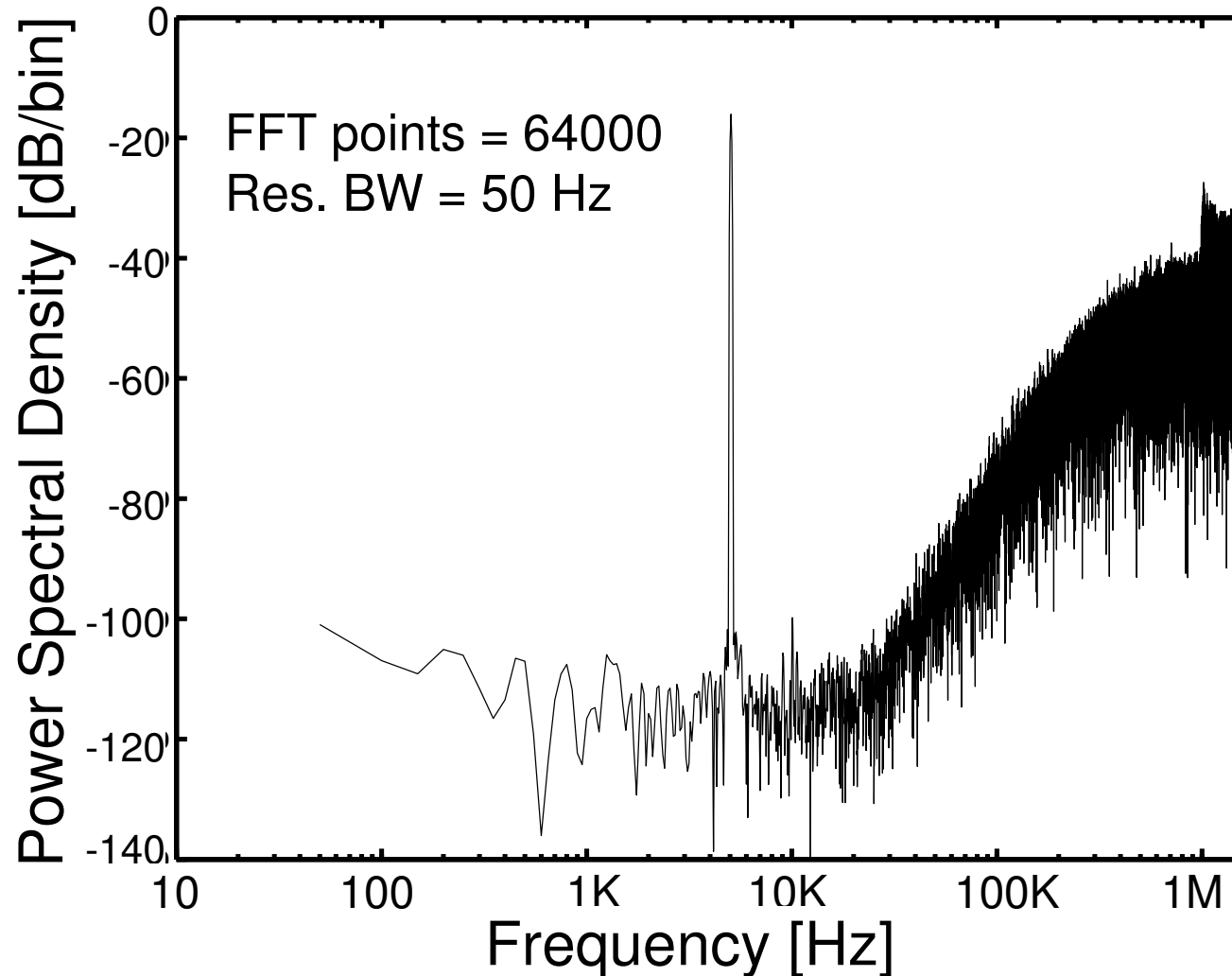
Die Photograph



- 0.18μm CMOS
- Standard V_T (0.5V)
- Triple-well devices
- 0.5V operation

K.P. Pun, S. Chatterjee, and P. Kinget, "A 0.5 V 74dB SNDR 25kHz CT Delta-Sigma Modulator with Return-to-Open DAC" in IEEE International Solid-State Circuits Conference (ISSCC), pp. 72-73, February 2006.

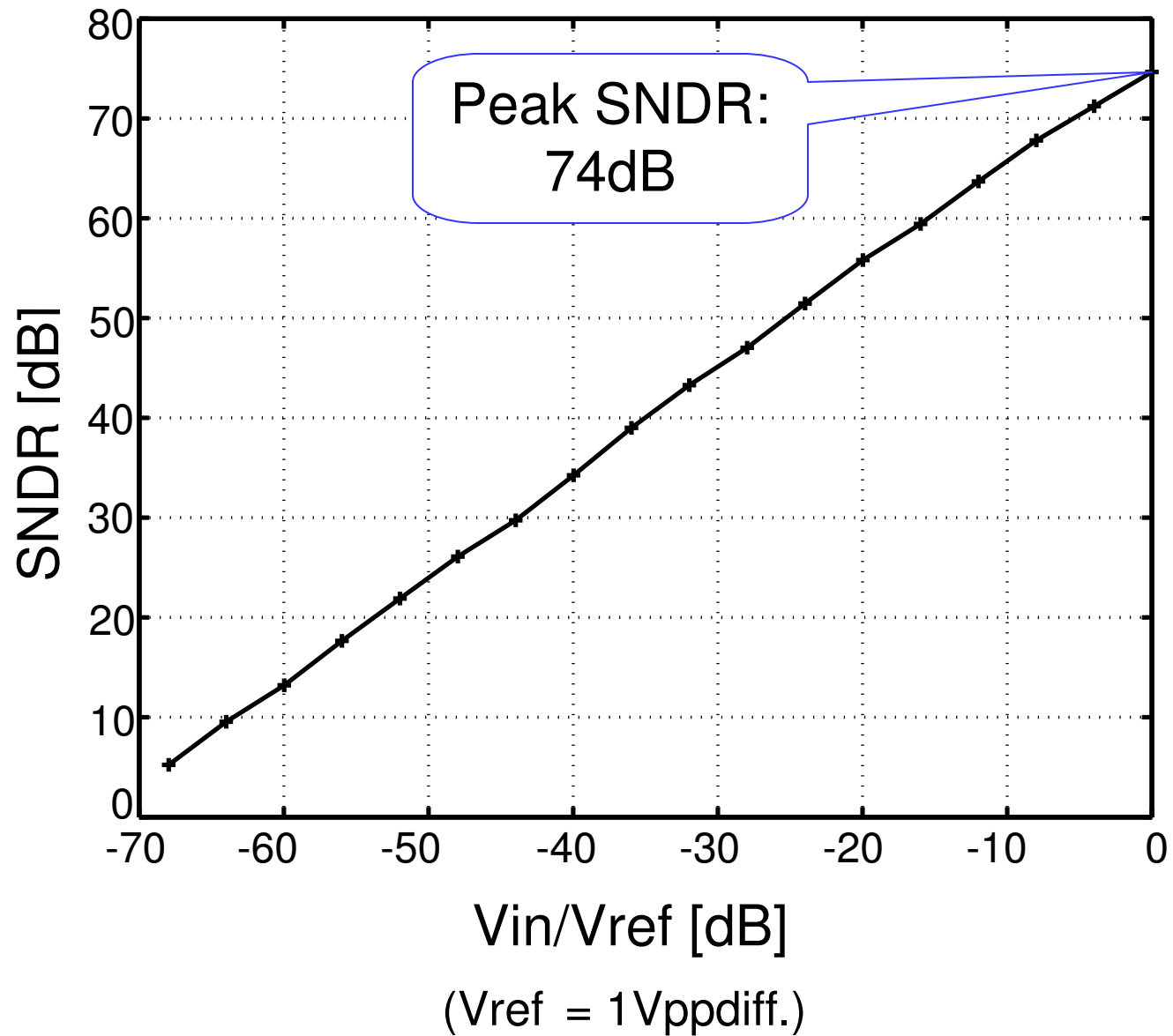
Measured Output Spectrum



2nd harmonic < 83dBc
3rd harmonic < 88dBc

@Vin = -4dB Vref, fin = 5kHz
(Vref = 1Vppdiff.)

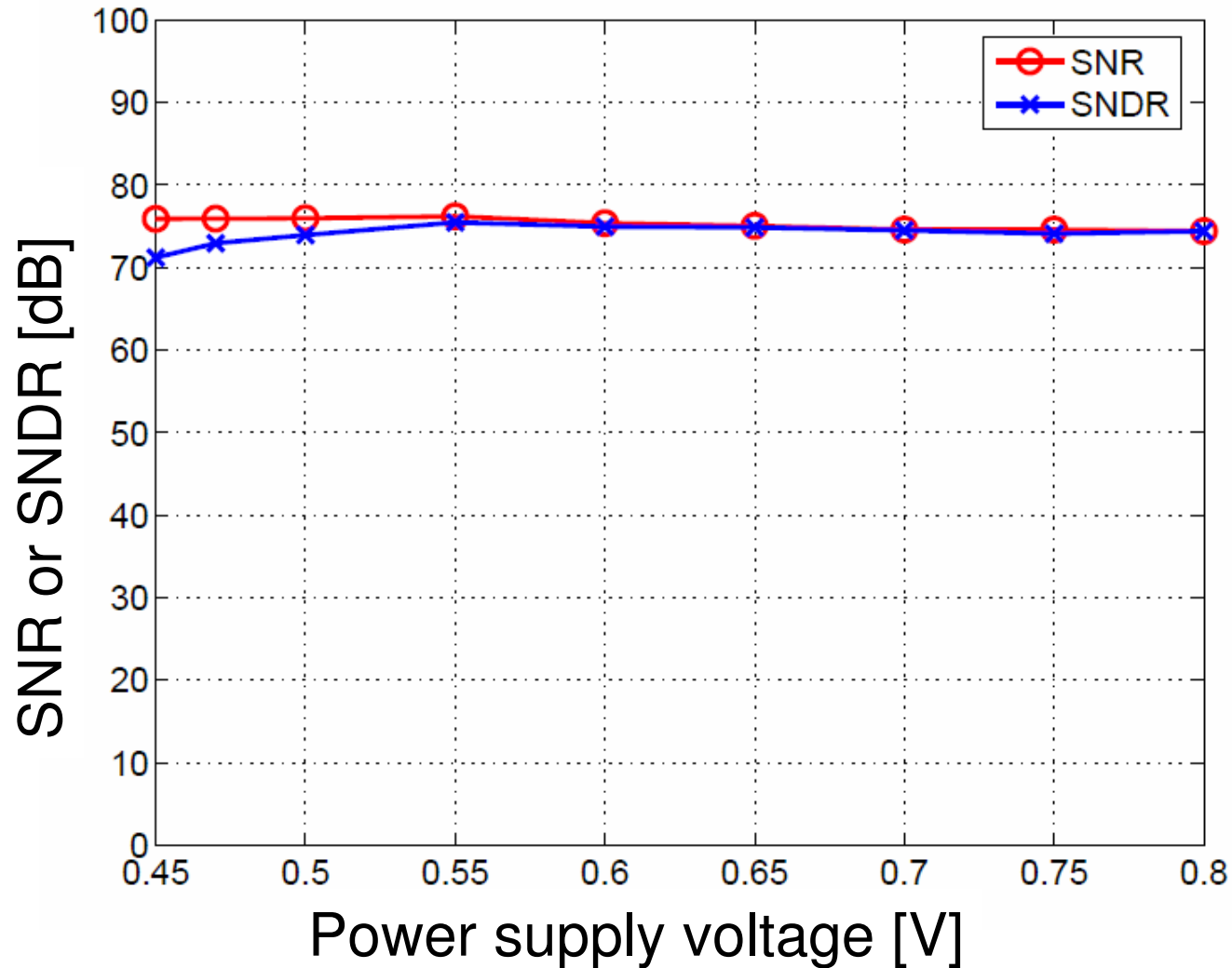
Measured SNDR versus Vin



Performance Summary at 25°C

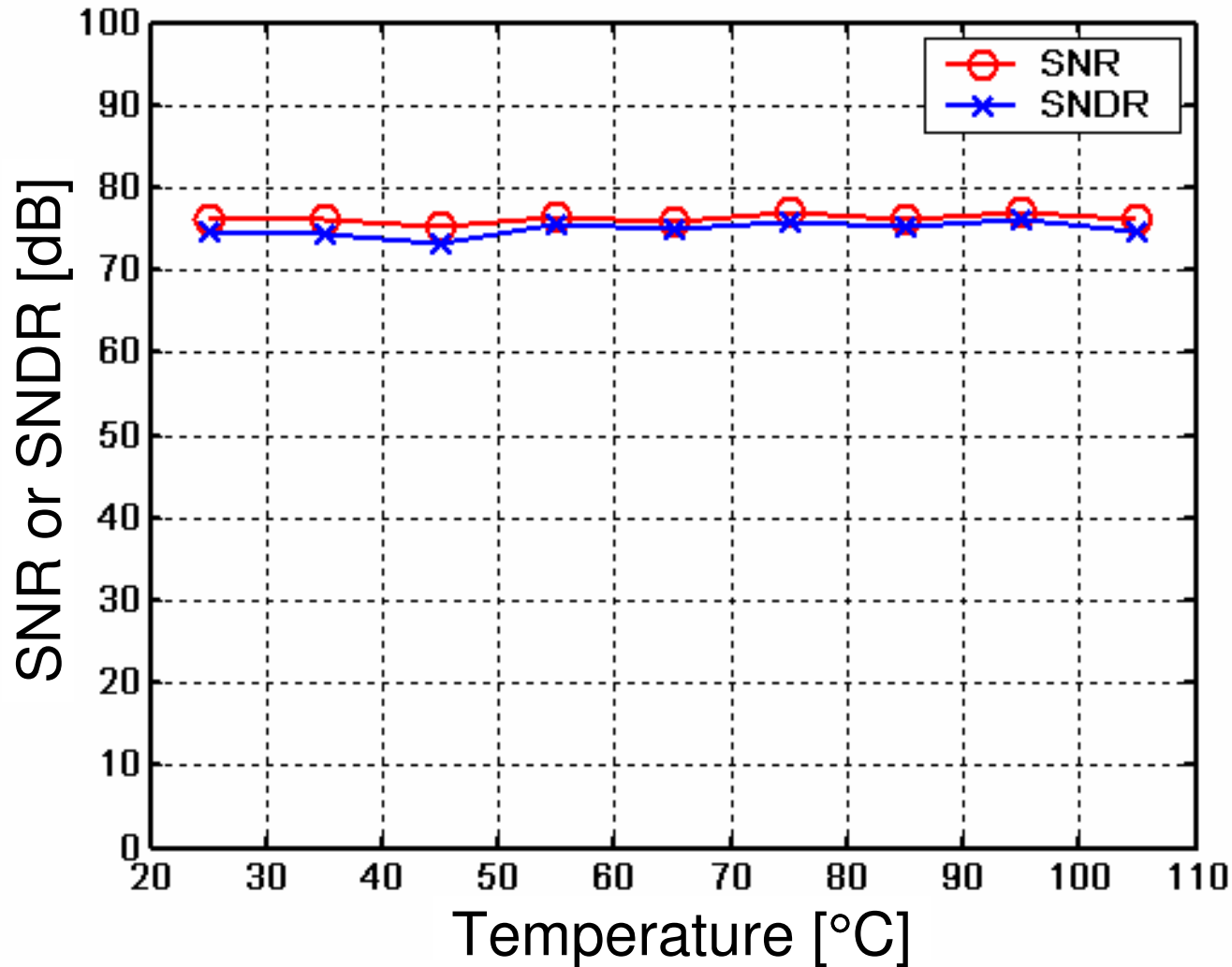
Modulator type	1-bit, 3rd order, continuous-time		
Signal bandwidth	25 kHz		
Sampling frequency / OSR	3.2 MHz / 64		
Input range	1 V _{ppdiff.}		
Supply Voltage	0.45V	0.5V	0.8V
SNDR @ V _{in} = 1V _{ppdiff.}	71 dB	74 dB	74 dB
SNR @ V _{in} = 1V _{ppdiff.}	76 dB	76 dB	74 dB
Power consumption (total)		370 μW	
Sigma Delta Modulator (filter + comparator + DAC)		300 μW	
Output buffers		70 μW	
Active die area	0.6 mm ²		
Technology	0.18 μm CMOS (standard V _T , triple-well, MIM, and HiRes Poly)		

SNDR versus V_{DD}



@25°C and $V_{in} = 1V_{ppdiff}$.

SNDR versus Temperature



@ $V_{DD} = 0.5V$ and $V_{in} = 1V_{ppdiff}$.

Performance Comparison

	VDD [V]	Type	SNDR [dB]	Bandwidth [kHz]	Power [uW]	Area [mm ²]	CMOS [um]		FOM [10 ⁹ /J]
Grech 1999	1	SO	56*	3.9	1500	0.9**	0.8		1.3
Keskin 2001	1	RO	78	20	5600	0.41	0.35		23
Matuya 1994	1	CT	51	192	1560	2.53	0.5	Low VT	36
Dessouky 2000	1	SC	85	25	950	0.63	0.35	Gate boost	381
Yao 2004	1	SC	81	20	140	0.18	0.09		1310
Ueno 2004	0.9	CT	50.9	1920	1500	0.12	0.13		366
Peluso 1998	0.9	SO	62	16	40	0.85	0.5		410
Sauerbrey 2002	0.7	SO	67	8	80	0.082	0.18		58
Ahn 2005	0.6	SRC	77	24	1000	2.88	0.35	Low VT	138
This work	0.5	CT	74	25	300	0.6	0.18		340

*=SNR only; ** Estimated from die photograph;

SO = Switched Opamp;

SC = Switched Capacitor;

SRC=Switched-RC

CT = Continuous Time;

RO = Reset Opamp;

$$\text{FOM} = \text{resolution} \times \frac{\text{BW}}{P}$$

Analog design techniques at 0.5 V

- How to do CM rejection?
 - Use local CM feedback & rejection
 - Use CM feedforward cancellation
 - Separate CM signal rejection and CM DC biasing
- How to increase DC gain?
 - Use negative load conductance
- How to use strong inversion operation?
 - Forward Body Bias to reduce V_T

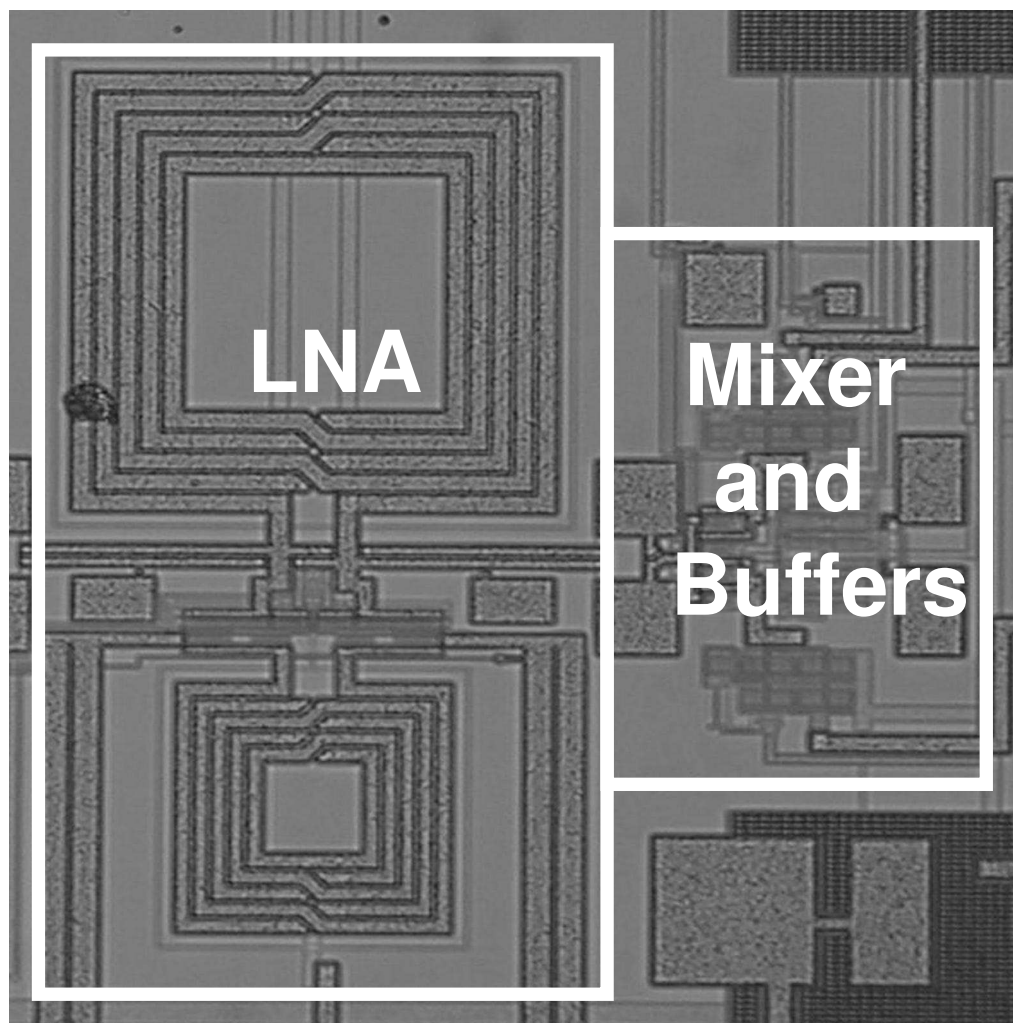
Extensive use of the body terminal

Extensive use of on-chip tuning & biasing

Architectural changes to eliminate signal path switches

Looking ahead

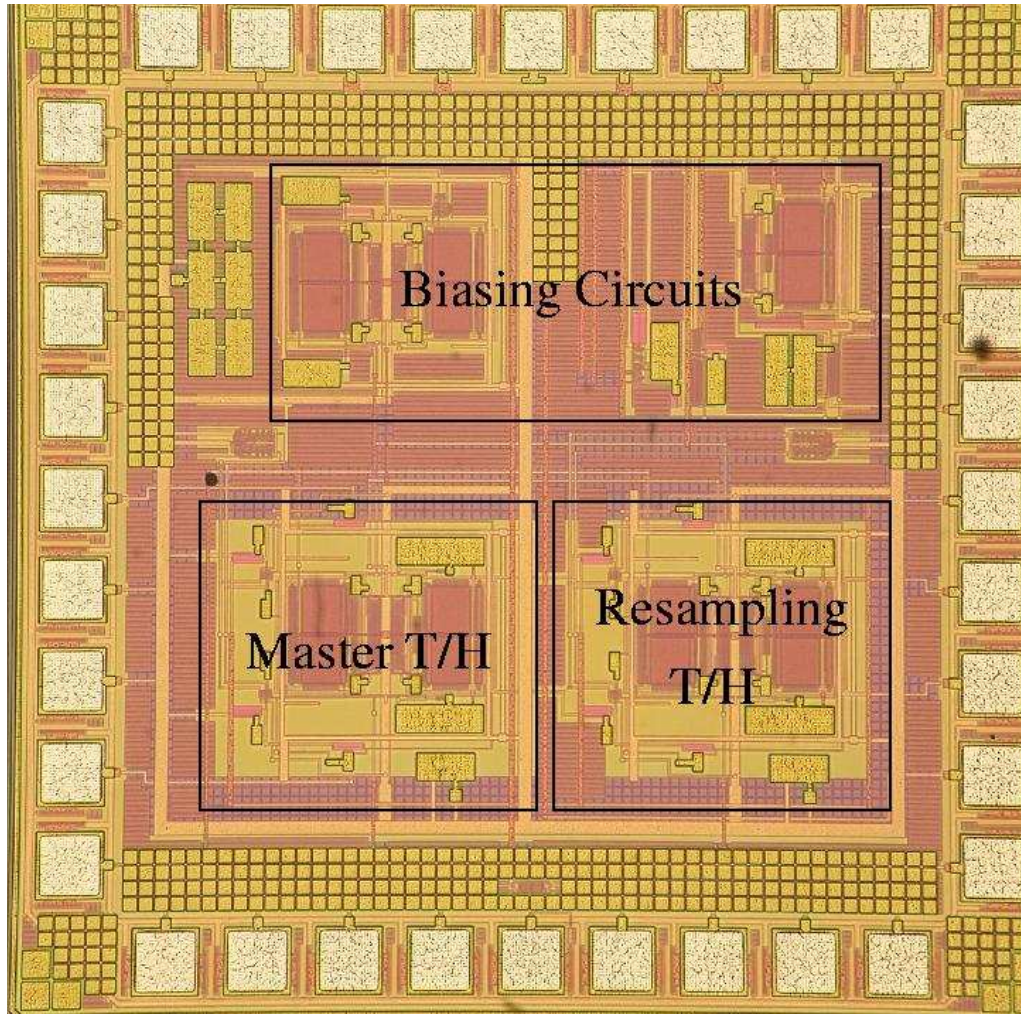
0.5V 900MHz RF Front-end



- 0.18 μm CMOS
- Low- V_T devices
- LNA/MIXER
 - NF 8.8 dB
 - Gain 11.5 or -7 dB
 - ICP -23 dBm
 - 5 mW
(w/ LO Buffers)

N. Stanic, P. Kinget, and Y. Tsvividis, "A 0.5 V 900 MHz CMOS Receiver Front End,"
IEEE Symposium on VLSI circuits, June 2006.

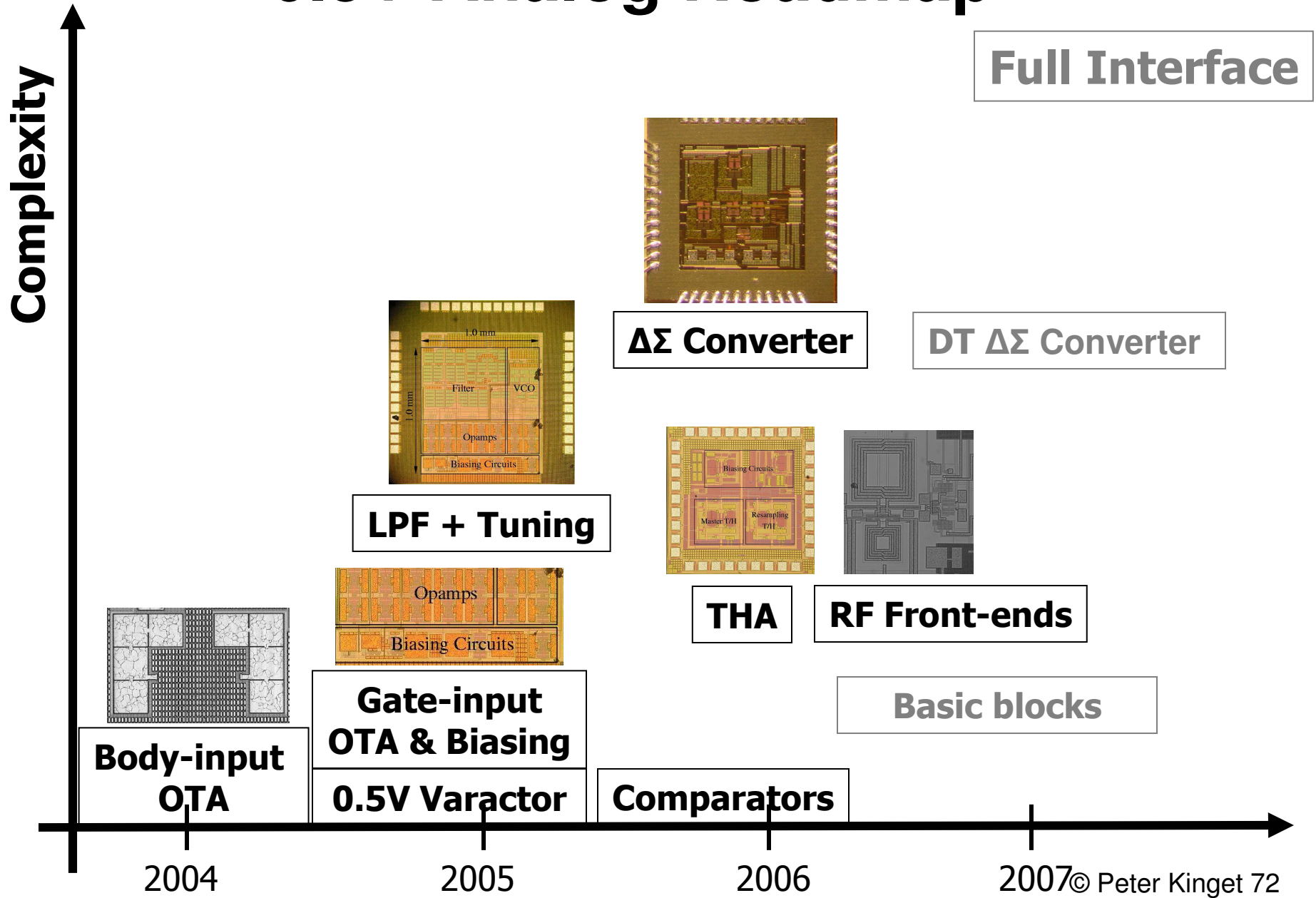
0.5 V 1 Msps 60 dB SNDR Track&Hold



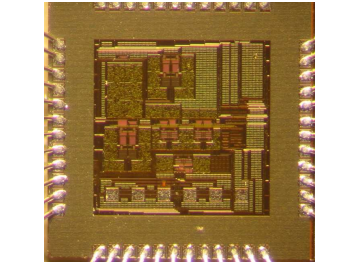
- 0.25 μm CMOS
- $|V_T|=0.6\text{V}$
- MIM caps
- High-res resistors
- Triple well nMOS

S. Chatterjee, and P. Kinget, "A 0.5-V 1-Msample/s 60-dB SNDR Track-and-Hold Circuit," IEEE Symposium on VLSI circuits, June 2006

0.5V Analog Roadmap

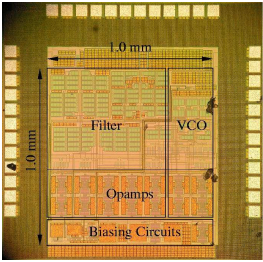


Full Interface

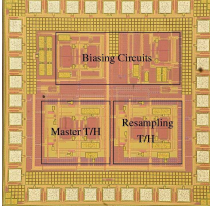


$\Delta\Sigma$ Converter

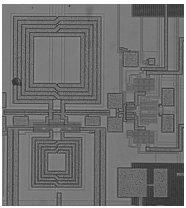
DT $\Delta\Sigma$ Converter



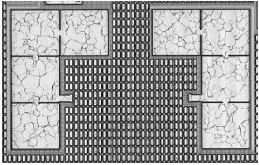
LPF + Tuning



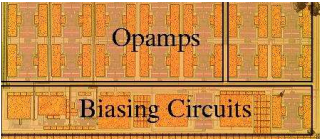
THA



RF Front-ends



Body-input OTA



Gate-input OTA & Biasing

0.5V Varactor

Comparators

Basic blocks

Other Challenges in nanometer CMOS

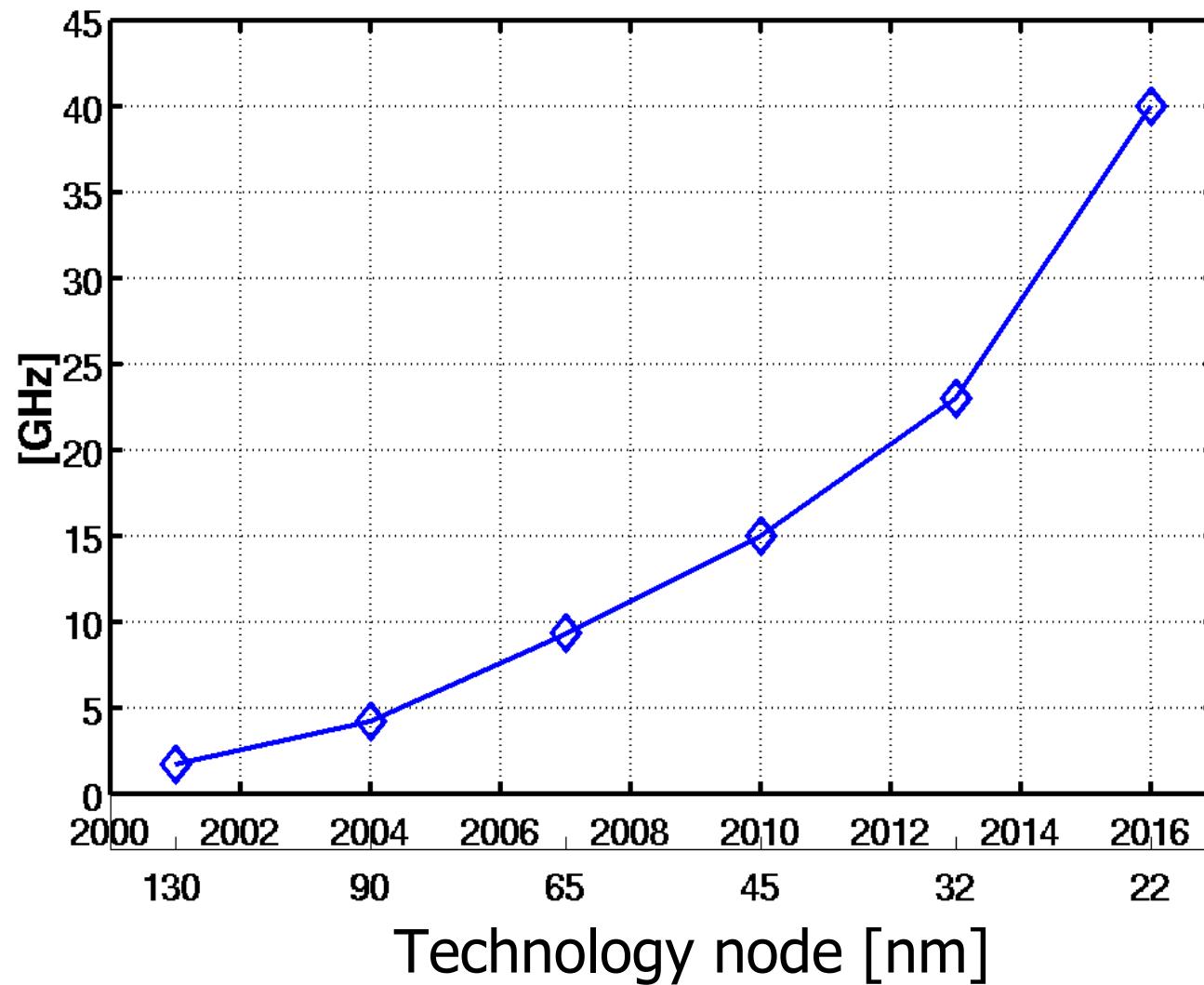
- Gate leakage.
- Sub-threshold leakage.
- Reduced body-effect [VonAmin05]:

$$V_T \propto \text{ & } t_{\text{ox}} \propto \text{ } g_{\text{mb}} \propto$$

Other Opportunities in nanometer CMOS

- Many V_T choices !
- Novel devices.
- *Extensive* Digital Calibration & Correction.

CMOS Trends: On chip Clock Speed



[ITRS'04]

Acknowledgments

- Analog Devices, Intel and Realtek for supporting parts of this work.
- Europractice and Philips Semiconductors for 0.18um and 0.25um prototypes fabrication.

More details

- [Cha 05] S. Chatterjee, Y. Tsvividis, and P. Kinget, ***"A 0.5 V filter with PLL-based tuning in 0.18 um CMOS technology,"*** in **IEEE International Solid-State Circuits Conference (ISSCC)**, pp. 506-507, February 2005.
- [Cha 04] S. Chatterjee, Y. Tsvividis, and P. Kinget, ***"A 0.5 V bulk input fully differential operational transconductance amplifier,"*** in **European Solid-State Circuits Conference (ESSCIRC)**, pp.147-150, Sep. 2004.
- [Cha 05] S. Chatterjee, Y. Tsvividis and P. Kinget, ***"0.5 V Analog Circuit Techniques and Their Application in OTA and Filter Design,"*** **IEEE Journal of Solid-State Circuits (JSSC)**, vol. 40, no 12, pp. 2373 - 2387, December 2005.
- [Pun 06] K.P. Pun, S. Chatterjee, and P. Kinget, ***"A 0.5 V 74dB SNDR 25kHz CT Delta-Sigma Modulator with Return-to-Open DAC"*** in **IEEE International Solid-State Circuits Conference (ISSCC)**, pp. 72-73, February 2006.
- [Abd 06] M. Abdulai and P. Kinget, ***"A 0.5 V Fully Differential Gate-input Operational Transconductance Amplifier with Intrinsic Common-Mode Rejection"*** in **IEEE International Symposium on Circuits and Systems**, May 2006.
- [Cha 06] S. Chatterjee, and P. Kinget, ***"A 0.5-V 1-Msample/s 60-dB SNDR Track-and-Hold Circuit,"*** **IEEE Symposium on VLSI circuits**, June 2006.
- [Sta 06] N. Stanic, P. Kinget, and Y. Tsvividis, ***"A 0.5 V 900 MHz CMOS Receiver Front End,"*** **IEEE Symposium on VLSI circuits**, June 2006.

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- [Leh 01] T. Lehmann and M. Cassia, "*1-V power supply CMOS cascode amplifier*," **IEEE J. Solid-State Circuits**, vol. 36, pp. 1082--1086, July 2001.
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- [Fer 96] G. Ferri and W. Sansen, "*A 1.3V opamp in standard 0.7 μ m CMOS with constant gm and rail-to-rail input and output stages*," **IEEE International Solid State Circuits Conference**, pp. 382--383, 478, 1996.

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- [Kob94] T. Kobayashi and T. Sakurai, "*Self-adjusting threshold-voltage scheme (SATS) for low-voltage high-speed operation,*" in **IEEE Custom Integrated Circuits Conference (CICC)**, May 1994, pp. 271–274.
- [Von94] V. R. Kaenel, M. D. Pardoen, E. Dijkstra, and E. A. Vittoz, "*Automatic adjustment of threshold and supply voltages for minimum power consumption in CMOS digital circuits,*" in **IEEE Symposium on Low Power Electronics**, pp. 78–79, 1994.
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- [Bul00] K. Bult, "*Analog design in deep sub-micron CMOS,*" in **European Solid-State Circuits Conference (ESSCIRC)**, September 2000, pp. 11–17.